Design, Fabrication, and Delivery **Concentrator Solar Array System** of a Miniature Cassegrainian

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Engineering and Test Division TRW Space & Technology Gri

TRW Space & Technology Group One Space Park Redondo Beach, CA 90278

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Prepared by Mark A. Kruer Work Performed for: Marshall Space Flight Center National Aeronautics and Space Administration Huntsville, Alabama 35812 TABLE OF CONTENTS

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JERRY JACOBY	OPTICAL DESIGN
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1. INTRODUCTION

This miniature cassegrainian concentrator (MCC) development project is third in a series of NASA sponsored programs conceived to advance photovoltaic concentrator designs for spaceborne arrays. Achieved during this project were broadened solar acceptance angle, increased optical efficiency, and increased manufacturability of both the optical elements and the support structure. The MCC was raised to NASA development level 5 (Component of engineering model tested in relevant environment) through thermal cycle and qualification acoustic testing. A pilot line quantity (270) of MCC elements were produced, three of which were submitted for flight on the LIPPS III experimental satellite.

Previously set goals of >28W/kg at the panel levels and >160W/m² are projected to have been achieved by the present hardware and new capability projections of as much as 87W/kg using ultra lightweight optics and advanced 27.5% silicon concentrator cells seem feasible, all at a cost of less than \$500/W.

Shown in figure 1-1 is the basic operational characteristics of a cassegrainian type concentrator. The chief advantages are small storage volume, passive thermal cooling and the capability to fine tune the optical input through multiple mirror surface shape reflectance control.

Figures 1-2 and 1-3 show the back and front of the large fully operational 35×142 cm panel built during this contract. Figures 1-4 and 1-5 show the back and front of the small fully operational 35×53 cm panel built during this contract. Figure 1-6 shows a close up of the panel in operation. Figure 1-7 is a close up at the completion of assembly in the manufacturing area.



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Showing Flat Cable Harness.

Figure 1-3. Back of Large Pa









Figure 1-5. Back of Small Panel Showing Flat Cable Harness.



Figure 1-6. 15 x 56 Array in Operation.

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Figure 1-7. Close-up of the Assembly Just After Completion . in the Manufacuring Facility.

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2. MCC HISTORY AT TRW

Figure 2-1 shows the early development of the MCC design under contract NAS8-34131. Goals of 160 W/m^2 and 28 W/kg were established as reasonable for the MCC design assuming current technology capabilities. Feasibility was demonstrated through construction and test of a nine element module.

Figure 2-2 presents the results of the immediate predecessor contract for MCC development, NAS8-35635. Significant improvements were made in the pursuit of the goals established in NAS8-34131.

The evolution into third generation hardware of the element (Figure 2-3) and the support structure (Figure 2-4) were set as goals for the present NAS8-36159 contract. All goals have been met by analysis of test articles.

Contract NAS8-34131 Technical Results Summary **Engineering and Test**

IRW Space & Division



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Figure 2-1

Contract NAS8-35635 Technical Results Summary

> **Engineering and Test** Division TRW Space & Technology Group

ICC Module 100-kW Array Predictions	<image/>	ite epoxy tri-hex • 160 W/m ² B0L abricated by Fiber ce • 28 W/kg B0L	deflection tests ed predicted ess
MCC Element M		 Optical efficiency Graphi grid feimproved from 55 to 70 percent 	 AMO 100X cell Load to the set of 17 to the set of 17 to the set of 18 percent at 28°C

ORIGINAL PAGE IS CE POOR QUALITY Figure 2-2

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MCC Element Evolution



Tri-Hex Grid (THG) Panel Evolution

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SECOND GENERATION TRI-HEX GRID 60% FIBER VOLUME • THERMALLY COM-PATIBLE INSERTS • 33W/KG (PANEL LEVEL)* ELIMINATE ALUMINUM INSERTS NAS 8-36159 INCREASE FIBER VOLUME ALUMINUM INSERTS FIRST GENERATION TRI-HEX GRID 20 TO 30% FIBER VOLUME 26W/KG (PANEL LEVEL)

*CORRESPONDS TO 28W/KG AT THE ARRAY SYSTEM LEVEL

Figure 2-4

RF-00689/36

3.1 OBJECTIVES AND PROGRESS

The objectives of this contract were to :

- a. Improve the miniature Cassegrainian concentrator (MCC) optic design in terms of total energy throughput and offpointability
- b. Design a cell stack compatible with the MCC and capable of low earth orbit operation for five years
- c. Manufacture the complete optic and cell stack and measure the improvements
- d. Further develop the support structure of the MCC panel
- e. Manufacture the improved support structure and enough MCC elements to fully populate two testable panels.

All objectives have been met.

3.2 TASK STATEMENTS

The task statements listed here were followed in performance of this contract. NASA directed modifications to the tasks following the basic statements.

- o Element Optical Design
 - Improve normal and off-pointing performance
 - Select materials and process based upon performance and cost
- o Cell Stack Development
 - Isolated/nonisolated element designs
 - Analysis/development test for 30,000 LEO cycle goal
- o Panel Development
 - Select substrate type (hexagonal/trihex grid)
 - Incorporate redesigned element
 - Finalize element attachment design
 - Test development hardware (elements, substrated, attachments)
 - Design panel wiring for 30,000 LEO cycles, manufacturability, low cost
 - Fabricate 15" x 56" panel (IO active elements)
 - Perform development tests in support of LEO goal
- o Pre-prototype Panel
 - Panel level design update
 - Fabricate 15" x 21" panel (100% active elements)
 - Deliver for long-term thermal cycling
- o NASA Modifications
 - Deliver the three elements developed in tasks 1 and 2 to NRL to support launch of test articles
 - Paint the primary and secondary emitting surfaces with S13GLO white thermal control coating

3.3 OPTIC INVESTIGATION AND TEST

Two efforts were initiated to improve the optic design of the MCC elements as compared to the design produced and tested under contract NAS8-35635 pictured in Figure 3-1.

The first effort was directed at finding reasons why performance of the design was not significantly in accordance with predictions. The second effort was directed to finding how to improve the offpoint performance of the design by changes in the mirror surface and interrelated geometries.

3.3.1 NAS8-35635 Investigation

3.3.1.1 Physical Measurements

The size and geometry of the primary mirrors was measured using a Cordex 3000 by sampling points along the surface in an absolute coordinate system. Results shown in Figures 3-2 and 3-3 indicate \pm .0025 inch error in the figure X coordinates compared to the theoretical design values. This is equivalent to a 6' arc error. The cup bottom on which the birdcage assembly rests was flat to within \pm .0005 inch. The cup center was offset from the primary surface figure center by 2 mils.

The center of the front surface of the solar cell was offset from the cup center by 3.8 mils. The height of the front surface of the solar cell from the cup interior surface was 1 mil lower than the designed placement.

The placement of the secondary in the birdcage brought the tip of the secondary 12.5 mils above the nominal Z direction design point. The secondary was found to be tilted by .12° compared to the XY reference plane of the primary cup. A Numerex Surface Profilometer measured the surface of the secondary by dragging a scribe across in various radial directions. The surface geometry was within a 6' arc error.

When combined with the birdcage offsets, the secondary absolute position in the XY plane was found to be 10 mils offset from the primary mirror cup center.

FIGURE 3-1. FRONT SIDE VIEW OF PREDECESSOR NAS8-35635 MCC ELEMENT IN TRI-HEX GRID **Engineering and Test Division** TRW Space & Technology Group





SURFACE ACCURACY ERROR MEASUREMENTS FOR #15 PRIMARY AND SECONDARY

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	>	60	120	180	240	300	THEORY	X	α	۵	TILT
PARABOLA	00						00				
. 29	4 077	9 .0765	.0755	.0755	.0751	.0763	.0770	.0761	.0010	(6000.)	.27°
.30	5 .081	0 .0807	.0802	.0796	.0795	.0806	.0802	.0803	.0006	.000	.14°
.43	8 130	1 .1292	.1290	.1288	.1289	.1299	.1293	.1293	.0005	0	°90.
.53	2 1.176	3 .1775	.1765	.1745	.1765	.1776	.1746	.1765	.0011	.0019	.17°
. 63	3 .235	5 .2356	.2344	.2334	.2345	.2359	.2331	.2349	6000.	.0018	.11°
.74	2 .310	5 .3099	.3080	.3075	.3082	.3100	. 3076	.3090	.0013	.0014	$.11^{\circ}$
.84	4 .391	5 . 3907	.3889	.3884	.3896	.3911	.3880	.3900	.0013	.0020	$.10^{\circ}$
.6.	8 .474	1 .4734	.4727	.4708	.4725	.4743	.4712	.4730	.0013	.0018	$.10^{\circ}$
1.01	2 534	3 .5397	.5359	.5356	.5344	.5422	.5370	.5370	.0032	0	.22°
1.02	5 534	8 .5346	.5349	.5346	.5346	.5349	.5370	.5347	.0002	.0023	
+ FIXT	.585	5 .5852	.5853	.5850	.5851	.5855					
HYPERBOLA	0 .439	2					.4328			.0064	
.1.	2 .472	3	.4701		.4720		.4656	.4715	.0012	.0059	.63°
.2(0 510	7 .5085	.5080	. 5086	.5099	.5110	.5032	.5095	.0013	.0063	.43°
.2	0 .543	7 .5437	.5427	.5418	.5426	.5434	.5369	.5430	.0007	.0061	.22°

FIGURE 3-2



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	0	60	120	180	240	300	THEORY	×	α	Δ	TILT°
PARABOLA 0	.000	.0002	.000	0000	.0001	.0002	0				
.22	.000	.0001	.0000	.0001	.0001	.0000	0	-			
.294	.0777	.0759	.0750	.0755	.0765	.0770	.0770	.0763	.0010	(.0007)	.26°
. 305	.0810	.0801	.0797	.0802	.0804	.0800	.0802	.0802	.0004	0	.12°
.438	.1300	.1286	.1283	.1280	.1285	.1289	.1293	.1287	.0007	(9000.)	.11°
.532	.1762	.1765	.1759	.1742	.1764	.1773	.1746	.1761	.0010	.0015	.08°
.633	.2356	.2346	.2342	.2332	.2344	.2354	.2331	.2346	.000	.0015	.06°
.742	.3110	.3087	.3078	.3079	.3082	.3093	.3076	.3088	.0012	.0012	.12°
.844	.3919	.3892	.3883	.3890	.3889	.3910	.3880	.3897	.0014	.0017	.12°
.938	.4755	.4721	.4712	.4722	.4710	.4732	.4712	.4725	.0017	.0013	.14°
1.012	.5342	.5352	.5418	.5424	. 5335	.5359	.5370	.5372	.0039	.0002	8
1.025	.5348	.5347	.5350	.5349	.5349	.5348	.5370	.5349	.0001	(.0021)	.006
HYPERBOLA 0	.4453						.4328	.4453		.0125	
.132	.4776	.4773	.4768		.4767	1	.4656	.4771	.0004	.0115	.13°
.200	.5160	.5156	.5142	.5149	.5149	.5163	.5032	.5153	.0008	.0121	.30°
.250	.5482		.5479		.5489		.5369	.5483	.0005	.0114	.11°
FIXTURE LIP	.0507	.0506	.0504	.0504	.0505	.0506					
							_	-			

FIGURE 3-3

.12°	SECONDARY TILT
.6°	BIRDCAGE TILT
1.8°	CONE TILT
.0118	SECONDARY XY DISPLACEMENT
.005	CONE XY DISPLACEMENT
.0125	SECONDARY + Z DISPLACEMENT
.024	CONE + Z DISPLACEMENT
6'	PRIMARY ARC ERROR
6'	SECONDARY ARC ERROR
31.1°	CONE ARC ERROR (.4)
.0038	BIRDCAGE XY DISPLACEMENT (CELL DISPLACED)

FIGURE 3-4: ELEMENT #12 TOLERANCE ERRORS

.006	SECONDARY XY DISPLACE
.006	SECONDARY X DISPLACE UP
.010	CONE DISPLACE Z UP
.005	CONE DISPLACE XY
.12	SECONDARY TILT
0.8	CONE TILT
0	BIRDCAGE DISPLACE X AXIS
.6	BIRDCAGE TPLT
6	MINUTE PRIMARY ARC ERROR
2	MINUTE SECONDARY ARC ERROR
31.1°	CONE ARC ERROR

FIGURE 3-5: ELEMENT #15 TOLERANCE ERRORS



The cone lower edge was 10 to 20 mils above the cell. This compares to a design goal of zero Z displacement. The cone XY plane offset was measured at 5 mils from the cup center The cone angle designed to be 31.5° , was measured to be 31.1° . The cone as mounted in the birdcage was tilted from the XY plane by 1.3° .

The average measurements above are summarized from Figures 3-4 and 3-5.

3.3.1.2 Measurement of Optical Losses

<u>Primary Mirror</u>. It was noted that there was some rounding of the optic edges at the inside and outside of the primary (Figure 3-6). To see if this contributed to energy collection losses, a number of masks were created to successively shadow more and more portions of the mirror in those positions using the theory that shadowing of unused portions would produce no change in output. The optic was set in a solar tracker specially designed for this application and current output was monitored. Successive masking of the outer edge was performed until a noticeable drop in current was seen. The size of the mask inner diameter was compared to the optic design and was noted to be approximately 19 mils less in radius than the primary mirror outer edge. This represented a 4% loss in collection efficiency from expected.

More masks were placed on the secondary mirror with successively greater diameters until again a noticeable drop in output was noted. This radius represented the unusable portion of the primary mirror near the inner cup edge. The distance, .298 mils or 33 mils greater than the inner cup radius design, represented approximately 2% loss in collection efficiency.

The primary mirror was physically distorted by screwing the edges down in the holding fixture with excessive force to see the effective change in output. A 2.1% loss in output was noted at the extreme range of distortion, estimated at 10 to 20 mils of "squeeze."

20.

<u>Conic Mirror</u>. The gap between the cone and the cell represented an "escape" route for the collected light. To check this the optic was mounted in a fixture such that the cone could be varied from 0 to 80 mils from the surface of the cell. The measured loss was 0.3%/mil of gap for 0 pointing error and with a 15 mil gap, a 14% loss was experienced at 2⁰ offpoint.

3.3.1.3 System Effects

Mirror Reflectance. The reflectance of each mirror has a direct effect on energy throughput. In all positions, the primary and secondary mirrors will redirect the light with some resulting reflectance loss composed of absorbed light and diffusely reflected light not reaching the cell. The amount of light reflected by the cone is a function of offpoint. The AMO reflectance of silver is generally quoted at 95% energy throughput. Since the GaAs cell only responds to light with wavelength between 0.4 and 0.9 micrometer,, the reflectance of the mirrors in this range is of interest and must be used for energy throughput calculations as measured by a GaAs device. То this end, spectral reflectance measurements of primary and secondary mirror samples were made. Based upon these measurements, the effective reflectance in the band 0.4 to 0.9 micrometer, was calculated for solar outputs of AMO, AMI, and The AMO reflectance averaged 0.965 for the secondary and AM2. 0.985 for the primary, and was not significantly different when calculated for AM1 and AM2 standard suns.

<u>Specular Reflectance</u>. Mirror samples were submitted for overall scatter measurements. A measurement is shown in Figure 3-7. The measurement corresponds to roughly 11% loss of usable light in the MCC optical system.

<u>Misalignment Effects</u>. The intention of this test was to get a feel for the sensitivity of the optics to possible assembly misalignments. A MCC element was mounted in the solar tracker and the birdcage containing the cone and secondary were misaligned from the most stable position. Slight movements (5 to 10 mils) of the birdcage resulted in output changes of up to 10% (see Figure 3-8).





Figure 3-8
3.3.1.4 <u>Summary</u>

A summary of the optical testing of the NAS8-35635 design is shown in Figure 3-9 for on point measurements and Figure 3-10 for offpoint measurements.

The many potential loss mechanisms that were apparent could easily account for the nine percent onpoint loss (7%/77%). Offpoint losses for the design could be even worse especially due to the misalignments inherent in any manufacturing process.

3.3.1.5 <u>Electrical Measurements</u>

Electrical output measurements of the optics studied above were reported in NAS8-35635 as 9 to 11% loss in output during onpoint with the expected concentration ratio of 127 not met by the test measurements of ~114. These measurements were reconfirmed. Offpoint testing was also performed as in Figure 3-8 to reconfirm the data.

3.3.2 <u>Analyses</u>

Two analyses were performed to support the investigation and testing of the NAS8-35635 MCC.

3.3.2.1 Specular Reflectance Analysis

A computer model of the MCC element was generated and energy loss due to scatter from the mirror surface was calculated as a function of overall mirror reflectance and RMS surface roughness. The results, shown graphically in Figure 3-11, indicate that surface roughness must be tightly controlled to minimize scatter losses. The NAS8-35635 polished to a "commercial" finish had a finish between 200 angstrom to 1000 angstrom roughness. At 200 angstrom and .98 mirror reflectance, the loss of energy attributable to scatter alone was 0.19 $-[1-(.98)^2] = .15$ i.e., 15%.

3.3.2.2 <u>Tolerance Analysis</u>

The mirror assembly was analyzed for output using the IPAGOS optical analysis program as modified for the MCC system to determine collection efficiency as a function of offpoint. The standard curve for perfectly aligned optics is the one shown for technology development goals. However, since mirrors are

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	Engir TRW 5	% LOSS EFFECT	0.3%/mil	0% all distances	.2% to .7%		up to 10% TOT 58	.9 to 2.1%		6 %		N/A	-5.6%			up to 40% 10 % most likel	0 + 1.5%	19
TRANSMISSION INVESTIGATION		METHOD OF INVESTIGATION	Change gap from 0 to 80 mils distance from cell and measure output. (Note gap _ 40 mils, should be 0)	Tolerance analysis of sub assemblies and piece parts for effect on output.	Test element with and without cone in place. Note any stray light not hitting cell.	Purposely misalign mirrors to see effect on output	IDIEFANCE ANALYSIS AS ADOVE	Distort mirrors while testing. Note types of distortions and effect on output.	Tolerance analysis as above	Shadow various portions of mirror surface to find effect on output. Compare to theoretical effect on output.	Tolerance analysis as above.	Measure spectral reflectance of mirrors.	Calculate mirror reflectance based on cell response wavelengths 0.38 to 0.93 µm and AMO and AMI solar spectrum.	Use modified integrating sphere for direct vs. diffuse reflectance from mirror parts.	BRDF measurement equipment.	Calculate effect of progressively diffuse surface based on surface roughness and spectral reflectance	Check wiring. Check sun tracking capability. Acquire GaAs standard for incorporation into test setup.	
TICAL			1EST	ANAL YSIS	TEST	TEST AMALYSIS	ARAL 1313	TEST	ANAL YSIS	TEST	ANAL YSIS	TEST	ANALYSIS	TEST		ANAL YS I S	TEST	AMAI VETS
JLT - 70 vs. 77% OF		POTENTIAL LOSS MECHANISM	A. GAP BETWEEN CONE AND CELL		 B. LIGHT NOT FOCUSED B. COMPLETELY ON CELL (DISTORTION OR FIGURE IRREGULARITIES) 	C. MISALIGNMENT OF ASSEMBLY PARTS		D. DISTORTION OF MIRRORS (INDUCED BEYOND	TRICTED MIRROR.)	E. MIRRORS OUT OF SPECIFICATION REQUIREMENTS		F. SPECTRAL SHIFT OF	OPTICAL ELEMENTS	G. NON SPECULAR Reflectance			H. TEST EQUIPMENT	T PROCEAM COBAD
EST RESU																		

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FIGURE 3-9

INVESTIGATION
PERFORMANCE
AXIS
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RESULTS
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Engineering & Test Division TRW Space & Technology Group

	POTENTIAL LOSS MECHANISM		METHOD OF INVESTIGATION	% LOSS EFFECT
Α.	GAP BETWEEN CONE AND CELL	TEST	Change gap from 0 to 80 mils distance from cell and measure output. (Note gap $\simeq 15$ mils, should be 0).	1° - 2% 2° - 14% 3° - 38%
		ANALYSIS	Tolerance analysis of sub assemblies and piece parts for effect on output.	1° - 7.6%/10 mils 2° - 13.1%/10 mils 3° - 42%/10 mils
в.	LIGHT NOT FOCUSED COMPLETELY ON CELL (DISTORTION OR FIGURE IRREGULARITIES)	TEST	Test element with and without cone in place. Note any stray light not hitting cell.	1° - 9% 2° - 1% 3°4%
ن ا	MISALIGNMENT OF	TEST	Purposely misalign mirrors to see effect on	ł
	ASSEMBLT PAKIS	ANLAYSIS	Tolerance anlaysis as above.	.3-12 - 3-17
D.	DISTORTION OF MIRRORS	TEST	Distort mirrors while testing.	1° - 5% 3° - 12% 2° - 11% 3° - 12%
	(INUCCED BETOND ALREADY DISTORTED UNRES- TRICTED MIRROR).	ANALYSIS	Tolerance analysis as above.	F.3-12 - 3-17
l Li	MIRRORS OUT OF SPECIFICATION REQUIREMENTS	TEST	Shadow various portions of mirror surface to find effect on output. Compare to theoretical effect on output.	Same as on axis
		ANALYSIS	Tolerance analysis as above	F.3-12 - 3-17
<u>u</u>	PROGRAM ERROR	ANALYSIS	Change method of ray trace inputs to see if variation causes change in offpoint prediction	1° - 7% 2° - 10% 3° ≁ 0%

FIGURE 3-10



Figure 3-11

not ideal surfaces due to inherent piece part manufacturing tolerance allowances, and mirror assemblies further suffer from tolerance allowances, it was decided to investigate the sensitivity of the optic design to these tolerances.

Each mirror component was considered separately and then as a typical composite based on measurements of the optics as assembled from section 3.3.1.1.

Each component was analyzed for the effect on energy collection as a function of translations along three orthogonal axes, rotations about three orthogonal axes and surface allowances as called out in the mirror manufacturing specifications such as the 10 arc minute allowance variation in the figure of the primary mirror or the $31^{\circ} \pm .5^{\circ}$ cone angle allowance.

The results are illustrated in Figures 3-12 to 3-17, for individual components. In some cases, the design is very sensitive to tolerances which are fairly tight in the design. When a combination of factors is considered, the resulting offpoint is illustrated in Figure 3-18. Included in the figure are the test results from two measured optics. The test performance is actually better than that predicted since the prediction assumed all worst case directions for output loss.

3.3.2.3 Optical Design

The design of the conventional Cassegrain system was varied to determine what improvements in offpointability could be achieved without significantly decreasing onpointed output. Results from an IR&D project showed that changing the geometric concentration ratio from the baseline 163 to lower values improved offpointability at increasing loss of optical transmission (Figure 3-19).

If the thickness of the system was allowed to vary, improvements in offpointability could also be achieved (Figure 3-20) but with significant decrease in volumetric packing for launch.

Some slight improvements could be made by varying the conic mirror surface, but none would address the inherent problem of tolerance allowance losses (missing of the mirror entirely).



EFFECT OF SELECTED TOLERANCES ON MCC PERFORMANCE FIGURES 3-12 to 3-17.

Multiple Misalignment Test Case

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ASSY 2 (1984 HDWR)

(1984 HDWR)

80.0

ASSY 1

100.0

(SOLAR INPUT)

TRACKING ERROR (DEGREES)

2.0

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0.00

 $\Delta = 1984 \text{ HARDWARE}$

D = IMPROVED

20.0

LEGEND

- **BASELINE SENSITIVE TO MULTIPLE** TOLERANCES
 - IMPROVED DESIGN SIGNIFICANTLY LESS SENSITIVE

FIGURE 3-18



NORMALIZED ENERGY ON CELL

(1984 HDWR)

40.0

TEST CASE

60.0



R5-00943/04



It was decided to dispense with conventional optical design techniques to achieve offpoint enhancement. Instead, a technique was conceptualized to use portions of the secondary mirror to redirect light from the primary during offpoint conditions toward the cell (Figure 3-21) as well as modify the surface figure of the portions used during onpointing to also direct any remaining offpointed light to the cone and thence to the cell. It was decided to optimize the design for three degrees of offpoint. The NAS8-35635 secondary mirror blockage diameter of 0.564 inches was retained to allow comparison with the NAS8-35635 design even though the actual mirror surface was only 0.50 inches in diameter. After a number of two dimensional iterations of the optic stack surface figures, the resulting operation of the stack in two dimensions seemed satisfactory as shown in Figures 3-22 through 3-24. Except for a very few rays, all rays entering the optic reach the cell.

3.3.2.4 <u>Support Analysis</u>

A three dimensional computer model was constructed for IPAGOS analyses. Calculation of the offpoint performance showed tremendous improvement over the baseline design (Figure 3-25).

The model was analyzed for tolerance effects as was the baseline and again tremendous improvement was seen. Figures 3-12 through 3-17 show the improved capabilities compared to the baseline design. The multiple parameter tolerance buildup was input to the model and again the improvement was great (Figure 3-18).

The secondary mirror was further optimized for output by consideration of changing the angles of the mirror portion devoted to redirecting the offpointed rays. Figure 3-26 shows the effect of varying the inner and outer zones from the baseline.

The design was checked against an optimal hyperbolic secondary which used the full 0.564 diameter of the secondary mirror blockage size for light collection. Cone angle was varied to check for possible synergistic design effects. Figure 3-27 displays the results of this comparison. The new secondary is clearly superior in the quantity of light collected.





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FIGURE 3-23: NEW DESIGN SHOWING RAY TRACE FOR ENTRANCE FROM THREE DEGREES FROM THE LEFT.



3. 20000

FIGURE 3-24: NEW DESIGN SHOWING RAY TRACE FOR ENTRANCE FROM THREE DEGREES FROM THE RIGHT.

Energy on Cell vs Tracking Error Collimated Source*



THING REPORT

Rays Reaching Cell versus Variations of Secondary Offpoint Collection Angles. The New Design is Fairly Insensitive to Figure Errors

OFFPOINT	BASELINE	۸۷	RY ANGLE	•	VARY A	NGLE 2*
ANGLE	(15 ⁰) (30 ⁰)	10 ⁰ (30 ⁰)	20 ⁰ (30 ⁰)	25 ⁰ (30 ⁰)	(15 ⁰) 27 ⁰	(15 ⁰) 33 ⁰
0	4524	4524	4524	4524	4524	4524
2	4286	4286	4286	4286	4286	4286
2.5	4039	4039	4039	4031	4035	4047
m	3698	3698	3698	3686	3680	3718
3.5	3222	3183	3218	3202	3190	3139
4	1686	1600	1680	1662	1647	1260
4.5		806	806	868		
NAME	SEC140	SEC640	SEC540	SEC440	SEC141	SEC142







Figure 3-26



Figure 3-27

New vs Hyperbolic Output

The cone angle for the new system was optimized at 17° . A 17° versus 18° cone angle comparison is shown in Figure 3-25.

3.3.2.5 <u>New Design Optics</u>

The new primary is shown in Figure 3-28. The new secondary is shown in Figure 3-29 and the new cone in Figure 3-30.

3.3.2.6 Part Physical Measurements

New optics were ordered to the design derived in the above analyses. The first articles were measured for surface figure and part tolerances. Since the parts were designed with keying for assembly measurements to these keys were added together for the various components to create tolerance build up potential offsets.

As for the NAS8-35635 design, the positioning of the cell surface and XY placement within the cup, the XYZ positioning of the secondary mirror considering the tolerances measured, and the XYZ positioning of the cone considering the tolerances measured were determined. All part dimensions except for the secondary figure were found to be within the tolerance allowances generated for the part manufacturing specifications (Figure 3-31) from the tolerance analyses. Actual values are given in Appendix A.

A Jones & Lambson EPIC 30 comparator was used to check for figure accuracy of the cone, secondary and primary against an accurate mylar of the drawings in the appropriate magnification range. A casting of the primary was made from the first article which was then checked on the comparator at 10 x magnification. The cone and the secondary were directly checked at 20 x. The primary and cone were within the required figure tolerance. The secondaries (ten in all) deviated from the required figure by varying amounts. Due to schedule constraints, it was decided to use seven of them which were believed to be close enough but not within tolerance, with the intention of checking the effect of the variations by electrical measurements of a single standard primary subassembly which included everything except the secondary and secondary mounting.



FIGURE 3-28 a: THE NEW PRIMARY INCORPORATES MANY IMPROVEMENTS



THERMAL PROPERTIES.



Secondary Reflector - Sheet 2 of MCC-010B

This reflector is a surface of revolution whose profile is defined in the x, y plane by the following table of points. The origin of the x, y coordinate system is defined in Sheet 1 of MCC-010B

<u> </u>	<u> </u>	<u> </u>	X	<u> </u>	<u> </u>
0	0	.099620	.035240	.159421	.068776
.044298	.011870	.101384	.036190	.161206	.069854
.044366	.011889	.103148	.037144	.162991	.070931
.046296	.012430	.104908	.038101	.164775	.072008
.048220	.012990	.106668	.039060	.166561	.073084
.050139	.013569	.108427	.040021	.168347	.074158
.052051	.014167	.110185	.040983	.170135	.075229
.053956	.014785	.111943	.041945	.171924	.076298
.055858	.015423	.113701	.042908	.173716	.077364
.057752	.016078	.115459	.043870	.175508	.078427
.059638	.016752	.117216	.044831	.177300	.079491
.061519	.017443	.118975	.045794	.179092	.080557
.063394	.018152	.120732	.046756	.180882	.081626
.065262	.018878	.122490	.047720	.182668	.082701
.067124	.019620	.124247	.048684	.184450	.083782
.068979	.020379	.126004	.049650	.186227	.084872
.070827	.021153	.127759	.050616	.187998	.085972
.072669	.021943	.129514	.051584	.189761	.087084
.074505	.022749	.131268	.052554	.191515	.088210
· . 076334	.023569	.133021	.053526	.193259	.089351
.078156	.024403	.134772	.054500	.194993	.090508
.079972	.025250	.136522	.055477	.196715	.091681
.081782	.026110	.138270	.056456	.198431	.092865
.083586	.026982	.140017	.057438	.200141	.094056
.085385	.027865	.141763	.058423	.201851	.095248
.087179	.028758	.143506	.059411	.203564	.096436
.088968	.029661	.145248	.060402	.205279	.097621
.090752	.030573	.146987	.061398	.206995	.098804
.092533	.031493	.148724	.062397	.208712	.099986
.094309	.032420	.150484	.063415	.210429	.101168
.096083	.033355	.152275	.064482	.210445	.101178
.097854	.034295	.154063	.065552	.282101	.142548
		.155851	.066625		
		.157636	.067700		

FIGURE 3-29b: EQUATION FOR THE SECONDARY MIRROR SURFACE



ASSEMBLED ITEM	2.5°	3°
XIS DISPLACEMENT OF SECONDARY	0.002	.0005
DISPLACEMENT OF SECONDARY	.0025	.0005
IF SECONDARY	.05°.0005 spid∆ .0025 para∆	.02°
XIS DISPLACEMENT OF CONE	.002	.0003
L SURFACEMENT OF CONE RELATIVE	.0035	.0003
IF CONE	.7° (2 mils ∆)	•6°
DEVIATION OF PRIMARY	1'	.5'
DEVIATION OF SECONDARY	> 10'	3.5'
DEVIATION OF CONE	 1° 	.05°

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ASSUME 1% LOSS AT ANGLE ALLOWED PER ITEM FOR TOTAL 8/5% LOSS AT ANGLE. DOUBLE ALLOWED LOSS GIVE DOUBLE TOLERANCE ALLOWANCE.

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Figure 3-31. Tolerance Allowance

3.3.2.7 Optical Measurements

The specular reflectance of a primary mirror sample was measured to be a factor of ten improved over the NAS8-35635 hardware before coating and a factor of five improved after coating (Figures 3-32 and 3-33). As required, all mirror edges were sharp and no unusual surface variations were observed. Testing for poor output portions of the mirror due to surface or figure variations was therefore not required.

The gap between the cone and the cell was set at 8 \pm 1 mils by the cover and adhesive (see cell stack design).

3.3.2.8 Concentration Ratio Check - Energy Throughput

Two optics were measured for energy throughput by measuring current of the cell with and without the secondary in place. A mask with a hole the size of the cell active area was placed over the cone to measure 1 sun output without the secondary in place, then the mask was removed, the secondary was replaced, and the total MCC element output at concentration was measured.

The measured concentration ratio was 114 and 117 versus an expected concentration ratio of 134.7. When corrected (section 3.3.2.13) for known deficiencies in the conic mirror (see Coatings), the CR became 134.4.

3.3.2.9 Element Performance

The offpoint performance of three MCC elements was measured (Figure 3-34). As expected, the performance was significantly improved over the NAS8-35635 hardware, though slightly lower than predictions. The lower offpoint output was subsequently explained to be due to conic mirror coating deficiency (see Coatings). At this time, the decision was made to continue with the design into Phase 4, complete population of the deliverable panels with MCC elements of the new design.

3.3.2.10 <u>Coatings</u>

It was not the intent of the design program to address coating applications. Only data and design concepts which were applicable to this design and available from scientific or engineering literature were incorporated into the design. A brief summarization follows.



THE PREVIOUS DESIGN.

Time of sample run: 5:15 PM WED., 16 JULY, 1986 JULY, 1986 Light source - White light 0.0 SOLAR CELL MIRROR, MCC [2] Angle of incidence = KODAK WHITE STANDARD Time of standard run: 3:50 PM WED., 16 File = SST04555 / VI SPECULARITY OF THE NEW MIRROR REMAINS FIVE TIMES BETTER THAN THE PREVIOUS DESIGN AFTER COATING. Standard title: Sample title: Comments: KRUER 60.00 40.00 ļ DEGREES OFF SPECULAR 1 i ł ţ ; -40.00 FIGURE 3-33: 1 + + + 10 - 60.00 다. 다. 다. 북088 분 1 101 ٦_۴ ۲





Figure 3-34: MCC Off-point Curves for LIPS III Hardware

Optical Coatings. The coatings required for this design were identical to those for contract NAS8-35635 hardware. Silicon oxide of 1700 Å was vacuum deposited over 1600 Å of silver which was vacuum deposited on the reflective nickel surface of the mirrors (Figure 3-35). The SiO coating is projected to be able to protect the optic from atomic oxygen effects based on extensive analyses performed by many companies and NASA centers nation wide. Other coatings such as indium tin oxide are also acceptable and can be incorporated as they are defined and tested.

<u>Protective Coatings</u>. Only the solar cell interconnect with silver metallization is subject to environmental attack in this design. A thin coating of silicone adhesive could be used for protection. It was not included in the present design.

<u>Thermal Control Coatings</u>. An added task to the design was the incorporation of S13GLO paint for thermal control of the MCC element. This silicone based white paint was used to coat the back (sun facing) surface of the secondary mirror, the sun facing surface of the spider mount for the secondary mirror (Figure 3-36) and the back surface of the primary optic (Figure 3-37).

Standard procedures using solvent wipe of the nickel and aluminum surfaces prior to a spray paint coating with the S13GLO were found to be sufficient for good adhesion of the paint to the painted surfaces. To test for adhesion, a MIL SPEC procedure was followed which consisted of scribing the painted surface of a sample, applying tape, and pulling the tape from the sample. No failure occurred. The sample was thermal shock cycled 100 times from -192° to $+60^{\circ}$ C. The tape test was performed again and no adhesion failures were observed.

Other Considerations

 <u>Primary and Secondary Mirror Coating Quality</u>. The adhesion of the optical coatings was of varying quality. The mirror vendor used two vendors as coating subcontractors but did not maintain traceability. Subsequent assembly of the primary and secondary mirrors incorporated the use of a protective and cleaning polymer which was spread on the surface, let dry, and removed with tape. When the polymer coating was pulled off, the surface coating of some



FIGURE 3-35. COATING SEQUENCE FOR OPTIC SURFACES (Primary sub-assembly without spider shown)



Figure 3-36. Front of New Element Shown While Operating, Spider and Secondary Back are Painted with S13GLO.

OR POOR QUALITY



Figure 3-37.

Back of MCC Element Showing Mounting Position, Solder Bonds for Electrical Interconnection, and Complete S13GLO Coating. primaries and secondaries (portions of the SiO and SiO+Ag) were removed as well. Discussion with the vendors determined that the coating adhesion should have been much greater than the adhesion of the polymer, and that the failures were most likely attributable to insufficient surface cleaning prior to The only fix available was to strip and then coating. re-deposit the coatings. Since the effect of stripping on the mirror surface was unknown (such as potentially roughening the polished surface), and the damage was apparent on only a few optics, it was decided to leave the coatings as is without testing the remaining coatings. Temperature shock testing of a mirror already showing partial coating failure did not induce any further degradation or removal of the coatings. Coating failures from thermal cycling or other stress during NASA testing will not be considered as design failures since an in-place acceptance test would find coating manufacturing problems for any flight optics. The use of the polymer as an acceptance test is recommended for such acceptance testing.

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Conic Mirror Coating Quality. All conic mirrors were visually inspected for coating defects such as missed or darkened sections or localized haziness. Coating quality in terms of absolute reflectance was not measured. After the measurement of offpoint performance of a large number of optics showed significantly high losses at small offpoint angles, test data was reevaluated to determine the cause. Data for output of the cell stacks with a cell sized mask was compared to output of the cone and cell combination with no secondary mirror (Figure 3-38). Since all light entering the cone would be absorbed by the cell, the reflectance of the cone could be backed out of the measurements as shown in Figure 3-39. Data for four optics showed that the conic mirror reflectance only achieved 65 to 70% in the 0.4 to 0.9 The reasons for this micrometers GaAs response range. were unknown. However, after questioning the coating vendors, it was found that a "proper" mounting procedure in the coating chamber to guarantee uniform coating quality was not used due to schedule and cost pressures from the electroforming vendor. The physical reason for the loss whether due to scatter or absorptance should be investigated. It is known that the loss is not caused by contamination. A series of cleaning fluids, acetone followed by freon followed by isopropyl alcohol, had negligible effect on most conic optics. Those improvements that were measured only increased total reflectance of the cone from 0.65 to 0.67 in a limited number of cases.

To check the extent of the low conic reflectance, all 180 optics to be mounted in the large deliverable panel were checked on an X25 solar simulator for total reflectance as measured by the GaAs cell in the



FIGURE 3-38 METHOD FOR FINDING SPECULAR REFLECTANCE OF CONE.

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FIGURE 3-39 Conic mirror to cell output ratio as a function of cone reflectance.

subject optic using the same methods as outdoor sun tracking testing. The range of reflectance was measured to be 59 to 71% with an average of 66% and a standard deviation of 5%. The $\pm 5^{\circ}$ illumination angle from normal as is typical for the X25 due to geometry of the simulator did not skew the results since even 5° illumination angles for light rays would still reach the cell.

The effect of the low conic reflectance was checked in the previous tolerance analyses by looking at the total light reaching the cell via the cone for all pointing conditions. Figure 3-40 is a plot of the percent of light versus pointing angle for the new design which first bounces from the cone. It was obvious that the conic mirror was as important as the primary and secondary mirrors when considering the total system performance.

Using the average measured cone reflectance it was possible to recalculate from the test data the normalized offpoint characteristics of the MCC elements, substrings, and modules if the conic mirror had been 97% reflective. The absolute output of the onpointed and offpointed elements could be similarly corrected. All plots of output versus offpoint for the small and large panel strings were corrected accordingly. The plots showed very good agreement with the response as analyzed during the tolerance analysis. Variations due to other electrical effects are discussed in section 3.3.2.11.

3.3.2.11 <u>Electrical/Optical Test Results of the Improved MCC</u> <u>Element</u>

Measurements of individual optic/electrical performances, performance of strings of a single element in parallel by six elements in series, and 5 elements in parallel by six in series were made using the solar tracker and mounting hardware designed especially for this application (Figure 3-41). All measurements were corrected to 1 sun AMO exposure using a GaAs standard cell and were further corrected for temperature based upon readings from thermistors mounted on the back of two randomly selected elements.

<u>Output Variation with Multiple Secondary Mirrors</u>. The "proof" secondaries were tested for variations in offpointability using a single primary subassembly. Figure 3-42 shows the performance of each of the seven accepted secondary mirror samples from the separate electroforming tools as corrected for the cone reflectance losses discussed in the "Coatings" section. The variability is fairly significant in terms of expected offpoint

Total Fraction of Light to Reach Cell Which Is First Redirected by the **Conic Mirror (Zero and Typical Tolerance Allowances Shown)**



Figure 3-40

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Figure 3-41. Both Deliverable Panels were Tested Using a Solar Tracker, Adapted from a Celestron Telescope Mount.


K+E 10 X 10 TO ¹2 INCH+2¹⁵ X 10 INCHES Keuffell & Esser co wantingsa performance of a mixture of the secondaries but it is important to note the relatively flat response each achieves for three degrees of total offpoint, near the center of the performance band.

3.3.2.12 <u>Multi-Element String Measurements</u>

Full current voltage (IV) curves were generated for each six cell in series substring located on the small and large deliverable panels. Zero degrees through three degrees and in some cases up to five degrees variation from normal sun were measured using a NORLAND 3001 data acquisition system with a fast load, and a concentrator one sun standard traceable to a balloon GaAs standard. The pertinent data from all measurements are located in Appendix A.

Offpoint Performance. The optics for the small 35 x 53 cm panel were chosen from optics with the initial high efficiency (>20.6%) cells available from ASEC. As expected, some loss due to matching of efficiency rather than matching of current at a set voltage was encountered. Essentially, each string is limited by the lowest MCC element current performance, which is in turn a combination of absolute cell output after assembly, mirror tolerance buildup effects on light collection efficiency and relative pointing of each of the elements. An ideal measurement of a well matched string is shown in Figure 3-43 for one substring. Figure 3-44 shows the effect of current limiting on the IV characteristic of another string. The sudden current increase near short circuit with a sharper knee indicates mismatching of output is occurring within the string. Figure 3-45 shows even greater mismatching to occur. A single MCC element which was found to be significantly low in output in string 3B was measured for the reverse voltage of the element as a function of string loading (Figure 3-46). The low output element ran quite hot in reverse as expected, but did not degrade after more than three minutes in the condition of approximately three volts at 300 mA across the cell.

The normalized offpoint performance of each of the strings of the small deliverable panel as corrected for conic mirror poor reflectance is shown graphed in Figures 3-47 and 3-48.



HON TO X 10 TO 15 INCH + 715 X 10 INCHES REUFFEL A ESSER CO. HART MUSA

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K-E 10 X 10 TO 15 INCH + 715 X 10 INCHES



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HOE TO X TO TO 15 INCH + 74 X TO INCHES METRELET & ESSEN CO. WAR IN USA

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FIGURE 3-46 REVERSE BIAS TEST OF ELEMENT WITHIN STRING IN NATURAL SUNLIGHT (NO CORRECTIONS)

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STRING 3B

		CONDITION	
String Voltage	<u>A</u>	<u>B</u> 2.96V	<u> </u>
	1.001	2.301	4.551
String Current	300mA	300mA	294mA
Voltage Element 7	.816	.790	.842
8	.868	.840	.867
9	.890	.880	.893
10	.844	.780	.869
· 11	-2.78	-1.23	589
12	.886	.900	.915
Mismatch	5.5%	6%	4.2%
Excluding #11			



KON NO X 10 TO 10 INCH 213 X 10 INCHES



KeE to X to TO 15 INCH - 15 X to INCHES

Paralleling of two sets of substrings into two groups for measurements with five elements in parallel by six elements in series was performed. The measured output of the groups were compared to the expected output based upon the individual component substrings within the group. Excellent correlation was found (see Figure 3-49).

3.3.2.13 Correction Methods for MCC Element and String Test Data

All test data was corrected for known test conditions and test item deficiencies.

<u>AMO Sun</u>. The correction to AMO sunlight was simply accomplished by using test standard composed of a GaAs concentrator cell calibrated to a balloon flown GaAs primary standard. The GaAs test standard was monitored continuously during test of the test items.

 $\frac{\text{Std AMO}_{cal. value}}{\text{Std Test}_{value}} \text{ x test item reading = corrected reading}$

<u>Temperature</u>. The correction for temperature for panel string tests was accomplished by mounting two thermistors to the back of randomly selected elements on the panel, and reading the resistances on Fluke 8060A calibrated meters. Each resistance was compared to a resistance versus temperature calibration chart (Figure 3-50) to define the base temperature, and then 6° C was added to the readings due to the known temperature difference between the cell and the thermistor mounting position including bond thermal resistance.

The current correction factor used was $0.045\%^{\circ}C$. The voltage correction factor was $-1.6 \text{ mV}^{\circ}C$. The factors were derived from thermal testing of two elements on the panel while on the solar tracker. Both factors corresponds closely with data available from GaAs cell literature.

 V_{meas} + (T-28)(-1.6 mV/^OC) = $V_{correct}$ I_{meas} x [1 + (T-28)(.0045)] = I_{correct}

Conic Mirror Reflectance

 Based on Figure 3-40 and assuming typical tolerances apply to the onpointed MCC element output, the correction for conic mirror reflectance rho at 0^o is:





OFFPOINT ANGLE (DEGREES)

ကု

m



 $\frac{\text{current}}{(.41 \text{ x rho}) + .59} = \text{corrected current}$

0

For offpointing measurements, the perfectly aligned optic reflectance curve was used to correct the measurements.

Data presented for offpoint check was only corrected using the perfectly aligned optic correction. The result is that in many cases, the output at offpoint angles was corrected to be greater than the 0° offpoint condition.

For onpointed measurement for concentration ratio and absolute output of the elements, the 41% conic reflection represents a maximum and will vary between 25 and 41%. Similarly, the reflectance of the cones vary between 59 and 71% with an average of 66%. Therefore, the range of correction factors is as follows:

 $\frac{1}{(.41 \times .59) + .59} = 1.202$ high $\frac{1}{(.25 \times .71) + .75} = 1.078$ low $\frac{1}{(.36 \times .65) + .64} = 1.144$ average Corrections for groups of elements in strings have a higher probability of being near the average values.

<u>Mismatch Effects</u>. Cell mismatch for the concentrator design is complicated by the additional consideration required due to variability of manufactured element tolerance effects. A high efficiency cell matched with a less quality optic may be equivalent to a lower efficiency cell in a high quality optic, but this would change as a function of offpoint. Conceptually, this is illustrated in Figure 3-51. Therefore, it can be expected that if low mismatch losses are desired, extensive testing and matching of a large population of MCC elements would be required.

Due to the small population of MCC elements available for this contract, the variability of the assembly tolerance effects, and the need for a dedicated grader for MCC element output which was not available, and the short time available for assembly and test, elements for the small deliverable panel were kitted into strings according to cell efficiency measured after the welding process used for electrical connection of the contacts.

Illustration of Mismatch Caused by Cell Efficiency Combined with Mirror Offpoint



Figure 3-51

A = HIGH CELL η , WORSE OFFPOINT CAPABILITY B = LOW CELL η , BETTER OFFPOINT CAPABILITY

AT 0°, B LIMITS CURRENT AT 2°, A LIMITS CURRENT The MCC elements were mounted in the panel and tested. One shorted element was subsequently removed and replaced. Offpoint testing was performed. The panel was later tested for the output of each element at short circuit and open circuit. The results of that test, presented in 3-52, show a number of elements with substandard output at short circuit. The mismatch which results, especially due to current limiting as seen in the current voltage (IV) curves of Figures 3-44 and 3-45, directly reduces the maximum power of the tested string or strings.

As a rough approximation, the short circuit current of each of the elements in a string can be averaged to get an average string current which may then be divided into the lowest element short circuit current in a string to derive an effective mismatch, all assuming the open circuit voltage of the elements are very close in value.

Shown in Figure 3-52 are the average current for the six cell string, the calculation of mismatch for the string, and the calculation of average mismatch for all the strings, which is 7.7%.

For the larger deliverable panel, all 180 elements as completed were measured for current at 85% of open circuit voltage using the x25 solar simulator and matched as best as possible prior to assembly into the panel. As an additional complication, the cells from the three cell vendors were kept in separate strings. It was noted that the MCC elements with Varian cells were particularly poor in output due to the welding difficulties encountered (section 3.4.2.3).

Min/ Avg	.837	.948	923		
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M	1048 1022 1052 1055 1058 1058	1056 1059 1057 1055 1033 1031	ie of Mi		
MCC	чом400 ×	7 88 111 121 121 7	AVERAC		
String	5A	8			
Min/ Avg	.915	.936	.835	.942	
ШA	452 438 430 430 420 422 422 425	421 392 394 432 438 438 438 438	442 355 416 450 452 432 432 425	425 405 445 437 437 435 435 430	
ŊW	1039 1066 1069 1079 1071 1071	1073 1074 1079 1073 1067 1082	1062 1053 1026 1031 1049 1058	1058 1051 1051 1053 1053	CULATION
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MCC	-100400 ×	× 10 9 8 4	× 004000	7 88 10 11 12 X	3-52:
String	IA	18	ZA	28	FIGURE

3.4 CELL STACK DESIGN AND INVESTIGATION

The baseline design for electrical interconnection was soldering of both the top and the bottom connections as was performed for the MCC element designed under NAS8-35635. It was noted under that contract that significant degradation of the current and voltage was experienced by the cell after soldering. Measurements were performed under 1 sun AMO.

To determine the possible causes, various portions of the stack assembly process were investigated. Figure 3-53 records the investigation areas. A plan was developed to test the cells for gross effects. The bare cells were tested at one sun AMO. A number of configurations using solder versus no solder were run through heating cycles as used for the cell stack assembly. Samples were heated in both vapor phase solder station (VPS) and a hot plate. In most conditions the samples degraded similarly to those in contract NAS8-35635. The sample size was large enough to show that soldering was the degrading mechanism. The results are shown in Figure 3-54. Average losses were computed for the various processes by combining data of similar origin. For example all cells with solder on the front contact were grouped together, ignoring other factors in the process such as mounting method. This enabled gross judgements of defect mechanisms. As a second refinement, successively greater narrowing of the error band and grouping of the cells within the band, helped establish that it was the soldering process itself that was causing the degradation and probably the front contact solder bond.

Subsequent discussion with the vendors indicated that unlike silicon, GaAs will be wet by solder. Therefore, in any environment where the solder cannot be precisely controlled, a potential for solder flowing over the GaAs and shorting the junction exists. Both the hot plate and the vapor phase solder method are not precision controlled for solder placement.

The soldering process (front contacts versus rear contacts) was investigated by substituting another process for the soldering and checking the results. In parallel with this, the mechanism of degradation caused by the solder was investigated. Effort was concentrated to make connection on the front contact. The options were soldering, welding, and adhesive bonding.

INVESTIGATION
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Engineering & Test Division TRW Space & Technology Group

Α.	CELL JUNCTION DEGRADATION	TEST	Put cell stack in various stages of assembly through vapor phase reflow equipment. Use oven heated and unheated cells for control.	3 - 60%
а. В	TEST EQUIPMENT ERROR	TEST	Review test procedures for error pro- pagation. Test cell output. Test cell output. Modify test fixture. Test cells again. Calibrate X25 simulator for uniformity in test area.	0 2.5% (1) <u>+</u> 1.5% (1)
ن ا ن	TEMPERATURE UNCONTROLLED	TEST	Attach thermocouple to cell and MCC element back. Calibrate temperature gradient. Check output against temper- ature reading.	0.7% (V)
	SPECTRAL SHIFT AFTER HEATING. USE OF SILICON STANDARD.	PROCUREMENT TEST	Acquire balloon traceable GaAs standard cells. Compare output using Si standard vs out- put using GaAs standard.	N/A +1.5%

FIGURE 3-53

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process (except heating)

Figure 3-54

Oven = all cells heated in solder reflow oven Plate = all cells heated on hot plate Process = all cells put through some part of soldering no Process = all cells not put through some part of soldering

no Front = all cells with no solder melted onto front contact
Flux = all cells using flux during solder operation
no Flux = all cells not using flux during solder operation
Oven = all cells heated in solder reflow oven

Front = all cells with solder melted onto front contact

40 = all cells exposed to 410 F(210 C) for 40 seconds BeO = all cells mounted on BeO insulator/thermal conductor no BeO = all cells not mounted on BeO Cu = all cells mounted to BeO and copper plate no Cu = all cells not mounted to BeO and copper plate Back = all cells with solder melted onto back contact no Back = all cells with no solder melted onto back contact

20 = all cells exposed to 410 F(210 C) for 20 seconds

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3.4.1 Solder Investigation

It was surmised that the solder was flowing over the top edges of the GaAs wafer and shorting the exposed junction at the edge of the cell. As a first attempt to control this perceived mechanism, a number of cells were sent back to the supplier, ASEC, and an SiO coating was applied to the sides of the cells.

Assembly of some of these cells in the VPS station yielded no better results than before. Since the back contact of the cell was required to make full-intimate contact with the heat sink, and solder was the best viable material, elimination of the uncontrolled VPS method was not considered practical. After success with another process (welding) was established, further process investigation was halted.

3.4.2 Alternate Bonding Methods

Any method to bond the top contacts had to be able to survive a vapor phase solder reflow process without debonding or shorting the cell. The reflow would be used for the bottom contact and/or the heat sink to primary bond.

3.4.2.1 Adhesive Bonding-Top Contacts

A silver filled adhesive was identified as a potential alternate to solder. Epoxies, polyimides, and even ceramics were considered. These processes were to be investigated in another ongoing program for which the results were made available. No effort was spent on this contract on these alternatives. The ceramic adhesive has good promise. The other adhesives degraded greater than 5% in thermal cycling. Scatter of the data was high.

3.4.2.2 Gold Germanium Eutectic

A gold germanium eutectic (350°C flow) was also considered but again results were available from another program. The bonds could not be made without significant degradation.

3.4.2.3 <u>Welding</u>

Since it was clear that soldering would not be viable with cell top contact installation, welding, a method with which TRW has had considerable development experience on silicon but not with GaAs was attempted. Initial trials developed good bonds but shorted the cell. The weld voltage was decreased until a good bond was retained and average cell maximum power point degradation was less than 1.2% (Figure 3-55). Testing was performed with a LAPSS moved to a range corresponding to 100 suns AMO exposure. The weld voltage range to maintain good electrical and mechanical bonding was more narrow than typically used ranges for silicon cells.

It was found that the weld schedule for GaAs was very specific to the cell manufacturer, most likely as a function of both cell construction and metallization method. For engineering purposes, an individual weld schedule was developed for each the ASEC, Spectrolab and Varian cells, without further investigation into exact weld metallurgy phenomena. The weld schedule for each vendor is shown in Figure 3-56.

Both the ASEC and Spectrolab cells had silver final metallization on the front and back contacts. The Varian cells had gold contacts. Contact metallization material was not specified for the cells for this application due partly to the original assumption that the cells would be soldered.

The silver interconnect to silver contact weld achieved the highest consistent weld strength of greater than 1 kilogram pull (shear only). An attempt to weld silver interconnects to the gold contacts was not successful due to the very low (<.05 kg) pull strength. Therefore, additional unplated interconnects were plated with gold of the same thickness as the silver interconnects and welding was again attempted. The resulting welds were significantly lower in strength (<.4 kg) and good adhesion was very difficult to attain without significant degradation of the cells (>10%) as evidenced by the extremely narrow weld schedule. Backing off of the time and increasing the voltage, and increasing time with decreased voltage compared to the baseline weld schedule yielded even worse results.

	WELD	SCHEDULE			ELEC	TR. BEF	ORE		ELECT	R. AFTE	R	
GaAs CELL NO.	VOLTAGE (V)	TIME (MS)	PRESS (Kg)	Isc (MA)	Voc (V)	Pop (MW)	PULL STRENGTH (1b.)	Isc (MA)	Voc (V)	Pop (MW)	PULL STRENGTH {1b.)	PA/PB
27	.56	100	1			346.7						0
9	.56					341.7				335 .3		.981
21	.56					338.7				342.9	5.0I	1.012
31	.56					348.0				347.7		. 999
51	58					343.0				337.5	2.8W	.984
80A	.58					341.6				336.8		.986
56	. 58			4		342.9				342.7		. 999
28	. 58					347.7				335.9		.966
43A	.60			1		335.0				332.7		.993
88	.60					340.0				333.2	1.00	.980
24	.60					344.2				345.4		1.003
23	.60					336.3				332.5	3.2W	. 989
36	.60					332.4				329.3		.991
10	.60					346.9				341.3		.984
5	.60					335.2				329.7		.984
70	.60					338.3				335.9	4. 5C	.993
49	.62					344.2				343.9		.999
41	.62					324.4				326.9	3.7₩	1.008
83	.64					339.3				338.7	3.5W	.998
4	.70					341.6				337.0	5.5W	.987
95	.72	100	1			335.1						0
1	DURAT (DIAL)	APLIT. (DIAL)	PRE SS (1b.)						(9%	5 Shorte	ed) Average	.991
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21						347.9						0
13	1					339.5						0
53						335.6				314.8		.938
55A						332.9				332 1	5.51	.998
16	8	5.5	+			341.2				342.3		1.003

FIGURE 3-55: CELL PERFORMANCE TEST (100 SUN FLASHER INTENS., ROOM TEMPERATURE) BEFORE & AFTER WELD/SOLDER OF FRONT CELL CONTACT

(30% Shorted) Average .978

* EDGE COATED CELLS/NO = SHORTED CELLS



Although the degradation of output of the Spectrolab cells was slightly greater than the ASEC cells after welding, the sample size was insufficient to determine if this was significant. No more cells were available for these experimental purposes.

All future subcontracts to vendors will require the cell to be silver metallized since the silver welds were so successful and there is no compelling reason to retain gold contacts.

3.4.2.4 Stack Subassembly

Pretested welded cells were placed in a VPS fixture to bond the cell to the heat sink with a one mil solder preform between the cell and heat sink. The preform was slightly smaller than the cell. After soldering, the cells were tested. Degradation averaged only one percent (Figure 3-57). The welded front contact with VPS rear contact was made baseline.

Thermal shock testing (100 cycles, liquid nitrogen to 100°C) showed no additional degradation of the substacks.

3.4.3 Electrically Connected Versus Isolated Cell Stack-Heat Sink

The heat sink for the solar cell could be made either electrically conductive or insulative. The heat sink exists to isolate the brittle cell from the thermal expansion mismatched copper nickel mirror. The heat sink is required to have an expansion coefficient very near to that of the GaAs cell to minimize stress on the cell.

A molybdenum sink would provide a conductive path to the MCC mirror. An alumina or beryllia sink would provide insulation from the mirror.

In light of the goal of low cost and light weight a comparison was made between advantages and disadvantages as shown in Figure 3-58.

Clearly, an electrically insulated design is most desirable since it simplifies control of the electrical power without compromising the design of the conductive graphite substrate and mirror mounts.

SOLDERING OF CELL REAR CONTACT TO BE BEO SUBSTRATE CELL PERFORMANCE BEFORE AND AFTER VAPOR PHASE

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R P AFTER /	Pmp P BEFORE	`	32.7	42.8 .990	39.6 993	28.3 286	31.8 .986	26.7 .986	39.0 390.	21.0 979	38.0 .985	42.8 .994	16.0 .972	
ICAL AFTE	Voc ((1.075 3	1.080 3	1.076 3	1.081 3	1.082 3	1.066 3	1.077 3	1.080 3	1.077 3	1.077 3	1.079 3	
ELECTR	Isc (mA)		363.1	370.9	368.8	356.2	358.5	370.9	371.6	364.5	369.5	373.3	353.4	
FORE	Pmp (Mm)		335.2	346.3	342.1	333.0	336.5	331.2	342.4	328.0	343.0	344.7	325.0	
I CAL BE	Voc (V)		1.0/3	1.080	1.076	1.080	1.082	1.066	1.075	1.080	1.078	1.076	1.082	
ELECTR	Isc (mA)		364.4	371.2	370.4	357.4	359.3	371.3	372.9	366.6	370.4	375.7	357.7	
	TIME (SEC)	•			15					15			70	
OLDER	TEMP. (°F)				419					320			428	
S	TYPE				Sn62					INDALLOY	#2		INDALLOY #3	
GaAs	CELL No.	ç	87	30	10	6	80	43	56	36	49	24	2	

FIGURE 3-57

Indalloy #2 Pavg = .987

Be0

ALUMINA

MOLYBDENUM

THERMAL CONDUCTANCE Btu	120	18	84.5
ELECTRICAL CONTROL	ISOLATED	ISOLATED	DIFFICULT
TEMP COEFFICIENT(Cm × 10 ⁻⁶)	5,9	6.4	5.04
ELECTRICAL CONNECTION	Requires Metallizing	Requires Metallizing	Requires Metallizing
DENSITY(<u>9</u>)	3.9	3.94	10.2

FIGURE 3-58: CELL HEAT SPREADER TRADE

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Beryllia was selected over alumina due to its high thermal conductivity and hence, lower effective operating temperature. The cost of alumina versus beryllia is not significant once the cost of metallization and high precision manufacturing are factored into the total cost.

The heat sink is shown in Figure 3-59. The two isolated metallized pads were provided before it was found that no mechanical attachment of the cone to the heat sink would be required. The pads will be eliminated in any future procurement.

3.4.3.1 Heat Sink Bond

The heat sink was bonded to the primary mirror using the vapor phase solder method. A pre-fluxed preform of 1 mil Sn62 solder was held tightly between the heat sink and the nickel surface of the mirror in a specially designed tool which was then lowered into the vapor phase station.

3.4.4 <u>Coverglass</u>

A coverglass (Figure 3-60) was incorporated into the cell stack to protect the cell from electron, proton, and other corpuscular radiation. Protection from atomic oxygen is also provided. The cover material was antireflection coated CMX, a ceria doped borosilicate glass manufactured by Pilkington, Great Britain. CMX was chosen over fused silica due to cost, wide use in other programs, and better thermal expansion match to GaAs, and to the nickel conic mirror.

3.4.5 Cover Adhesive

The cover adhesive is Dow Corning 93-500 silicone. This adhesive is standard to the solar array manufacturing industry. Adhesive bonding was chosen over mechanical capture of the cover over the cell. The darkening of this adhesive in this application should be investigated and is recommended for any future contract.

3.4.6 <u>Conic Mirror</u>

As defined in the Statement of Work for NAS8-36159, the conic mirror is considered part of the cell stack. A number of options were considered for mounting of this mirror to the cell





stack (Figure 3-61). A cover with metallization could be used to solder from the cone to the cover. Potential thermal mismatch stresses, cost of the specialized metallization process (even for over 100,000 units), and loss of cone to cell optical centering flexibility, excluded this choice. The cone to heat sink solder bond was excluded due to added complexity of a new part and lack of precise positioning control in the soldering process. Direct soldering of the cone to the glass was considered. Indium solders wet well to glass but the process required (brushing with a metallic brush wet with the solder at elevated temperatures) made this impractical. Adhesives which were considered are shown in Figure 3-62.

DC93500 was a low strength candidate chosen chiefly for its low (around -120°C) glassing point, lower than the -80°C temperature minimum expected in a low earth orbit for the array. This would yield low glass to nickel strain and therefore little likelihood of failure under thermal cycling. DC61104 was chosen for its higher strength, and low temperature compliance. Lefkoweld epoxy was chosen for its resilience and availability as well as experience with flight space- craft. Another epoxy (EA934) was considered as a stronger material, but it had somewhat less resilience. Of the cone to cover adhesive bonding methods, the Dymax 628T ultraviolet curing acrylic adhesive was selected for high processibility, relative low thermal stress, and high strength. Considerable mechanical and thermal cycle stress testing was performed to assure the capability of withstanding a LEO environmental exposure.

3.4.7 Cell and MCC Element Electrical Interconnections

The cell stack electrical interconnect designs were patterned after similar TRW manufactured interconnects used on flight hardware. The cell top contact interconnect (Figure 3-63) was a plated kovar material chosen for thermal expansion match to GaAs. The physical configuration incorporated two bonding pads at the corners of the cell, and an out of plane thermal expansion loop.

The interconnect for the back contact (Figure 3-64) was designed to pick up the gold plating electrical path on the beryllia heat sink upon which the cell backside was soldered.

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Cell Stack Mechanical Attachments Investigated

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PRESENT CHOICE	SELECTED	SELECTED	N/A	SELECTED	SELECTED
VIEW					
TIONS	MECHANICAL CAPTURE	SOLDER	ADHESIVE	ADHESIVE	PRESS FIT.+ BOND
10	ADHESIVE	ADHESIVE	SOLDER	SOLDER	SOLDER
e Joined	CELL	COVER	BeO	PRIMARY	PRIMARY
PARTS TO B	COVER	CONE - OR -	CONE	BeO	TERMINALS

Figure 3-61

CONSIDERED BEST MANUFACTURING OPTION

					_	_	-	-	
	MFG HANDLING	Y I ELD STRENGTH	TYPE OF BOND	RESIL IENCE	ADHESION	OXYGEN ATOMIC	THERMAL CYCLE TEST	OUTGASSING	RADIATION RESISTANCE
RTV 3145	FAIR	450 PSI	TACK	G00D	EXCELLENT	EXCELLENT	PASSED	POOR	EXCELLENT
DC93 500	600D	300 PSI	FULL	GOOD	FAIR TO POOR	EXCELLENT	PASSED	GOOD	EXCELLENT
DC6-1104	FAIR	400 PSI	TACK	600D	GOOD TO FAIR	EXCELLENT	PASSED	G00D	EXCELLENT
LEFKOWELD EPOXY	FAIR	2200 PSI	TACK	VERY GOOD	EXCELLENT	~.	PASSED	FAIR	G00D
EA 934	FAIR	3500 PSI	TACK	FAIR (Brittle)	G00D	ċ	PASSED	600D	600D
DYMAX 628T	EXCELLENT	1800 PSI	FILLET	VERY GOOD	600D	~	PASSED	FAIR	~

FIGURE 3-62: ADHESIVE TRADE FOR CONE TO COVER BOND

>





Two contact positions were provided on the interconnect which were then welded to the beryllia metallization. A gold to gold weld was chosen over soldering due to a manufacturing process desire to use vapor phase soldering for subsequent assembly steps. The interconnect has out of plane expansion loops to minimize the contact stresses. The weld schedule and strength are shown in Figure 3-65.

Each of the interconnects was mounted to special terminals using a standard SN62 solder. Posts on the terminals fit through holes in the interconnect as a mechanical bond (Figure 3-66).

The terminals are commercially available hermetically sealed feedthrough systems (HSC Series 1000 SP30, Hermetic Seal Corp.) which incorporate a glass bead to electrically isolate the electrical feedthrough post from the mechanical mounting. The glass perimeter is covered by metallization which may be used for solder mountings. In this application, the terminal is soldered to the feedthrough holes in the primary mirror cup. Electrical connection between optics is via wire soldered to the terminals showing on the backside of the cup (Figure 3-37).

3.4.8 <u>Summary</u>

Figures 3-62 and 3-67 summarize the cell stack materials and bonding methods trades.

GaAs CELL No.	GOLD PL INTERCO BeO CHI THERMAL VISUAL	ATED DNN. TO F AFTER CYCLING PULL (15.)
5	ОК	1.4
9	*	
10	ОК	1.3
24	ОК	2.1
30	ОК	1.4
36	ОК	1.5
43	ОК	2.2
49	ОК	2.1
56	ОК	1.9
80	ОК	2.0
. 1		

FIGURE 3-65 INTERCONNECT TO HEAT SINK WELD TEST RESULTS

* Ribbon removed in therms.


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Cell Stack Materials Trade

Part	Options	Choice based on:
mounting pad	BeO Al203 Mo	Electrical design, thermal conduc- tion, coefficient of thermal expansion (CTE) match to GaAs
coverglass	Fused Silica CMX	Cost, CTE match to nickel
interconnect	2mil Ag wire formed Kovar	
unting pad metallization	AG CU CU	Solderability in manufacturing environment
erconnect bonding agent	Ag filled adhesive solder, <u>weld</u>	
d through terminals	TRW design commercial	Cost, thermal design

5104re 3-67

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3.5 STRUCTURAL DESIGN OF THE MCC

3.5.1 MCC Primary Mirror

The primary mirror built for contract NAS8-35635 was found to be less stiff than desirable as an unassembled piece. This resulted in unacceptable distortions when mounted to a structural assembly, as reflected by the tolerance analysis.

To stiffen the structure, two items were incorporated into the design. Stiffening rings were designed into the rim of the mirror and the edge of the flange to provide rigid right angle joints and minimize deflections.

The spider structure mount for the secondary mirror acts as an additional stiffener across the bowl of the primary when the MCC is completely assembled.

3.5.2 MCC Secondary Mirror

The secondary mirror of contract NAS8-35635 was found to be sufficiently rigid. However, the new secondary design did not have a similar flat flange at the rim. A stiffening ring was therefore incorporated at the rim.

3.5.3 <u>Secondary Mounting</u>

The secondary mounting was changed from the "birdcage" approach (Figure 3-1) in NAS8-35635 to a "spider" approach (Figure 3-68). A leg was incorporated to provide stiffness in a third direction if necessary, but was later deleted after testing showed sufficient strength and stiffness to pass launch dynamic inputs. The change to a spider was made to decrease effective blockage of the collection aperture, to decrease the cost of the mounting system, and to improve the manufacturability of the MCC element (Figure 3-69). Mounting bosses were incorporated into the primary mirror flange to facilitate accurate assembly of the spider to the primary (Figure 3-70). The spider was produced by wire electrical discharge machining of a stack of plates with the correct dimensional characteristics.



Mechanical Design Options	E, LIGHT WEIGHT, MINIMUM OBSCURATION		VIEW OBSTRUCTION COMMENTS	7% COSTLY	• 14% SIMPLE TO PRODUCE HEAVY	4% SIMPLE TO PRODUCE ASSEMBLY MODERATELY DIFFICULT SECONDARY HEIGHT FINE TUNABLE		VIEW CONTRACT	NASB 36159 SOME PACKING FACTOR LOSS. BEST CHOICE FOR MANUFAC. TURABILITY	N/A DIFFICULT TO IMPLEMENT. MAY NOT ELIMINATE INITIAL MANUFACTURIN PROCESS
ta	R RIGID STRUCTUR	Y SUPPORT	E CONTRACTS	NAS8 35635	NAS8 34131	NAS8 36159	ISTORTION	B RING	DRMED	Y BONDED
ingineering and Te Division RW Space & echnology Group	• DESIGN FOI	 SECONDAR 	STRUCTURI	BIRDCAGE	2-D SPIDER	3-D SPIDER	 PRIMARY D 	STIFFENING	ELECTROFC DOUBLE FLANGE	SECONDARY RING



ORIGINAL FACE IS OF POOR QUALITY

3.5.4 Mirror Manufacturing Methods

Methods for manufacture of the mirrors are shown in Figure 3-71. The baseline method of electroforming was chosen for direct comparison of the new design with the model developed in NAS8-35635 and because surface replication was known to be excellent.

3.5.5 MCC Element Bonding Methods

The joints for the cell, interconnects, cover and cone interfaces were considered under cell stack design. The joints for the secondary to spider and spider to primary were developed in parallel with that effort. The options for the secondary to spider bond are shown in Figure 3-72. Solder was chosen for its high thermal conduction path to the spider and the manufacturability inherent in the reflow design. Testing in acoustic and thermal cycling environments (Appendix A) confirmed the capability. The options for the spider to primary bond are also shown in Figure 3-72. Adhesive bonding with DYMAX 628T was chosen for good bond strength, good thermal cycling capability and ease in assembly.

3.5.6 Complete MCC Element Assembly

An assembly drawing of the MCC element is shown in Figure 3-73. Photographs of the assembly showing the assembly method to the support structure are shown in Figures 3-74 and 3-75. Manufacturing methods (Figure 3-76) employed for the production of MCC elements are described in Appendix B.

Mirror Material and Manufacturing Trade

-									
	SURFACE REPLICATION GOOD, SURFACE FINISH GOOD, NECES- SARY FOR DESIGN COMPARISON WITH PREVIOUS CONTRACT	PREVIOUS USE FOR MIRRORS, SURFACE REPLICATION GOOD, UNKNOWN SURFACE QUALITY, UNKNOWN METALLIZATION ADHERENCE, REQUIRES REDESIGN, LIGHT WEIGHT	GOOD SURFACE REPLICATION, ADDITIONAL POLISHING	SURFACE QUALITY POOR, ACCU- RATE FIGURE REPLICATION POOR, REQUIRES ADDITIONAL POLISHING, MACHINING	NOT STUDIED	BEING STUDIED ON SEPARATE CONTRACT, RESULTS TO BE AVAILABLE IN FUTURE	NOT STUDIED	NOT STUDIED	SURFACE MAY BE SECONDARILY BONDED TO ANY OF THE ABOVE BASE MATERIALS. AS ACCURATE AS FI FCTROFORM
SET ESTIMATE AND 100,000 PARTS	15.00	0.80	12-20	1-10		15-30	1-6	1-20	Δ15
RANK	(1) BASELINE	(2) BEST CHANCE FOR SIGNIFICANT COST/WEIGHT REDUCTION	(3) NEXT BEST CANDIDATE	(8)	(4)	(9)	(5)	(1)	NA
MATERIAL	Ni, Cu	PLASTICS	Cu, Al, Be	A	Ti, Al, Zn	AI, Be	GLASS	CERAMICS	AN
MANUFACTURING METHOD	ELECTROFORM	INJECTION MOLD, COMPRESSION MOLD	POWDERED METAL	STAMPING	SUPERPLASTIC FORMING	MACHINING (DIAMOND TURNING)	BLOW MOLDING	SLURRY MOLDING	REPLICATION

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Optic Mechanical Attachments Investigated





3-73: COMPLETE MINIATURE CASSEGRAINIAN CONCENTRATOR ASSEMBLY FIGURE

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Figure 3-76

Figure 3-76: Existing MCC Assembly Process Flow Diagram

3.6 MCC SUPPORT STRUCTURE

3.6.1 Frame Design

The main component of the structure, the tri hex grid design (THG) (Figure 3-77), was retained from NAS8-35635. This structure was compared with a competing hexagonal structure for stiffness and manufacturability. The significantly greater stiffness of the tri hex grid for unit weight (Figure 3-78) combined with the inherently simpler manufacturability confirmed the selection of this design as baseline to the program.

Potential materials were reviewed for cost and manufacturability (Figure 3-79). The Syalon ceramic material was rejected for difficult process control (shrinkage) which may have required secondary machining. A Beryllium structure was defined and found to be manufacturable at a reasonable cost for a large order of units. However, for potential low cost applications, a graphite fiber reinforced epoxy (GFRP) system was selected to explore manufacturability and cost. The inherent material cost was lower and overall fabrication cost was found to be less than that for beryllium. (For a more detailed discussion of processes see MFG-Panel in Appendix C.)

The GFRP layup methods used in previous contracts and TRW internal research resulted in a structure higher in resin content than desirable. Methods to compact the structure walls and achieve high fiber content (>60%) were considered (Figure 3-80).

The trapped rubber mold method had been used previously in commercial applications for squeezing resin from composite systems. Application to the array was believed to be the best choice for success.

As built, the small GFRP strips and a four element panel exceeded the goals for stiffness, fiber volume and void content.

The large 37 x 53 cm and 37 x 142 cm panels built under this contract met most or all requirements as initially manufactured. Some bowing of the larger panel out of specification was alleviated through a secondary cure process wherein the panel was heated to a higher temperature than that used for cure, stressed to counter any bowing and held for a specific time. After this, the panel was within specification.









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Hex versus Tri-Hex Trade

TRI-HEX		BENDING 1.50 TORSION 9.60	MINDING	LOWEST	PERMITS USE OF ADJUSTABLE INSERTS
НЕХ		BENDING 1.00 TORSION 1.00	ÐNIQNIM	MODERATE TO LOW	PRECLUDES USE OF ADJUSTABLE INSERTS
PARAMETER	CONFIGURATION	SPECIFIC STIFFNESS FACTOR	FABRICATION OPTIONS	PROJECTED COST	MCC ASSEMBLY TO PANEL

Figure 3-78

*KEY

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THG Fabrication Process Trades

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MATERIAL AND PROCESS	VIEW	KEY FEATURES
CARBON FIBER REINFORCED PL ASTIC (GERD)		LIGHTEST WEIGHT
		 POTENTIAL FOR LOW COST
		• TECHNOLOGY STATE OF THE ART
HUBBER COMPACTION DURING CURE		 POTENTIAL 300 MSI/LB SPECIFIC STIFFNESS
		 STIFFEST STRUCTURE
	۲	 WELL KNOW TECHNOLOGY
BERYLLIUM		HINGE AND STRUCTURAL DETAIL JOINING SIMPLE
RAJED		• 600 MSI/LB SPECIFIC STIFFNESS
	side Top	 10% ELONGATION MATERIAL (NON BRITTLE) AVAILABLE
		• WFIGHT ~ AI LIMINIIM
 SYALON (Si, AI, O, N-CERAMIC COMPOSITE) 		 NEW TECHNOLOGY
 SLURRY MOLD 		 MAY BE SLURRY MOLDED
• SINTER		300 MSI/LB SPECIFIC STIFFNESS

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Compaction Methods

COMMENTS	COMPLEX TOOLING. DANGEROUS	COMPLEX TOOLING	SIMPLE BUT CONFINEMENT AT TOP COMPLEX	SELECTED BASED ON EASE OF IMPLEMENTATION IN MANUFACTURING
METHOD	PNEUMATIC PRESS	HYDRAULIC PRESS	MECHANICAL PRESS	BULK DIFFERENTIAL THERMAL EXPANSION
			FORCE	FORCES

Eigure ≥ 30

R5-00943/36

3.6.2 Insert Design

The tri hex grid panel required mounting provisions for the MCC elements. The natural location for the mounts were at the triangular sections formed by the THG geometry. The mounts were designated "inserts" which consisted of two or more components: a fixed insert in the panel; a fastener for the MCC element; a sliding insert for flatness control; a snubber for positive gripping of the MCC element. The design for the NAS8-35635 contract consisted of an aluminum female threaded part bonded in the THG, an aluminum male threaded part to fit in the female part allowing adjustment of the height above the panel and on which the MCC was positioned, a washer and a screw threaded for the interior of the male part which held the MCC in place.

To simplify assembly and manufacture, and decrease weight, a new part was designed with the intent to use a commercially available snap fastener to hold the MCC in place. The simplest process for bonding the fixed insert in place was to co-cure the insert with the THG manufacturing process. Since the flatness of the panel could not, at that time, be predicted, a sliding insert was designed to secondarily bond in place and minimize any out-of-tolerance flatness achieved during manufacturing (Figure 3-81).

A commercially available snap fastener was located which met overall dimensional requirements (Figure C-8). The fixed insert (Figure 3-82) was designed to be lightweight yet resistant to pressures developed in the trapped rubber mold manufacturing process. The insert was triangular and of a slightly large than nominal THG triangle size to ensure good bonding over the exterior surface with the graphite fibers. A triangular sliding insert (Figure 3-83) was designed to mount into the fixed insert and accurately slide within the hole provided with little rocking or offsetting. A snubber was designed which consisted of a washer-like 2 mil piece of kapton coated on one side with RTV silicone adhesive (General Electric RTV-142). The washer fit on the snap fastener such that the RTV faced the MCC element (away from the head of the fastener) (Figure C-8). The sliding insert mounting surface was modified with a groove to allow for MCC primary nickel material overgrowths (Figure 3-84).

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THG Mechanical Attachments Investigated







The sliding-to-fixed insert bond was tested with five bonding materials and three bonding positions as illustrated. FIGURE 3-84:

B Interior Edge Fillet C Exterior Edge Fillet A Interior Surface 8 ∢ 2 יננווווו Groove to allow for primary

BONDING MATERIAL POSITIONS

rough edge clearance.

The sliding and fixed inserts were designed to meet requirements as shown in Figure 3-85. Materials considered were plastic, metal, and ceramic (Figure 3-86). Plastics were selected for easy, least cost manufacturing and best thermal expansion match to the THG GRFP material.

The plastic material choices needed both high (200^oC) and low (<-170^oC) temperature tolerance, low thermal expansion coefficients, and high tolerance to corpuscular radiation. Atomic oxygen susceptibility was an unknown, but coatings could be used if necessary. Of the four plastics finally considered (Figure 3-87), three were used to manufacture the inserts: polyetheretherketone, poly(amide)imide, and polyphenylene sulfide (PEEK, TORLON, RYTON).

Bonding Methods. Three methods for bonding the sliding to the fixed inserts were considered: adhesive, welding (plastic thermal reflow), and staking. The least effort method (adhesive bonding) was tried first.

The requirements of the bond were resilience, adequate strength for assembly (>3 lbs push force which was 50% above the snap fastener maximum push force), and good thermal cycling stability and reworkability.

A number of adhesives (Figure 3-88) were considered. The selected choice of Dymax 628T adhesive was based on adequate strength, good stability under thermal shock and deep thermal cycling environments, and reworkability with solvents. In addition, the fast 15 second set time made manufacturing a high productivity effort.

To provide an absolutely flat surface the THG panel was suspended by shims above a micro flat table, the inserts were carefully slid into place, the adhesive was applied, and quickly cured. The error was less than three mils on any insert.

	Eng Divi TRW Tech	ineering and Test ision / Space & nology Group	THG Insert Design Requirements	
·	•	Light weight		
	•	Low cost		
	•	Thermal expansion coe	efficient compatible with THG	
	•	Environmentally stable	under thermal cycling, UV, e , P+, γ	
12	•	Easily manufactured		
21	•	Compatible with comm	nercially available snap fastener	
•	•	Adjustable height from	n grid surface	
	٠	Compatible with THG	fabrication method (co-curable)	
			Figure 3-85	
	R5.	00943/55		

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Insert Materials

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lastic	 May be filled with carbon fiber for characteristic modification Light weight May be injection molded Lowest cost (0.30 ea/1000)
letal	 Moderate weight High strength Tolerances hard to hold without machining Powder metal process best option Moderate cost
eramic	 Brittle Moderate weight Tolerances hard to hold without machining Slurry mold best option High cost

•••

Figure 3-86

R5-00943/56

Engineering and Test Design TRW Space & Technology Group	 Four engineering plastics, all carbon fiber filled Polyethersulfone Polyphenylene sulfide Poly(amideimide) 	 All plastics have High (>400°F) temperature capability with no flow High P+, e ', γ radiation resistance High UV resistance Have been used in low (near cryogenic) temperatures

Best choice to be made after 30,000 thermal cycles performed by NASA

123

FIGURE 3-88 PUSH STRENGTH (LBS) FOR ADHESIVES FOR SLIDING INSERT

		INSERT MA	TERIAL
	TORLON	RYTON	PEEK
Dymax 628T*	6-22	4-6 M	6-11
DC93500	-	0-3 X	-
RTV 3145*	-	5-12	22-28
DC6 1104	-	2-10 X	4-12 M
Lefkoweld Type 46*	4-22 M	18-32	-
RTV 118	-	-	2-5 X
Cyanoacrylate*	>220	3.5 X	4.5 M
EA 934*	61-65	5-44	4-36 M

X = Cannot Use

M = Marginal

* = All adhesives tested in thermal cycling had greater than
 4 lbs residual push strength.

4. ANALYSES

4.1 THERMAL CONSIDERATIONS

4.1.1 Thermal Performance For Cell Output

The new design of the MCC element was checked against thermal analyses for designs from previous NASA contracts. The essential components of an 8 mil copper optic/radiator have not changed. Thermal response in a low earth orbit for a typical element is as shown in Figure 4-1.

4.1.2 <u>Secondary Mirror Temperatures</u>

The temperature reached by the secondary mirror is important for both possible alignment distortions due to thermal mismatch and for long term stability of any materials used in the manufacture of the mirror and support structure.

A simplistic analysis assuming no fin cooling from the spider showed that the present design should run between 130 and 140°C. This is acceptable for the materials used. Consideration of the fin effect due to the aluminum spider should significantly reduce this range.

Thermally induced mismatch between the 80°C primary and a 138°C spider structure would cause a relative growth difference of only 0.8 mils which is much less than the 2 mil allowance at the local spider to primary bond interface. Very little optical distortion can be expected from this source.



4.2 WEIGHT

Shown in Figure 4-2 is the weight goal for a flight ready panel compared to the achieved weight of the NAS8-35635 contract and the new achieved weight of this contract.

Figure 4-3 displays the weight of each piece part of the MCC panel and summarizes the total average weight achieved per element.

The THG framework has reached the design weight goals originally set for it. The insert attachment hardware is greater than fifty-five percent decreased from the NAS8-35635 design but requires a two thirds reduction to meet the design goal. The MCC elements mounted on the large panel have achieved the flightweight design goal. The harnessing is 15% less than the flightweight goal. Altogether, the system weight per element as presently achieved is only 11% greater than the flightweight design, that is 14.17 g/element versus 12.60 g/element.

To achieve the design weight goal it is only necessary to order primary optics nominally 8 mils instead of nominally 9 mils thick as with the current manufacturing process. This has been discussed with the electroform vendor, Optical Radiation Corporation, and has been found to be easily achievable with only small risk of decreased yield. For example the 10 mil nominal thickness secondary mirrors were actually delivered as 4 to 6 mils thick and primary mirrors as delivered ranged from 6 to 11 mils thick.

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MCC Panel Weight Analysis

	LED .	L MASS g)	14	68	86	91	59***
DESIGN*	POPULAT VREL	, TOTAI	- 1	31(41
HTWEIGHT I	FOR FULLY IVARTER PA	QUANTITY	-	330*:	372		
FLIG	WEIGHT 0	UNIT MASS (g)	714	9.6	0.5	91	
	JR FULLY R PANEL	TOTAL MÂSS (g)	737 .	3171	558	85	4551
<pre>built)</pre>	ED WEIGHT FC ATED QUARTE	QUANTITY		330	372	1	
itract as	PROJECT POPUL <i>i</i>	UNIT MASS (g)	737	9.6	1.5	85	
resent Con	(15"×56") anel	TOTAL MASS (9)	421 .	1730	326	74	2550
31659 (P	of large cation P	QUANTITY	1	180	217	1	
NAS8-:	Weight (Demonst	UNIT MASS (g)	421	9.6	1.5	74	
	ght from (4 Panel)	TOTAL MASS (g)	1509	3168	1224	- 91	5342
35635	cted wei ilt data	QUANTITY	1	330	372	1	
NAS8-3	Projec as-bui	UNIT MASS (g)	1509	9.6	3.3	91	
	COMPONENT		TRI-HEX GRID PANEL AND FRAME	MCC ELEMENT (CELL STACK AND OPTICS)	ELEMENT ATTACH- MENT HARDWARE	PANEL WIRING AND Connector	TOTAL PANEL MASS

PANEL DESIGN CONSISTENT WITH 28 W/Ag ARRAY SYSTEM PERFORMANCE (BEGININING OF LIFE)

••330 ELEMENTS PRODUCE 137W AT THE ARRAY SYSTEM LEVEL

•••ARRAY STRUCTURE ADDS AN ADDITIONAL 19.5% IN MASS

WEIGHT ANALYSIS SHOWING PREVIOUS CONTRACT CAPABILITY, PRESENT CONTRACT AS-BUILT WEIGHT FOR THE LARGE PANEL, PROJECTED WEIGHT FOR A QUARTER PANEL(26" X 56"), AND ULTIMATE FLIGHT GOAL.

FIGURE 4-2:

SUMMARY
WEIGHT
AND
PARTS
PIECE
Р,
WEIGHT
4-3:
FIGURE

MCC ELEMENT COMPONENTS	AVERAGE WEIGHT (GRAMS)	ELEMENT ATTACHMENT COMPONENTS	AVERAGE WEIGHT (GRAMS)	MISCELLANEOUS ELECTRICAL	WE I GHT (GRAMS)
primary secondary cone cell glass insulator (ReO)	7.538 .459 .116 .047 .011	fixed insert sliding insert snap fitting snubber adhesive	1.080 .281 .119 .005 .014	wire 28 AWG large panel wire 28 AWG small panel connector bonds & ties large panel small panel	45 12 26 3 2
interconnect top interconnect bottom terminals (2) spider	.007 .018 .350 .350	T0TAL (G0AL	1.50 0.50)		
adhesive paint	.450	STRUCTURE (THG)	WEIGHT (GRAMS)	DENSITY g/cm ³	
TOTAL (GOAL	9.61 9.60)	141.4cm x 37.7 cm 52.5cm x 37.7 cm	421.4 159.7	.069gcm ³ (0.67g/cm ³ goal) .071g/cm ³ (.067g cm ³ goal)	LARGE SMALL
TOTAL WEIGHT (ESTIMATE	1			MEASURED	OVERALL
SMALL (9.61 × 66) + LARGE (9.61 × 180)	(84 × 1.5) + 159 + (217 × 1.5) + 4	.7 + 12 + 26 + 2 = 96 21.4 + 45 + 26 + 3 =	58g 2550g	 2.55 <u>+</u> .01g (GOA	<pre>14.67g/element 14.17g/element L 12.60g/element)</pre>

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4.3 PERFORMANCE ANALYSIS

4.3.1 Overall Electrical Achievement

Figure 4-4 shows the capability of the as-built MCC element configuration for this contract, compared to the goals set for the MCC technology. Also shown is the projected capability of the current design when the effect of known manufacturing defects is eliminated.

4.3.2 Electrical Output Corrected for Known Defects

The outputs for the substrings of the 37 cm x 53 cm panel are shown in Appendix A. At 0° offpoint the average power for a six element in series substring is 2.14 W after AMO and temperature correction. This amounts to 0.357 W/element. When corrected for the poor reflectance of the conic mirror (from 0.66 to 0.98), using the method specified in 3.3.2.13, the power jumps to 0.419 W. When corrected for mismatch also as described in section 3.3.2.13, the power achieved is 0.453 W. Performance at 85° C would be 0.419 W.

An element under 1 sun AMO, $85^{\circ}C$ should be capable of 0.162 x .1353 W/cm² x pi(2.54 cm)² = 0.444 W with a 20% efficient at $85^{\circ}C$ cell in the present design. Correction to $28^{\circ}C$ is [1 + (57^{\circ}C) x (.13%/°C)] x 0.444 = <u>0.478 W</u>.

The cells used for this small panel were initially 20.6% efficient at 28° C or 19.1% efficient at 85° C. Allowing for an increase to 20% efficiency cells at operating temperature, the current design would achieve (20/19.1) x .453 = <u>.475 W</u> at 28° C at the element level which is very close to the 0.478 W as expected from the above calculations.

The corrected measurements achieve the capability goals of the design. There are no unexplained losses in the system.

FIGURE 4.4: MCC ELEMENT CAPABILITY

	NASA 35635	NASA 36159		
	ACHIEVED	ACHIEVED	CORRECTED ⁺	GOAL
ODTIC TRAIN				
BLOCKAGE	86	01	01	90
PRIMARY REFLECTANCE	.00 97	08	98	08
SECONDARY REFLECTANCE		08	. 90	. 90
	97	86*	99	00**
SCATTER LOSS	93	96	96	96
GLASSING LOSS		1 0	1 0	1 0
MISALIGNMENT	.96	.99	.99	.99
TOTAL	.70(.79)	.714(.81)	.822	.80
CELL STACK CELL EFFICIENCY @ 85 ⁺⁺ °C FABRICATION LOSS	.138 .89	.194 .98	.194 .98	.200 N/A
UTAL	.123	.190	. 190	.200
PANEL LEVEL				
MISMATCH	N/A	.94	.99	.98
ELEMENT PACKING	.79	.82	.82	.79
WIRING & DIODE LOSS***	.97	.97	.97	.97
OFFPOINT ERROR (1.1°)	.98	.99	.99	.98
FOTAL	.75	.74	.78	.74
OVERALL SYSTEM EFFICIENCY	.067	.100	.122	.118
W/ element	.184	.277	.334	.324
w/m ²	90.8	136	165	160

⁺Corrected for known manufacturing deficiencies.

*Based on 66% cone reflectance, 0.60 + (0.40 x 0.66) .86

**Based on 98% cone reflectance, 0.60 + (0.40 x 0.98) .99

***Actual losses were negligible. This is shown for comparison to a system design only.
Based on the achieved weight calculated per element in section 4.2, the specific power of the design is 29.6 W/kg at the panel level and 24.7 W/kg at the array system level using the 100 kW array parameters from NAS8-34131, and the corrected performance values shown above.

4.4 ADVANCED DESIGNS

To surpass the weight goal of 28 W/kg there are many categories of change which can have significant impact.

4.4.1 <u>Material Thickness Change</u>

The optics may be changed from the present 9 mil thickness to 4.5 mils thickness. Counting only the primary mirror, this would be equivalent to a 3.8 g per optic drop or 1244 g per quarter panel for a total of 3307 g remaining or 35.2 W/kg at the array level.

4.4.2 <u>Material Type Change</u>

With the proviso that the mirror surface could be replicated and secondarily bonded into place, a 30 mil magnesium casting could be used to achieve 3.5 g optic drop or nearly that of the 5 mil copper optic.

The best candidate is to compression mold graphite fiber cloth whose thermal conductivity is near that of aluminum structure (66 Btu/hr ft^OF) such that no secondary radiator would be required. Five mils of this material at 1.7 g/cm³ would total only 0.8 g per primary for a savings over the baseline of 6.8 g/optic or 2244 g of element weight. Subtracting from 3168 nominal element weight leaves 924 g. Combined with the other articles and a 0.5 g element attachment hardware, the total weight would be 1915 g with .444 W element x 330 = 146.6 W. With 19.5% backup structure, the system watt/kg is

 $\frac{146.6}{1915 \text{ g x } 1.195} \text{ or } 64 \text{ W/kg}$

4.4.3 Coatings

The coverglass may be coated with an infrared reflecting filter for a potential of 11°C drop or 1.43% improvement.

4.4.4 Advanced Cells

The concentrator may use any advanced cells as they become available and in a size which may be relatively easy to produce. A twenty-seven percent efficient cell which has been reported would increase power to 197.9 W on a quarter panel or 39.8 W/kg.

4.4.5 <u>Combined</u>

The combined potential of the above design changes could make the MCC concentrator achieve 1.35 x 1.0143 x 64 W/kg = 87 W/kg.

4.4.6 Manufacturing

If compression molding were implemented, the piece part price could be reduced to less than two dollars a part depending on final complexity.

4.4.7 Offpoint Performance

Quick research into historical analyses discovered that a focusing refracting lens placed on top of the cone would increase offpointability by an extra degree. This remains to be seen with the new element optical design. The lens could be used in place of the protective glass cover.

5. CONCLUSIONS

The optical design of the miniature Cassegrainian concentrator (MCC) element has been improved for both offpoint and onpoint power capability. The cell stack design has shown no losses under the high short term thermal stresses imposed by component level test and is projected to be capable of greater than five years thermal cycle life in low earth orbit. The structural design met all requirements for stiffness and flatness and requires adjustable inserts for fine tuning of the GFRP structure to meet flatness goals. The completed, fully populated small and large MCC panels deliverable under this contract perform electrically as expected.

A solid acceptance inspection program to guarantee quality of all purchased parts, and continued manufacturing process improvements will make the MCC design a viable low cost alternative to standard flat panel technology. Minor improvements to the cell stack design of the MCC element can make significant improvements in both the performance and manufacturability of the MCC system.

6. RECOMMENDED FOLLOW-ON WORK

The following schedule shows recommended follow-on work to be accomplished prior to acceptance of the MCC array system as a low risk alternative to flat panel technology arrays. 171

Recommended Follow–On Development Plan

ΑCTIVITY	1987	1988	1989	1990	1661
 CONTRACT NAS8 36159 (PANEL SEGMENT DEVELOPMENT) 		-			
THERMAL CYCLING BY MSFC	4	4			
WING AND PANEL CONCEPTUAL DESIGN					
 LOW COST ELEMENT PRODUCIBILITY INCLUDING EFFICIENCY IMPROVEMENT 			₽		
LOW COST PANEL PRODUCIBILITY			P		
 ENGINEERING DEMONSTRATION MODEL INCLUDING TESTING AND GSE 		4			
 ELECTRICAL AND THERMAL TESTING OF A PROTOTYPE PANEL 	4				
 FLIGHT EXPERIMENT (2 AXIS SUN TRACKER) PROTOFLIGHT PANEL 	•		4	P	

APPENDIX A ENVIRONMENTAL AND ELECTRICAL TEST RESULTS

1. INTRODUCTION

This section presents the parameters and results of selected environmental and electrical testing performed to support this contract.

2. ENVIRONMENTAL TESTING

2.1 THERMAL CYCLING

The following tests were performed.

CONDITIONS	TEST ARTICLES	RESULTS
A. 200 cycles -160 to 10 ⁰ C	20 weld joints to cell, 20 solder joints to cell, 6 weld joints to BeO,	1 failure due to incipient cell crack failure no failures 1 failure due to Au metal-
	6 solder joints to BeO	no failures
B. 120 cycles (shock) -65 to +124 ⁰ C	10 cells mounted on BeO, 10 silver welds of cells, 15 gold welds to BeO, 3 each Torlon, Ryton, Peek sliding insert to fixed insert epoxy bond	no failures no cracks
C. 470 cycles -150 to+65 ⁰ C *(-170 to +80 ⁰ C)	<pre>small tri-hex panel with bonded inserts, *small parts from (B) above</pre>	no failures, partial loss of epoxy strength but no effect on capability
D. 100 cycles (shock) -80 to +100 ⁰ C	Plastic parts as in (B) except with UV628 bonds, cone to cover UV bonds, 2 completed unpainted optic element with spider bond with UV 628, sliding inserts with epoxy 9321	no failures, no visible degradation
E. 100 cycles -80 to +80 ⁰ C	5 cones with covers, UV cure adhesive	no failures, no visible degradation, bond strength greater than glass
F. 5 cycles (shock-LN ₂ Dip) -196 to 66 ⁰ C	2 completed optic elements with S13GLO paint (bonds-Dymax	no bond failures, no Ag, SiO coating failures, no paint failures (passed UV628, DC93500) tape test)
G. 100 cycles +80 to -80 ⁰ C (3 openings)	See Figure A-1	See Figure A-2

T <u>EMPERATURE RANGE</u> +B0 to -B0°C (+176 to -112°F) 	<u>MAY 1, 1986</u> (0 CYCLES)	 Initial inspection & photo. Cone accidentally debonded by technician. * May 5, 1986 (30 CYCLES) 	 No change 	May 12, 1986 (76 CYCLES) Additional (unplanned) cold temp exposure; ~-180°C/15 hrs. • Additional cone debronded (adhecive failure to cone: 93-500)	May 14, 1986 (100 CYCLES)	Spider debonded by technician upon removing from chamber; 93-500	failed adhesively to spider	A ANALYS PLANCE UNG WATED ON TEET DANEL BLEDDE	ACCIDENTAL COLD TEMPERATURE SOAK AT LIQUID NITROGEN TEMPERATURES. EVEN AFTER COLD SOAK LITTLE DAMAGE WAS APPARENT.	Figure A2 THERMAL CYCLING RESULTS
ALUMINUM ALUMINUM 93-500	STAINLESS 93-500		NI CKEL ALUMI NUM	142 NICKEL INDIUM #2	NICKEL	INDIUM #2	NICKEL INDIUM #2			IC EXPOSURE
ALUMIMUM ALUMINUM 93-500	5TAI NLESS 93-500	NI CKEL 93-500	NI CKEL ALUMINUM	93-500 NI CKEL 93-500	NI CKEL NI CKEL	LEFKOWELD	NI CKEL LEF KOWELD	57A1NLESS 93-500	STATIILESS LEFKOWELD	ST PLATE FOR ACOUS
ALUMINUM ALUMINUM 93-500	STAINLESS 93-500		ALUMINUM	93-500 57A1NLESS 93-500	NICKEL	93-500 W/CABOSIL	NICKEL 99-500 W/CABOSIL			ERIALS USED ON TES THERMAL CYCLING
LATE METAL PIDER METAL PIDER-TO-PLATE BOMD	ECONDARY METAL PIDER-TO-SECONDARY BOND	ONE HETAL ONE-TO-GLASS BOND	LATE METAL .pider metal	\$PIDER-TO-PLATE BOHD SECONDARY METAL \$PIDER-TO-SECONDARY BOND	PLATE METAL SPIDER METAL	SPIDER-TO-PLATE BOHD	SECOHDARY NETAL SPIDER-TO-SECONDARY BOND	CONE METAL CONE-TO-GLASS BOHD	CONE METAL CONE-TO-GLASS BOND	Figure Al Mar

A2

2.2 ACOUSTIC EXPOSURE

The test panel from 2.1G above was subjected to an acoustic exposure prior to thermal cycling. The acoustic spectrum is plotted in Figure A-3. Overall pressure level was 146 dB. No failures were observed as a result of the test.

3. ELECTRICAL TESTING

3.1 CELL ELECTRICAL OUTPUT

The cell data curves for forward one sun, 100 sun, dark forward, and dark reverse testing are too numerous to present here. All data is held at the contractor. A summary of the data is provided.

All efficiencies reported below are at 100 AMO sun intensity.

The cells from ASEC all performed between nineteen and twenty one percent at 28° C with a few stragglers above and below this range. An additional 100 cells from ASEC produced and received as replacements for those with contact problems had efficiencies all above 20% at 28° C. As noted in the text, the Spectrolab cells averaged 18% efficient with a range of 17.5% to 18.5%. The Varian solar cells averaged 16% with a range of 11% to 18.5%. (Known contact and batch problems with the delivered lot caused the low efficiency, but time constraints precluded waiting for another batch. Cells received for another TRW program all ranged near 20% at 80° C.)

The dark forward characteristics showed no notable changes from the 100 sun data.

The dark reverse testing for the cells revealed significantly different characteristics from typical measurements of silicon cells. The reverse breakdown voltage ranged between 1 and 2 volts for most samples. No samples exhibited breakdown at any greater than 6 volts. No damage was apparent after reverse testing. For comparison, 2x4 data for silicon cells typically shows a breakdown >20V with a range between 5 and 50 V.

A3

3.2 SMALL PANEL STRING OUTPUT DATA

The small panel contains MCC elements with copper nickel sandwich primary mirrors. The best cells of the ASEC quantity were reserved for this panel. All matching was performed based upon pre-welded outputs. No equipment was available to match elements The MCC elements were arranged in strings of twelve in outputs. series. Measurements were performed on half strings (6 in series) to avoid some equipment limitations in voltage. After data was gained on each of the 11 half strings, five of the "A" half strings were put in parallel and measured. The same was done for the "B" half strings. All data was corrected for solar intensity using a GaAs concentrator cell transfer standard at 1 sun and corrected for temperature using the average of two thermistors mounted on the back of elements and including a known steady state temperature drop of Some data may be off by 3 to 5°C at random due to some 3°C. transient wind cooling but effort was made to wait for steady state conditions.

Data for the strings was then corrected for the conic mirror coating defects as discussed in section 3.3.2.10 using an average reflectance of 0.70.

Both the data corrected to 28^oC and standard conditions and corrected for the average conic reflectance loss are reproduced here in figures A4 and A6.

Data for the combined strings are contained in Figures A5 and A6.

3.3 LARGE PANEL STRING OUTPUT DATA

The large panel contains all nickel MCC elements with various strings composed entirely of cells from each of ASEC, Spectrolab, and Varian solar cell manufacturers. Specific kitting may be found in Appendix B.

Data was measured for individual six element in series half strings as in 3.2. However a 3 month time lag between measurements occurred between measurements of elements 1A through 4D and 5A

Α4



Figure A3

8. Voc Ise Vinp Inp Pro FF from and Tre FT T2 5 5755 011 5.174 .010 .051 .784 .024 2.64 41.6	4 6.193 .063 5.830 .053 .307 .793 .193 .193 .487 49.2 49.2 3 6.364 .304 5.959 .175 1.011 .803 .489 452 49.4 45 3 6.364 .304 5.959 .175 1.011 .803 .489 49.4 45	3.5 6.577 .5.70 .5.71 7.75 .775 .775 .775 .745 .745 2 6.405 .324 5.60 .321 1.57 7.80 .711 1.57 7.80 1.5 6.405 .361 7.60 .311 1.57 7.60 .311 1.5 6.405 .366 .306 .312 1.57 7.60	1 6.413 .340 5.621 .340 7.048 .811 .112 .242 5.20 5.2 5 6.431 ,405 5.621 .377 2.117 .812 .995 .942 2.50 5.2 0 6.431 5.623 5.84 .387 2.145 .792 .997 2.75 58.5 0 6.487 .906 5.634 .387 2.121 .790 .987 .388 2.77 54.5 46.	44 5.7 5.4 5.5 5.5 5.6 5.4 5.4 5.5 5.	2 6.37 7.4 7.4 7.4 786, 387, 081.1 102, 558.3 256, 116.0 4 2 6.160 2052 5.662 243 820, 823 850 451, 751, 751, 751, 754 435 43 5	2B 28°C corrected con	5 5.87 ,016 5.799 .015 .075 .811 .033 259 40.6 34 46.5 34 46.5 34 37 3.94 46.6 34	4 6.333 111 5.453 5.411 5.454 5.81 5.73 5.47 35 3 6.442 7.73 5.738 1.528 1.528 1.578 5.73 4.7 35 3.5 6.471 7.842 5.738 1.509 5.85 1.870 5.93 4.7 35 3.5 6.471 7.845 5.738 1.909 5.855 1.870 367 3.91 50 4.15 35 2.5 6.471 5.738 1.809 7.855 1.890 7.91 50 4.15	2 6.451 .382 5.35 1.962 7.96 863 .890 2.91 505 435 1.5 6.460 .404 5.586 .373 2.078 .797 .917 501 50 46 1.5 6.400 .404 5.586 .373 2.078 .797 .917 50 46 1.5 6.400 .401 5.78 2.373 .207 .475 501 501 501 501 501 501 485	S C. 775 . 473 5. C. 1 . 397 2. 365 . 786 . 970 1.009 2.88 50 96 6.981 . 930 5.660 . 402 2.375 . 817 1.001 1.002 2.85 995 43 0 6.991 . 928 5.656 . 402 2.371 .818 . 999 . 998 2.95 995 4	5 (2.415 .428 5.636 .380 2.140 .773 .441 .778 .273 342 . 29 2. 290 .386 2.159 .793 .950 .389 .295 .295 .295 .295 .295 .295 .295 .200 .200 .200 .200 .200 .200 .200 .20	1.5 6.445 327 5.780 2.371 1.717 814 755 772 2.455 773 2.5 6.446 .327 5.780 .296 1.777 .814 .755 .723 2.455 50 445 2.5 6.446 .327 5.787 .293 1.793 .874 .795 6.702 2.946 46 96 3.6 6.384 .320 5.778 .234 1.292 .880 568 6.536 296 46 96 4 6.196 .371 .860 .63 6.536 2.96 45 74 75 4 6.196 .371 .860 .63 6.337 .909 .917 40 27 28 245 20 75 5 5.745 .000 5.057 .009 .948 .825 .023 2.96 70 .917 .825 .921 .825 .921 .825 .725 .725 .725 .725 .725 .725 .725 .726 .725 .725	15" x 21" PANEL . CORRECTED FOR
1 A 28°C corrected	3 6.36 5.54 5.73 1.51 , 80 , 713 , 69 1.81 34 2.5 6.36 5.544 .312 1.71 .81 .907 .77 1.85 34	2 6.38 383 5.37 .355 1.91 .78 .901 .86 1.65 37 1.5 6.41 .413 5.40 .384 2.07 .79 .976 .95 1.89 35 1 6.42 .419 5.42 .385 2.09 .78 .966 .97 .39	· 5 6.42 .423 5.49 .389 2.13 .79 1.01 .98 2.05 40 MERS 0 6.39 .433 5.49 .390 2.13 .78 1.00 1.00 2.15 41 1 411 1 \$ 6.40 .421 5.35 .370 2.09 .77 .97 .97 1.70 41 4 5 5 6.42 .411 5.40 .379 2.05 .78 .97 20 .95 1.81 40	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	9E 28°C corrected EST	1 2 (22 .30 5.53 .381 1.59 .83 .74 0 .71 3.19 36 5.2 20 2.20 2.20 2.21 1.82 .201 2.10 3.10 3.10 3.10 3.10 3.10 3.10 3.10 3	545 6.32 .393 5.43 ,368 2.00 .81 .74 10 .318 37 5.45 6.32 .417 5.43 .387 2.10 .80 .99 .97 2.16 38		1 6 6.37 419 55.50 388 2.13 .80 1.00 78 2.19 4. 4. 4. 4. 5.8 6.25 .398 5.13 .80 1.00 78 2.19 4. 4. 4. 4. 4. 4. 4. 4. 4. 4. 4. 4. 4.	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	E 28.1 E1. 11 E1. 18. 22. 250. 80.5 550. 86.5 27	ORIGINAL J OF POOR Q	FIGURE A4 HALF STRING OUTPUTS FOR 1 INSOLATION AND TEMPERATUR

4A 28°C corrected	$\frac{\theta}{\theta}$ Voc Isc Vrie Ind Price FF And and Isc STD T1 T3	3 6.71 .16.3 2.75. 777. 267. 267. 827.2 2.17 T. 7.6	74 7.8.7 28.6 1.8.9 2.4.8. 1.7.1 30.4. 1.7.1 2.8.0 1.8.1 1.5.7 2.8.2 1.2.2.4 2.8.2 1.2.2.4 2.8.2 1.2.2.4 2.4.2 1.5.2.2 24.2 1.5.2.2 24.2 1.5.2.2 24.2 1.5.2.2 24.2 1.5.2.2 24.2 1.5.2.2 24.2 1.5.2.2 24.2 1.5.2.2 24.2 1.5.2 1.5.2.2 1.5.2 1	1.5 6.275 .315 5.542 .295 1.635 .829 .763 0 .722 2.85 50	1 6.285 .371 5.494 .336 1.849 .792 .863 0 .951 2.85 49 	0 6.316 , 435 5.408 , 395 2.138 , 779 , 998 0, 998 2.84 975	0 6.300 .437 5:353 .401 2.145 .779 1.001 70 1.002 7.87 49	1 6.381 .426 5.324 390 2.076 777 929 977 2.6 48	1.5 6.277 .388 5.374 .360 1.934 .794 .903 10 3.85 47	2 6,264 ,354 5,385 ,324 1.745 ,788 ,815 17, 812 2.85 45	3 6.217 .237 5.645 .209 1.181 .802 .507 0.544 7.8 43		. 4B 28°C corrected	3 (21) 7(1) 5 876 (31) 737 528 m 20 77 WC	2.5 2.7 2.7 2.7 2.6 607 117 200 1 100 200 1 10 200 2.7 2.7 3.7 3.6 2.7 3.7 3.7 3.7 3.7 3.7 3.7 3.7 3.7 3.7 3	2 6.310 , 356 5.568 .318 1.772 , 790 .831 0 .836 2.69 96.3	1.5 6.332 .410 5,493 ,369 2.025 780 ,949 0 ,922 7.71 45	1 6.338 .411 5,537 .370 2.051 787 962 0 7.55 2.14 445	0 6.363 474 5:746 :311 2.038 774 755 50 972 2.67 745 0 6.363 428 5.546 387 2.147 789 1.005 2.73 457	0 6.34 .4th 5.553 .382 7.120 .787 .994 40 .995 2.61 44.7	5 6.346 .431 5.487 .394 2.161 ,790 1.03 TO 1.03 Z60 465	1 6.335 .421 5.563 .375 2.084 .783 .977 m .988 2.59 46.3 15 7 21 297 5.540 266 7.555 851 201 202 2.58 47	2 6.320 331 5.612 .296 1.664 795 300 80.777 2.59 46.3	25 6.308 .356 5.854 .333 1.367 .847 641 D.601 2.59 45	3 6.290 183 5.962 1.164 .975 ,849 .457 0 .430 2.57 43	ÖRI DE ()	G11 20	¥A1 OR	L PA QU	AGE 'ALJ	ONTINUED)
9 Voc, Isc. Vince, Inp. Page FF. rearbed an work, STD, 71, 73	5 5.648 .017 5.043 .015 .073 .746 .035 .040 2.94 41.7 345 4 6.357 .116 5.671 .105 .593 .821 .383 .776 2.95 48 375	14 64 262 819. 809. 177. 272.1 812. 228.2 00.2 826.3 E	2 6.373 .342 5.612 .305 1.709 .784 48 48 2.87 2.96 495 43	1.5 6.374 .379 5.524 .343 1.896 .786 .904 BD .900 2.91 507 45	1 6.398 ,406 5.538 .367 2.035 .783 9.70 0 9.964 2.85 495 43 5 6.397 417 6.535 379 2.097 7.87 999 0 990 2.84 50 44	0 6.391 ,423 5.498 ,384 2.113 .787 1007 p 1005 2.94 51 46	0 6.403 ,419 5.529 ,377 2.084 ,776 .793 ,595 2.95 49 44	2 6.903 (71) 3.757 (380 5.012 (2009 1.778 9.97) 10 2.94 47 41	14 74 49. as 19. 47. 409. 1 ESE. 504.2 78 2. 27.5 2.1	2 6.365 ,356 5,374 ,339 1,832 ,803 ,948 6 ,946 2.94 475 43 2.352 319 5417 303 1,633 ,807 778 6 758 2.94 45 41	0 5 2 6.300 .227 5.631 .203 1.41.1 EOS. 189.5 722 .005.3 E	4 6.054 1053 5.624 0.042 .736 .752 .112 .124 2.93 37 37 5 5.202 .007 4.343 .006 .026 .743 .017 2.93 38.2 36	7 7 4	20 28°C correduct	22 22 18.2 080 200 461 421 600 069.3 40. 201 3	75 79 88. 136. 435. 758. 097. 3818. 3818. 201. 115. 4	3 6.370 .296 5.74 .273 .835 .835 .746 .47 38	35 6.370 .329 5,613 .313 1.799 .833 .807 .731 2.84 475 41	14 84 100 100 100 100 100 100 100 100 100 10	14 84 192 389, 9 089, 797. 747. 741. 283. 200. 2 124. 498. 1 1000	14 274 192 2.638 .393 2.13 .811 1.001 19 299 2.92 2.92	0 6.381 .434 5.610 .381 2.110 .741 1.001 50 1.005 2.77 455 40	5 6.376 .427 5.576 .394 7.199 .870 1.014 50 1.000 7.63 45 39	1 6.372 .418 5.533 .387 2.140 .803 .987 10 .979 2.62 44 38	1.5 6.367 .373 5.640 .333 1.875 .790 .865 0 .874 2.62 44 38	2 6.368 .334 5.675 .306 1.734 .887 .807 0.806 2.66 425 37	\$2 24 39.2 369. 0 512. 028. 052.1 928. 376 3.68 42 38	4 6.311 .113 5.777 .094 .545 .775 .351 .365 2.69 375 37	5251 6551 111 1201 1201 0111 1401 2101 AUXICI 4101 ANDICI 6001 6		FIGURE A4 (CO

SC 28° corrected	3 6.19 .215 5.43 .207 1.12 .845 .569 70 .540 1.45 34	2.5 6.23 7.90 5.43 7.77 1.74 .818 .751 77 7.77 1.47 7.55 2 6.23 3.337 5.43 .305 1.66 .803 .843 so 843 1.33 33	15 6.21 ,356 5.45 ,307 1.69 .763 .558 20 .894 1.16 33	1 6.25	0 6.368 .398 5.49 ,356 1.96 ,787 .985 1.00 1.4× 335	15 6.78 .392 5.47 .363 1.98 .807 1.005 50 .985 1.49 34	1 6.36 .379 5.45 .349 1.90 .803 .764 50 .552 1.51 34 15 7.34 340 5.57 .304 1.70 .800 .863 D .854 1.50 345	2 6.23 , 299 5.67 , 266 1.50 , 803 .761 D .751 1.50 345	25 6.22 .253 5.67 .222 1.26 .774 .690 D .646 1.51 34		CELL 73-7 OFFPOINT 45°C @ O"angle RENCIABLE SNDER 19.9% ORONO estimated	04 29.2 577, 183, 728, 732, 922, 188, 712, 910, 1	17 19.2 LIL HIL SO8. 082' LIE' H38. 242' 8101 52	2 1.020 , 378 , 871 , 342 , 398 , 774 , 760 , 774 , 265 , 43	44 65.2 526. 126, 208, 232. C14. 538. 144. 5201 1	S 1.027 .476 .885 .436 .386 .799 .985 .798 .2.61 445	0 1024 477 881 444 7392 188 1.000 1.000 1.000	0 1,024 .477 .575 .987 .387 .386 .980 1.002 .747 .450 001 0	2 1.031 . 101 . 11: 11: 11: 11: 12: 12: 12: 12: 12: 12:	4 1.2 1.021 121 122 128 732 232 784 1.812 122 122 124 49	2 1.023 ,310 ,890 ,288 ,326 ,806 ,28 2.4 2.67 2.67	3 1,020 .167 .892 .157 .140 .825 .357 .350 2.68 52				ONT I NUED)
B Voc Isc Vmp Inp Prof. FF Par corected	7 6.247 .328 5,582 .379 1.558 .760 .734 P .775 1.75 36 2.5 6333 .241 5.559 .297 1.620 .763 .763 P .806 1.61 35	2 6.257 .376 5.544 .327 1.815 .773 .855 D .889 1.61 35	1.5 6.253 ,400 8,492 .363 1.973 ,187 .187 .187 .185 6 .979 1.67 36	5 6.298 422 5,448 ,393 2,143 .806 1.009 6 ,998 2.12 465	0 6.255 ,472 5.406 .395 2,134 .808 1.005 6 .991 1.61 375	1 C.359 407 5.436 391 2.116 807 996 6 991 1.4 21	1.5 6.327 .388 5.421 .358 1.942 .804 .914 6 .917 1.64 36	25 (224) 321 5.467 2.493 1.600 ,802 .733 4.8 1.8 1.8 1.8 1.8 2.467 .243 1.600 1.802 .251	3 6.175 .247 5.486 .228 1.252 .820 .589 80 .58 1.53 34	5B 28°C	2 25 0E.1 017. 42 334. 183. 210.1 081. 4EE.2 861. 351.2 E	2.5 6.311 , 757 5.668 , 734 1.324 .878 ,635 50 ,610 1.44 375	1.5 6.216 328 5.24 2.99 1.678 528 528 1.60 1.00 1.20 1.30	1 6.259 .385 5.468 .358 1.960 .813 .940 70 .41 1.43 33	- 5 6.263 .410 5.418 .379 2.051 .799 .984 TD .974 1.43 34	0 6.245 .420 5.342 .388 2.073 .790 .995 6 .998 1.25 21.5	1 2.01 1, 2.352 .353 3.050 ,783 .984 TD .998 115 JUD	15 6.341 .396 5.328 .363 1.931 .782 .927 19 19 19 19 19	2. 6.216 , 366 5,303 , 335 1.779 .783 , 954 6 ,869 1.22 315	3 6,168 . 289 5,289 ,252 1,335 ,748 ,641 6 ,686 1,13 30.5		OR OF	IGINL	AL R	PAG	FIGURE AL CON

		d	33	ļ	5	36	35	7	U	5,5	S	25	56	6								(nat	ĸ				. ^	و	9	2.5	6	7.5	5	6	0	6	5	SS	
		F	30.5		Y	5.45	34.5	33.5	36 3	<u>د</u> ء	34.5	33	582	5.85					···			CORREC	3/ 3	ז ז				35	35	\$5.5 3	36 3	35.5 3	36 3	36.5 3	37 4	37 3	36	33.5	
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	C COM	larm Esc				<u>~</u>	R	n	-	n	<u> </u>	-	<u> </u>	~	<u>.</u>					-	0	<i>20</i> 2	or	1				90 10	-/	00 / /	K 00.	00 X	00- K	8 3	87 3	26 J	68 1	34 3.	
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	N PAR	Ц Ч			61.	62.	61.	.78	. 79		.76	5		.78					in di			みんみんしも	22.	1		5	2 8	2 F.	۶.	.78	.77	.78	11.	.78	.78	18.	.8.	Ë	
	'B" 1	Pine	1.29		4.80	8.29	18.2	8.51	8.87	9.98	9.70	9.81	10.04	6.63					DUE TO			4 21	.66	0 (1	1 1 1		156	10.28	14.01	10.36	86.01	10.32	20.01	9.07	42.8	7,38	3.68	
	S H9A	Ime	.25		.86	-20	1-41	1.55	1.63	\$.8	.83	28.	\$8	18.	<u></u>				47.4		:	S B	51.			9 5	0	4	68	26	52	26	16	86	66	49	3	ور	
	1 Тнко	đ	33		24	2	2	\$	E.	2 2	31 1	38 / /	1 58	<u></u> Ω					a a			HOUCH	54		<u>, 1</u>	<u> </u>		 		י <u>ן</u> נו	9 1.		9 1	9 1.	7 1.	1	3 1		
	VGS	X	'S		5	<u>بر</u> مر	ŝ	5:5	5.4	5.3	5	5	5	5,3				<u> </u>	8			-	2'5		5	9 (N (<u>,</u> 1	1 5 1	5.4	5.5	5,3	5.4	5,3	5.3	5.4	5.5	5.6	5.6	
	STR	Ts.	35.		6.	1.64	1.55	1.73	1.78	2.04	10.5	1.99	30.6	1.96	4			•				5-9~124	.10	1	\$ <u>,</u>	Į		681	2.03	2.11	2.11	3.11	7.11	2.02	1.83	1.2.1	₩.	Ŗ	
		Voc	6.07	-	6.29	6.35	6.35	6.36	6.34	6.37	6.37	6,36	6.37	6.28								15	5,93		6.24	6.50		25.2	6.36	6.36	6.36	6,37	6.36	6,35	6.35	6.33	6.33	6.24	
		θ	4	5	M	2.5	R	1.5	~	Ś	0	0	Ň	-	1.5	К	3.5	ц	3.5	4			S #	2	ž,	ę y	< Y	5 7	6	6	200	5	r 4	ţ	Š	522	25	10 ×	
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		-	33 37	ñ	26 - 2	5	3 45	3 47	3 47	5 46	۲ ۲	5 43.	5 45	5	24 2.	1 43	9 41	25 39	0 37	37		(naus	15 33.	33	+ 35	5 10 15	5	1 19	- 6°	5 39.	26	2	5 42.5	3 43	2 5	2 45.	5 44.	42.7	-
•		e	38	<u>.</u>	2 2	47 9	46 4	<u>+</u>	4 4	3	5 5	4 41	5	16 8	9 42	0 4	0 0	4	8 8	5 2		CORRE	8	m m	۳ م. ر	r 	<u>, a</u>	-: • 	n 5 	. 3		- *	<u> </u>	3		+ 4		- 2	
	(vorta	Е ч	8	<u>к</u> 17	2 2 2	ій м	7	4 N	2,6	وزلا	0.0	0 2.3	0 2.4	2,3	7 3	7	ц 4	2.2	n n	u u		° (28°	2.2	ē.	<u>к</u> ,		- 0	0 0 0	2.0	В В	й. Й	n N N	2.3	2.35	2.2	ц Ц	2.3(2.4	
	score	2 Fi 	0	Ŕ		ب	<u>, v</u>	Å,	6.	6	<i>е</i> ,	1.0	1.0	<i>.</i>	¢	38.	.78	59,	5.	50.		TED 90	50.	ŗ.	Ň		ŝ		<u>;</u> ;	6.	- 62	.8	°.,	. 58	,93	.86	.80	68.	
	r (38,	15	6.	٢,	¢.	S	64.	28.	26.	56.	66.	1.00	1.00	66.	.93	.85		.68	53	.37		Roth	+0.	ź	87.	8	j j	2 2	6	.97	- 62	1.00	66.	36.	.93	°52.	. \$0	85°	
	JACALE	Ľ	12.	84.	11.	66	18'	. 80	.78	.78	28'	,78	34,	,78	11.	.77	"	.76	SL'	<i>۲۲:</i>		フヨフフトの	.66	. 68	51,	21.		26	78	.78	64.	.78	,78	• 78	82'	61.	20	08.	
	N, N	Pmp	.67	2.14	15'4	6.42	40'8	8.75	9.36	9.99	010	61.01	42'0	10.04	9.48	8.71	7.88	16.9	2.44	3.75		ted NI	57.	1.14	2.97	2010	5 . 5 . 6 .	200	9.75	12.0	52.0	12.0	0.43	0.37	7.80	9.03	64.8	7,28	
	1 5 F	<i>م</i> لس	. 13	.34	\$2.	1.16	7 47	é,	76	88	847 1	16	10	85 - 85	76	61	, Sh	26	66	68		رد د	60	22	54	20	, l , l	57	78	88	88 /	34 1	1 22	10/	82			<u> </u>	
	Ducence	I di	14	2	52	21	1 4	<u>ن</u> د	С	: 3	36 1.	+ /	~ 0	 ~		· 0	 +	· 0		0	:	NOUCH	~	<u> </u>	•	•••	< - 	- 1		, , ,		~` 	~		~ ~	~	5./		
	1 2000	Υ,	ษ	3	5,5	5	5.4	5,3	5,3	5.3	5,3	5.34	5.4	5.4	5,∉	5.4	5:4	5,5	5 S	5.5		4 -	6'6	2.1	ν, ι γ	~ ~ ~		1 3 1 0	3.5	5.42	5,43	5,45	5,43	5.40	S N	14.2	5,50	5.53	
	STRN	<i>T</i> 5,	.16	54.	6.8.	1.29	1.57	1.73	68'1	10.5	1.936	3.06	50.2	2.03	1.93	1.78	1.61	1.43	1.16	18.		STRWGS	=-	28		202		1.80	1.95	2.04	2.04	3.11	2.10	2.07	1.97	1.8.1	1.65	54.1 66.	
		Voc	5,88	6.13	6.36	(.31	6.34	6.33	6,35	6.38	046.3	:.37	6:39	8	5.37	:36	:35	. 33	.30	,26			5.70	5.97	6.17		2.2	22	6.37	.37	:39	.40	.39	.39	:38	ネ	ह, १	25. 32	
•		.0	4	35	m	25	a	1.5	7	Ń	0	0	v	-	1.5	ñ	2.5	3	35 6	4 0	F	49	H.	6 2	012	<u>}</u>	67	17	90	Ø	Ø	3	e F	2	k k	200	7	2 0 1 1	
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FIGURE A5 COMBINED STRINGS CORRECTED FOR INSOLATION AND TEMPERATURE

OFFRUM	~		4		1												
AMLE			INDIN	DWL	HAL	2 K	S S S S S S	ļ			I		•	•••	Elect	° •	90
	4	8	8	28	99 9	38	44	4 B	SA	SB	SC	V	۲	4	8	8	8
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ს			e.	ş	•02	.10							.				
3-			.19	ų.	ы.	45							0%	<i>.</i>			
3	.90		.63	. 87	80	5	.49	.80	101	.61	.70	22.	-55-	-64	22	.73	
2.5	<i>36'</i>		5	10.1	16.	16.	.67	ε.	101	90	16.	.87	66.	.8,	16.	26.	
ĸ	1.05	178°	16.	90%	.96	.97	.75	.99	1.06	50.	8.	. 94	.90	16.	22.	.97	
<u>i</u> ,	201	.87	56.	101	56	103	.78	1.04	207	\$\$.	76.	46.	66	56.	76	.97	
-	00-1	.93	.95	1.03	<u>99.</u>	101	.87	8	107	46.	- 47	96'	46.	46.	86	8	
ຸ່	8.	86.	.97	20.1	00-1	1.00	.95	86.	1.00	.98	1.00	86	66	86	8	1.01	
0	100	00.1	1.00	1.00	1.00	1.00	1.00	1.00	100	1.00	00-1	1.00	1.00	100	1.00	1.00	
0	1.00	1.00	1.00	1.00	1.00	1.00	007	1.00	00-1	8,	1.00	1.00	007	1.00	1.00	00%	
Ś	1	10-1	99.	1.00	00%	1.01	1.02	1.02	1.00	00.1	66.	1.00	10.1	1.01	101	10.1	
	1.00	1.01	99.	101	100	10.1	1.00	101	99.	101	86.	1.00	10.1	10-1	1.01	8	
15	1.02	00.1	.95	195	007	46.	.96.	1-00	66.	101	26.	36.	10.1	1.00	86.	46.	
R	1.02	1.02	35	16.	107	ж.	.96	26.	1.02	603	-89	.99	201	1.02	%.	.90	
25	66.	.90	\$	88.	26.	86'	3	22.	26.	66'	.79	8	- 6-	1.00	96.	5	
ς.	88.	.60	8.	.70	14.	16.	112.	,56	<i>3</i> /.	.89	.وج	22.	06.	88.	.73		
5	35.	1	.16	ÿ	.17	.34	•						50				
ა	١			.03	•03	.05	_			•							
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				REFLE	CTANC	E OF)		• • • • • • • • • • • • • • • • • • • •						

ORIGINAL PAGE IS OF POOR QUALITY.

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 through 10D. During that time the panel was stored but not bagged in the array manufacturing area as well as the test stand. It was noted that additional contamination of the mirrors was evident. Strings 1A through 1D and 2D were remeasured to see this effect. An apparent 1 to 12% loss in output was recorded compared to earlier readings. The average was near 5%. Also noted was additional conic mirror coating degradation in terms of actual increases in defect areas. It was not possible to determine the relative contributions of the contamination and conic mirror degradation to the total loss recorded. Data for the remeasured mirrors is noted as strings 1A2 through 1D2 and 2D2.

As with the small panel data, the large panel data is shown corrected to standard conditions in Figure A7 and corrected for conic mirror average loss (0.70) in Figure A8. Note that with reference to efficiency in Figure A8, an efficiency of 15.5% would represent a 20% efficient cell in an optic with nominal capabilities as defined in the main text figure 4-4 "corrected".

3.4 SECONDARY MIRROR TESTING

The secondary proof mirrors (bare nickel) were checked by bonding each to a dedicated nickel spider and then successively measuring the short circuit current output of two primary subassemblies at various pointing angles. Figure A09 shows the current and normalized output recorded for eight proof secondaries corrected for intensity only. Figure A-10 shows the normalized data corrected for conic mirror reflectance of 0.70.

ION		NOI	NOI	NOI
INSOLAT.	TEMP ERROR 1.1 1.1 1.4 0.5 0.5 0.5 0.5 0.5	INSOLAT TEMP ERROR 0.1 0.1 0.6 0.6 0.6 0.8 1.1 1.2 1.2 1.7 0.4	INSOLAT TEMP 6.5 0.5 0.8 0.6 0.6 0.5 0.5 0.5 0.5 0.5 0.5	INSOLAT TEMP 5.3 1.7 1.7 1.1 2.3 2.3 2.3 2.3 2.3 2.3 2.3 0.4 0.4
E AND	ORIG TEMP 339.2 38.5 37.2 33.5 33.5 33.1 29.3 29.3	te and Orig Temp 25.3 26.1 24.4 22.8 23.3 22.8 23.3 21.2 21.2 21.2 20.7 18.5	RE AND ORIG 27.7 25.3 25.0 23.4 33.4 33.4 34.3	RE AND ORIG ORIG 322.8 25.8 25.8 25.8 25.4 27.4 33.4 33.4 33.4 26.9 31.4 26.9
ERATUR	FILL ACTOR 726 757 778 778 778 769 763 763 7763 7752 7752 7752	PERATUR FTILL ACTOR B31 B31 B31 B33 B33 B17 B17 B13 B13 B13 B13 B17 B17 B17 B17 B17 B17 B17 B17 B17 B17	PERATUF FACTOR FACTOR . 809 . 776 . 714 . 714 . 813 . 813 . 833 . 833 . 833 . 773	PERATUI FILL 736 736 736 736 736 736 736 736 738 738 738 776 7763
OR TEMP	PMP (W) 1.476 1.488 1.488 0.965 0.686 1.495 1.238 0.604 0.410 0.410	CR TEMI Y PMP PMP (V) 22.147 22.147 1.131 1.131 1.131 1.131 2.153 2.153 2.153 2.153 1.898 1.898 1.607 1.607	COR TEM PMP (W) (W) (W) (W) (W) (W) (W) (W) (W) (W)	FOR TEM TY PMP (W) 1.887 1.579 1.579 1.579 1.579 1.579 1.579 1.579 1.579 1.579 1.579 1.579 1.555 0.555
	Imp Imp (A) 3318 321 284 136 136 136 080 080 042	(A) (UALI 193 (A) (A) (A) (A) (A) (A) (A) (A) (A) (A)	CTED IMALI (A) (A) (A) (A) (A) (A) (A) (A) (A) (A)	CTED IMP IMP IMP (A) (A) (A) (A) (A) (A) (A) (A) (A) (A)
CORREC	WMP	CORRECT CORREC	CORREL IIRROR (VMP (V) (V) 5.087 5.) CORRE MIRROR WPP VMP (V) (V) 5.064 5.064 4.885 4.885 4.885 4.885 4.885 4.885 4.840 5.015 5.015 5.015
NG 3A	1125 1125 (A) 3364 3364 3364 161 161 142 098 098 098	NNG 38 112C NG 38 412 412 412 412 1143 1143 1143 1143 1143 1143 1143 1	NIC NIC 30 001C A 15C A	NIING 31 15C 15C 15C 15C 15C 15C 15C 15C 15C 15C
STRI	VV) VV) 6623 · . 5551 · . 5525 · . 5525 · . 5525 · . 5522 · .	C C C C C C C C C C C C C C C C C C C	<pre>c STRI 40T CC 70C 70C 70C 702 083 084 071 071 071 071 071 073 073 073 073 073 073 073 073 073 073</pre>	<pre>% STR: 007 C(007 C(0012 0034 0034 0034 0034 0034 0034 0034 003</pre>
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				-
ATION	6	ATION	ATION	ATIO
INSOL	TEMP ERRO 0.1 0.2 0.2 0.2 1.3 1.3 1.5 1.5	INSOL TEMP 1.1 1.2 1.2 1.2 0.5 0.2 0.2 0.2 0.2	ERRAN	INSOU ERROL 2.6 0.1 1.1 2.6 0.1 1.2 1.2 0.1 1.2 1.2 1.2 1.2 1.2 1.2 1.2 1.2 1.2 1
re and	0816 760 30.07 33.48 33.48 33.89 33.88 33.89 33.88 33.89 33.89 33.89 33.89 33.89 33.20 33.20 33.20 33.20 33.20 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.00 30.000 30.000 30.00000000	RE AND 0R1G 29.6 30.0 31.0 33.1 33.1 33.1 33.1 33.1 33.7 33.7 33.7	IRE AND 0R1G 422.1 422.1 333.5 33.5 33.5 33.5 33.5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 33.5 5 5 33.5 5 5 33.5 5 5 33.5 5 5 33.5 5 5 5	RE AND 0R1G 33.4.5 33.4.5 33.4.5 33.1.1 32.0 32.0 32.0 32.0 32.0 32.0 32.0 32.0
PERATU	FILL FACTOR 811 .811 .773 .773 .773 .773 .778 .778 .778 .778	PERATUL FILL 812 .812 .812 .812 .812 .812 .812 .812	PERATU F11L FACTOR 779 .779 .779 .779 .779 .779 .779 .779	PERATU FILL FACTOF 794 7794 7792 7795 7772 7772 7772 7772 7772 7772
OR TEMI	PMP (W) 1 (W) 1 (W	OR TEM PMP (W) (W) (W) 1.761 1.761 1.590 1.590 1.590 1.870 1.233 1.233	FOR TEM IY PMP (W) (W) 1.699 1.699 1.631 1.631 1.631 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.738 1.746 1.746 1.746 1.647 1.646 1.647 1.747 1.647 1.747 1	FOR TEM PMP (W) (W) (W) (W) 1.942 1.256 1.256 0.059 0.0559 0.0559 1.264 1.920 1.647 1.462 1.046
TED F	IMP IMP 3323 336 336 3376 3376 2393 108 108 108 108 108 108 108 108	TED I IMP IMP (A) 394 403 320 403 320 403 320 403 330 240 330 240 330 240 330 240	TED I UALI I MP (A) (A) (A) (A) (A) (A) (A) (A) (A) (A)	CTED IMP IMP (A) 399 374 374 374 374 374 374 374 373 374 154 154 154 154 154 154 154 154 154 15
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AND I	RIG . 15.0 28.7 29.0 29.0 29.0 28.5 28.5 28.5	AND 11 233333333333333333333333333333333333	AND I AND I 338.6 336.5 336.5 335.6 335.1 34.1	AND I TEMP 37.9 33.1 33.1 33.1 33.1 33.1 28.1 33.1 50.9 30.9
ERATURE	FILL C ACTOR 1 757 757 758 784 811 840 840 840 840 760 840 840 840 840 840 840 840 840 760 840 840 840 760 840 760 840 778 787 787 787 788 777 788 7777 788 7777 788 7777 788 77777 778 7777 778 7777 77757 77757 77757 77757 77757 77757 77757 7767 77757 7767 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 7768 77757 77757 7768 777577 777577 7775777 7775777777	ERATURE FTLL ACTOR 786 7786 7768 7768 7785 785 786 788 788 787 787	PERATURE ACTOR - 768 - 768 - 850 - 850 - 850 - 775 - 775 - 184 - 1	PERATURE FILL 776 .776 .808 .831 .832 .831 .776 .776 .748 .741 .741 .741
R TEMP	PMP (W) 658 658 503 502 503 584 584 584 584 584 584 584 584 584 584	R TEMF PMP (W) F (W) F (W) F (W) F (1) F (R TEMF PMP (W) F (W) F (R TEM PMP (W) (W) (W) (W) (W) (W) (W) (W) (W) (W)
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FIGURE A7 DATA FOR 15 x 56 PANEL CORRECTED FOR TEMPERATURE AND INSOLATION

A12

INSOLATION INSOLAT INSOLAT INSOLAT ERROR 6.2 8.3 8.3 8.3 9.4 8.3 8.3 8.4 8.4 TEMP ERROR 1.6 1.4 1.1 1.4 1.1 1.5 3.0 3.0 4.0 TEMP ERROR 2.1 2.1 2.1 2.1 3.5 2.8 3.5 2.3 2.3 2.3 2.3 2.0 2.0 ERROR 1.5 1.5 1.4 0.7 3.3 3.4 3.3 3.3 3.3 4.0 4.0 AND AND **Å** 0816 116 54.5 54.5 50.8 50.8 50.8 44 5.6 44 5.6 45.6 45.6 45.6 AND ORIG TEMP 550.4 48.5 550.4 48.5 49.2 44.1 44.1 44.5 44.5 FOR TEMPERATURE TEMPERATURE TEMPERATURE TEMPERATURE FILL ACTOR .723 .767 .837 .837 .837 .837 .727 .719 .719 .789 .789 .789 FILL FACTOR .751 .751 .801 .816 .816 .807 .752 .807 .787 .763 (W) (W) 1.451 1.451 1.418 1.216 1.216 1.215 0.871 1.311 1.473 1.311 0.913 0.759 0.567 (W) 1.560 1.511 1.511 1.510 0.972 0.972 0.801 1.570 1.556 1.128 0.856 (W) 1.644 1.644 1.131 0.884 0.597 1.652 1.652 1.140 0.967 0.967 đ MP diid . For . For FOR 00 Y QUALI IMP IMP 357 357 355 339 339 339 339 257 339 257 184 CORRECTED CORRECTED CORRECTED (V) (V) 705 986 058 086 732 881 881 RROR RROR RROR VMP (V) 4.184 4.184 4.136 4.136 4.136 4.204 4.210 4.282 4.282 4.282 4.282 4.282 4.282 4.282 4.282 4.282 4.282 4.238 VMP (V) 5.016 5.130 5.130 5.130 5.135 5.135 5.314 5.314 5.314 5.314 5.314 5.314 5.314 5.314 5.314 5.314 5.314 5.315 5.314 5.315 5.31 6A MII **3**88 ×Ψ ωĪ പ STRING DT CONIC g CONI STRI STRI NOT (VOC (V) (V) 895 881 903 903 903 903 919 919 VOC (V) 757 757 757 757 782 782 782 781 781 781 781 692 NOT I VOC VOC VOC VOC 797 NOT For FOR For ່ທ່ທ່ທ່ DATA FO BUT DATA FO BUT DATA FO BUT DATA FC BUT ANGLE (DEG) 0.0 1.0 2.5 3.0 0.0 -2.5 -2.5 -2.5 -3.0 ANGLE (PEG) 0.0 1.0 2.5 3.0 0.0 -2.5 -2.5 -2.5 -3.0 (DEG) 0.0 1.0 2.5 2.5 2.5 -2.5 -2.5 -2.5 ANGLI NO N NO **INSOLATION** S INSOLAT INSOLA INSOLAT TEMP ERROR 3.3 3.3 1.9 1.2 1.2 1.2 1.1 1.1 1.1 1.1 ERROR 0.6 0.3 0.4 0.4 0.4 0.7 2.1 1.1 1.1 1.1 1.6 2.9 TEMP ERROR 1.7 0.6 1.4 1.5 1.5 1.5 1.5 1.9 2.9 TEMP ERROR 3.4 2.1 2.2 2.4 2.8 0.5 0.5 2.8 AND AN ORIG TEMP 40.3 39.8 336.6 337.9 337.6 337.6 337.6 337.6 ORIG TEMP 551.07 499.2 449.8 46.9 46.3 46.9 ORIG 1TEMP 43.1 442.7 442.7 442.7 339.4 339.3 339.3 339.3 339.3 339.3 339.3 339.3 339.3 AND AND FOR TEMPERATURE FOR TEMPERATURE TEMPERATURE FOR TEMPERATURE FILL FACTOR .804 .827 .821 .821 .821 .822 .820 .795 .795 .820 .820 .860 F1LL FACTOR .816 .808 .826 .838 .833 .857 .831 .831 .831 .849 .847 (W) 1.856 1.856 1.826 1.874 1.874 1.373 1.137 0.466 (W) 1.864 1.858 1.698 1.698 1.511 1.295 1.208 1.208 0.955 0.955 (W) 1.660 1.150 0.895 0.895 0.895 1.662 1.662 1.662 1.662 1.662 1.662 qMq PMP CORRECTED FOR T IRROR QUALITY VVP IMP PMP VVP IMP IMP PMP 5.236 .355 1.855 5.231 .355 1.855 5.231 .355 1.855 5.231 .355 1.855 5.232 .356 1.865 5.232 .356 1.865 5.232 .356 1.865 5.354 .222 1.29 5.399 .177 0.555 5.399 .177 0.555 P.P. CORRECTED (V) 5.087 5.152 5.155 5.155 5.155 5.155 5.155 5.146 5.146 5.146 5.143 5.255 5.363 RROR (V) 884 902 902 751 751 920 920 920 916 902 916 đW 5A MII 5C MI ¥I 28 20 M STRING g STRING S CON STRI NOT CO V0C (V) 5.994 5.975 5.975 6.010 6.010 5.878 5.878 5.878 5.878 NOT C VOC (V) 6.325 6.287 6.248 6.248 6.228 6.228 6.215 6.215 6.126 6.126 6.045 5.947 Not DATA FOR BUT NO ANGLE VOI FOR ñ ß DATA FO BUT BUT BG ANGLE (PEG) 0.0 1.0 2.5 3.0 0.0 0.0 --2.0 -2.5 -3.0 ANGLE (DEG) 0.0 2.5 3.0 2.5 2.5 -2.5 -2.5 -2.5 ANGLE (DEG) 0.0 1.0 2.5 3.0 3.0 --2.0 --2.0 -3.0 DATA DATA ORIGINAL PAGE IS OE POOR QUALITY 8 INSOLATION INSOLATION 8 INSOLAT INSOLAT TEMP ERROR 1.2 1.2 0.2 0.6 0.6 1.1 1.1 1.3 1.4 ERROR 2.8 2.6 2.5 2.5 2.5 2.5 2.5 3.0 3.0 3.3 3.1 3.1 TTEMP ERROR 0.7 1.4 1.5 1.6 0.7 0.7 0.8 1.8 1.0 ERROR 1.7 1.7 1.7 1.3 1.3 1.3 1.3 1.3 1.3 1.3 2.0 2.0 2.0 AND AND ORIG TEMP 29.7 332.8 332.8 332.1 337.1 337.1 337.1 331.4 331.4 331.4 25.5 25.5 26.5 AND AN ORIG TEMP 23.9 224.5 224.5 23.1 221.9 221.9 221.9 221.9 ORIG TEMP 32.3 33.5 33.5 28.1 28.1 28.6 28.6 33.5 33.5 28.6 28.6 28.6 28.6 28.6 28.6 28.6 29.4 24.4 ORIG TEMP 23.6 24.3 24.3 24.3 25.5 525.5 225.6 227.8 227.8 223.3 222.0 222.0 FOR TEMPERATURE FOR TEMPERATURE TEMPERATURE TEMPERATURE FILL FACTOR 737 737 737 8837 .833 .834 .733 .733 .752 .779 .779 .836 FILL FACTOR .678 .637 .716 .743 .743 .743 .787 .787 .814 .818 .818 FILL FACTOR .821 .823 .823 .825 .867 .826 .826 .826 .812 .809 .809 FILL FACTOR .836 .824 .843 .843 .849 .828 .828 .828 .828 .828 .828 .823 .834 PMP (W) (W) (-793 (-793 (-793 (-793 (-779 (-779 (-779 (-779 (-779 (-779 (-779)) (-779) (-779) (-779) (-779) (-770) PMP (W) (W) 701 779 777 777 777 PMP (W) 1.945 2.073 1.888 1.716 1.716 1.521 1.633 1.673 0.909 0.745 (W) 2.171 2.171 2.172 2.176 2.171 2.262 1.313 2.069 2.806 3. PMP
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A13

FIGURE A7 (CONTINUED)

DATA FOR STRING ID2 CORRECTED FOR TEMPERATURE AND INSOLATION BUT NOT CONIC MIRROR QUALITY ANGLE VOC ISC VMP IMP PMP FILL ORIG TEMP (DE6) (V) (A) (V) (A) FACTOR TEMPERROR 0.0 6.034 391 5.006 345 1.727 733 36.5 0.1 1.0 5.972 366 4.910 337 1.655 757 38.9 0.6 2.0 6.077 302 5.249 282 1.480 807 31.5 1.2 2.5 6.049 239 5.333 185 0.989 823 33.1 0.3 3.0 6.061 338 5.039 343 1.727 777 717 34.2 1.0 0.0 6.061 339 5.028 312 1.570 7708 34.5 0.4 -2.0 6.041 367 5.028 312 1.570 7708 34.5 0.4 -2.0 6.041 367 5.028 312 1.570 7708 34.5 0.4 -2.0 6.041 367 5.028 1.727 7.717 34.2 1.0 -2.0 6.041 367 5.028 1.727 7.717 34.2 0.7 -2.5 6.049 309 5.060 253 1.570 7.078 332.2 0.7 -2.5 6.049 309 5.060 253 1.570 0.600 32.0 0.3 -3.0 5.873 1.57 4.845 1.26 0.610 .660 32.0 0.3 INSOLATION TEMP ERROR 3.8 3.2 0.8 0.8 0.8 0.8 0.8 0.8 1.1
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N												<u>N</u>																NOL	5																	U D	2															
INSOLATI	TEMP	ERROR	0.6	0.1	0.6	0.3	0.1		+ I		.,	INSOLAT		TEMP	ERROR	1.5	1 0				c	0.0	1.3	0.7		, r 		TA IOSUT	INSULAI		I EMP	FRROR				<u>د.</u> 0	0.1	0.4			1 .1	1.7	1.5	4	;	TNSOLA		TLUD		EKKUK	c.0	0.4	0.7				4.O	1.1	1.6	0.5		
re and	ORIG	TEMP	42.8	41.2	39.8	41.6	45.3	4/./4	4.14	D. 54		IRE AND		ORIG	TEMP	38.1	1 2 2 2 2 3			1.70	2.45	37.4	38.4	37.2	10.10	0.10	1.10		JRE AND		ORIG	TFMP	28 J		20.2	39.9	37.6	37 5			31.1	35.0	37.5		1.55	NDF AND		0100	UKIG		31.1	33.1	33.9	20 4		1.20	36.3	36.7	37.6	38.5		
PERATU	FILL	FACTOR	. 665	.689	.732	.759	5775	2	46/.	. / 12	ct /.	MPERATU		FILL	FACTOR	814	797	100	170.	+ no -	.833	. 781	.792	846	200		- 8U4	TAGION	MPERAI		FILL	FACTOR	200		. / 83	.791	.740	745	200	100.	.800	.804	808	200		CMDCDAT			11L	FACTOR	.789	.805	.823	110		768.	.787	.764	197	200	486	201
FOR TEV	ЫМ	(M)	0.897	0.914	0.843	0.732	0.787	c// 0	0.681	196.0	124.0	FOR TE	ITΥ	PMP	(A)	1,390	202		161.1	1.050	0.940	1.329	1.276	1 099		202.0	0.790	11 001	FOR TE	λLI	dMd	Ξ	1 746		1/0.1	1.436	1.160	0 856	1 750	1.130	1.743	1.555	1 350	200 1		E DD T		111-	L M L	3	1.956	1.920	1.759	174	104.1	0.93/	1.944	1.768	1 431	1 008	1.000	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,
CTED	đ	(A)	307	310	275	234	252	251	224	504	0 #	CTED	QUAL	IMP	(A)	404	370			<u></u>	.26/	.387	.373		200	107.	177.		ECTED	QUAL	M		2000	2	.314	. 286	.228	168	51.	0 t 0	. 338	299	260		nn 7 -	CLEC			T T	E	.373	.366	330		*0.7.	G91 .	.376	338	124	101	121.	700.
DB CORRE MIRROR	dων	(V) ••••	2.920	2.952	3.071	3.131	3.125	3.083	3.033	2.844	109.7	A2 CORRI	MIRROR	dW	2	3 441	2 425			3.484	3.515	3.433	3.418	3 547		+10.0	3.489	0000 00	B2 CORR	MIRROR	AMP	5	150		210.6	5.017	5.089	5 100		C/1/2	5.148	5.192	5 200		C07.C				AWA	Ξ	5.251	5.252	5 332		0.000	5.692	5.167	5.226	5 281	101.0	107.0	010.0
ING 10	ISC	(A)	341	334	. 290	.246	.261	.259	.234	.216	. I 33	I NG 1	CONIC	ISC	(A)	422		2	100.	320	.279	.421	401		200	167-	. 240		ING	CONIC	ISC		Ξů		334	. 305	. 263	102	2.1.	2002.	.362	321	080	35	c77.	- UNIC	- ONLY	- CNT	150	3	.403	.389	350		C97.	. 181	.406	382	200	227.	52.	TCI.
IN STR	NOC 1	(V)	020	3.972	3.967	3.915	3.882	3.852	3.851	3.782	5./U4	DR STR	T NOT	VOC	2	A 047			1000	4.029	4.042	4.043	4 014	000 F		4.010	3.99/		OR STF	IT NOT	200	(N)	E 003		6.003	5.943	5.970	F 027	100.1	0.440	6.015	6.031	5 076		070.0	110 00-			202	Ξ	6.160	6.131	6 108		0.110	6.083	6.085	6.061	6 033	r 005	5.400	2.714
DATA FC BUJ	ANGLE	(DEG)		5.0	2.5	0.0 .0	0.0	-1			-3.0	DATA F	BU	ANGLE	(DEC)			- 0		ç.2	з.0	0.0	0 [-			c .,	-3.0		DATA F	3	ANGLE	(DEC)			1.0	2.0	2.5			0.0	-1.0	- 2 0			- 2.0	1 47.40		ที่	ANGLE	(DEG)	0.0	1.0	0		2.7	з.0 З	0.0	0-1-		2.1	0.7-	-3.0
																				-																																										
ION												NOL								-									LION																		ION															
INSOLAT ION	TFMP	ERROR	8. . c	3.1	2.8	1.8	3.0	3.6	3.5	4.2	5./	INSOLATION		TEMP	EDDOD				2.1	3.1	3.3	9		1.7	5.7	3.3	3.7		INSOLATION		TEMP		EKKUK	1.4	1.9	3.7	11		<u>c.</u>	1.7	3.1	C 4		3.2	3.2		INSULAI JUN		TEMP	ERROR	1.5	1 6			2.8	2.0	2.2	0.0	, u	0.7	1.2	2.4
AND INSOLATION	ORIG TEMP	TEMP ERROR	45.b 1.8	42.8 3.1	45.6 2.8	43.9 1.8	45.4 3.0	45.6 3.6	43.8 3.5	40.5 4.2	41.3 5./	AND INSOLATION		ORIG TEMP			40.3 2.3	5.2 8.64	43.8 2./	42.3 3.1	41.5 3.3	413 39			41.9 2.9	42.2 3.3	40.1 3.7		E AND INSOLATION		OPIC TEMP		IEMP EKKUK	4/.0 1.9	49.9 1.9	44.9 3.7			39.5 1.5	44.6 1.7	43.1 3.1	42 0 4 0	10.1 1.1	43.4 3.2	43.9 3.2		E AND INSULATION		ORIG TEMP	TEMP ERROR	41.0 1.5	16 185	20 1 2 7		41.0 2.8	41.2 2.0	44.5 2.2	43.8 3.0	10.1 0.1 10.1 0.1		91./ 2.J	3/.1 4.5
FRATURE AND INSOLATION	FILL ORIG TEMP	ACTOR TEMP ERROR	.656 45.6 1.8 541 40 0 2 2	.041 40.0 5.2 697 42.8 3.1	.655 45.6 2.8	646 43.9 1.8	.660 45.4 3.0	.710 45.6 3.6	.760 43.8 3.5	.765 40.5 4.2	.763 41.3 5./	PEPATURE AND INSULATION		ETLI ORIG TEMP	FILL UNIG ILTE FACTOR TEMD EDDAD	FALIUM TEMP ENNUM		8.c4 5./.	.764 43.8 2./	.765 42.3 3.1	.715 41.5 3.3	738 413 39			.860 41.9 2.9	.861 42.2 3.3	.863 40.1 3.7		PERATURE AND INSOLATION		ETLI OPIC TEMP	FILL ONLY LET	FACTOR TEMP EKKOK	./08 4/.0 1.9	.741 49.9 1.9	763 44 9 3.7			.658 39.5 1.5	.700 44.6 1.7	536 43.1 3.1	70E A2 7 A 7		./23 43.4 3.2	.734 43.9 3.2		PERATURE AND INSULATION		FILL ORIG TEMP	FACTOR TEMP ERROR	.628 41.0 1.5	612 387 21		1.3 I.CC 010.	505 41.6 Z.8	.029 41.2 2.0	.625 44.5 2.2	476 43 8 3.0		0.7 4.74 444.	.5/1 41./ Z.1	.3/9 5/.1 4.5
OR TEMPERATURE AND INSOLATION	DIND FILL ORIG TEMP	(W) FACTOR TEMP ERROR].505 .656 45.6 1.8 . 458 541 48 0 2 2	1,430,041,40.0 5.5 1 134 697 42.8 3.1	0.973 .655 45.6 2.8	0.844 .646 43.9 1.8	1.518 .660 45.4 3.0	1.435 .710 45.6 3.6	1.083 .760 43.8 3.5	0.936 .765 40.5 4.2	0.620 .763 41.3 5./	COD TEMPEDATIIDE AND INSOLATION		DALD FILL ORLY TEMP	THE FILL UND THE	(W) FACIUM TERF ERNUM	I.349 .//0 40.3 2.3	1.364 ./93 45.8 2.3	1.155 .764 43.8 Z./	0.999 .765 42.3 3.1	0.772 .715 41.5 3.3	1 206 738 41 3 3 9		1.7 6.14 60/. 677.1	0.854 .850 41.9 2.9	0.707 .861 42.2 3.3	0.551 .863 40.1 3.7		FOR TEMPERATURE AND INSOLATION	TY	DWD FILL OPIC TEMP	THE LICE ONLY THE FORD	(W) FACTOR TEMP EKKUK	1.438 ./08 4/.0 1.9	1.187 .741 49.9 1.9	0 964 763 44 9 3.7			0.394 .658 39.5 1.5	1.423 .700 44.6 1.7	1 024 536 43.1 3.1		1.7 1.07 00/. CI1.1	1.052 ./25 43.4 3.2	0.897 .734 43.9 3.2		FOR TEMPERATURE AND INSULATION	TY	PMP FILL ORIG TEMP	(W) FACTOR TEMP ERROR	n 931 628 41.0 1.5	0 030 612 387 21	0 70E EIO 30 1 2 7		0.559 .565 41.6 2.8	0.025 .029 41.2 2.0	0.910 .625 44.5 2.2	0 574 476 43 8 3 0		0.2 4.24 444. 700.0	U.182 .5/1 41./ 2.1	U.114 .3/9 3/.1 4.5
TED FOR TEMPERATURE AND INSOLATION	UALLIT TMD DMD FILL ORIG TEMP	(A) (W) FACTOR TEMP ERROR	342].505 .656 45.6].8	255 1.450 .041 40.0 5.5 257 1 134 .697 42.8 3.1	227 0.973 .655 45.6 2.8	196 0.844 .646 43.9 1.8	343 1.518 .660 45.4 3.0	321 1.435 .710 45.6 3.6	231 1.083 .760 43.8 3.5	201 0.936 .765 40.5 4.2	.137 0.620 .763 41.3 5.7	TEN END TEMPEDATLIRE AND INSULATION		TWD DWD FILL DRLC TEMP	INF FMF FILL UNIG ILIT	(A) (W) FACION TERF ENNUN	.328 1.349 .//0 40.3 2.3	.332 1.364 ./93 45.8 2.3	.289 1.155 .764 43.8 2.7	.248 0.999 .765 42.3 3.1	202 0.772 .715 41.5 3.3	226 1 206 738 41 3 3 9		.310 1.223 ./03 41.3 2.1	.200 0.854 .860 41.9 2.9	.164 0.707 .861 42.2 3.3	.128 0.551 .863 40.1 3.7		CTED FOR TEMPERATURE AND INSOLATION	DILAL LTY	TWD DWD FILL OFIC TEMP	IFIC FILE LILLE UNIVER LEN	(A) (W) FACTOR TEMP EKKUK	.292 1.438 ./08 4/.0 1.9	243 1.187 .741 49.9 1.9	180 0 964 763 44 9 3.7		.171 0.050 .029 J.1 1.1	.077 0.394 .658 39.5 1.5	.283 1.423 .700 44.6 1.7	213 1 024 536 43 1 3 1		3.7 3.67 00/. 613.1 663.	2.2 43.4 CZ1. ZC0.1 QIZ.	.186 0.897 .734 43.9 3.2		CTED FOR TEMPERATURE AND INSULATION	QUALITY	IMP PMP FILL ORIG TEMP	(A) (W) FACTOR TEMP ERROR	300 0 931 628 41.0 1.5	313 0 030 612 38 7 2 1	242 0 70F FID 20 1 2 7	7.7 T.C. 010. CO./.0 242.	.198 0.559 .565 41.6 2.8	.149 0.025 .029 41.2 2.0	311 0.910 .625 44.5 2.2	105 0 574 476 43 8 3 0	7 6 7 67 777 100 0 701 7 6 7 6 7 6 7 7 7 7 7 7 7 7 7 7 7 7 7	1.0 0.3 4.34 444. /00.0 0.1.	.UDD U.182 .5/1 41./ 2.1	.Uos U.II4 .3/9 3/.1 4.5
CORRECTED FOR TEMPERATURE AND INSOLATION	LKKUK UUALLIT VMB TMD DMD FILL DRIG TEMP	(V) (A) (W) FACTOR TEMP ERROR	1.396 .342 1.505 .656 45.6 1.8	1.349 .335 1.436 .041 40.0 5.5 1 1 24 697 42.8 3.1	1 244 227 0.973 .655 45.6 2.8	1 300 196 0.844 .646 43.9 1.8	4,427 .343 1.518 .660 45.4 3.0	4 472 .321 1.435 .710 45.6 3.6	4.684 .231 1.083 .760 43.8 3.5	4.658.201 0.936 .765 40.5 4.2	4.535.137 0.620 .763 41.3 5./	CODDECTED END TEMPEDATION AND INSULATION	LUKKEUTEU FUN IERTENATUNE AND THOOLANTAN	UND THE DAD FILL DRIG TEMP	VMP IMP PMP FILL UNIG ILI'	(V) (A) (W) FALIUM TERF ENNUM	4.119 .328 1.349 .//0 40.2 2.3	4.109.332 1.364 ./93 49.8	3.994 .289 1.155 .764 43.8 2./	4.021.248 0.999 .765 42.3 3.1	3 818 202 0.772 .715 41.5 3.3	2 007 275 1 205 738 41 3 3 9		5.940 .310 1.223 ./03 41.3 2.1	4.259.200 0.854 .860 41.9 2.9	4.315.164 0.707 .861 42.2 3.3	4.289.128 0.551 .863 40.1 3.7		A CORRECTED FOR TEMPERATURE AND INSOLATION	TIPPOR OUDI ITY	VMD TMD DMD FILL ORIC TEMP	VIT LIT THE LICE ONLY INTO THE	(V) (A) (W) FACTOR TEMP EKKUK	4.918.292 1.438 ./08 4/.0 1.9	4 893 243 1.187 .741 49.9 1.9	5 113 180 0 964 763 44 9 3.7		1.1 0.04 660. 000.0 171. C17.C	5.102.077 0.394 .658 39.5 1.5	5.034 .283 1.423 .700 44.6 1.7	4 700 213 1 024 536 43 1 3.1		4.020 .233 1.213 .700 43.5 7.5	4.8/6.216 1.052 ./25 43.4 3.2	4.830.186 0.897 .734 43.9 3.2		3 CORRECTED FOR TEMPERATURE AND INSULATION	MIRROR QUALITY	VMP IMP PMP FILL ORIG TEMP	(V) (A) (W) FACTOR TEMP ERROR	3 012 300 0 931 628 41 0 1.5	3 000 313 0 030 612 38 7 2 1	0.000 010 0.000 011 001 01 0 0	7.3 T.EC NID. CN/.N CH7. 060.7	2.828 .198 0.559 .565 41.6 Z.8	0.170 .149 0.025 .029 41.2 2.0	2 925 311 0.910 .625 44.5 2.2	2 0 A 0 1 0 5 7 4 4 7 6 4 3 8 3 0	7 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0	2.300.100 U.3U/ 4444 44.30 2.2 4.34 110 0.301 0.20	Z.//4 .U06 U.18Z .3/1 41./ Z.1	1.8U5.Ub5 U.114 .5/9 3/.1 4.5
NG BA CORRECTED FOR TEMPERATURE AND INSOLATION	VIC MIKKUK UUALITT SC VAND TAND DAND FILL ORTG TEMP	(A) (V) (A) (W) FACTOR TEMP ERROR	392 4.396 .342 1.505 .656 45.6 1.8	391 4.349 .355 1.456 .041 40.0 5.5 260 4 418 257 1 134 .697 42.8 3.1	750 4 794 227 0.973 .655 45.6 2.8	228 4 300 196 0.844 .646 43.9 1.8	392 4.427 .343 1.518 .660 45.4 3.0	347 4 472 .321 1.435 .710 45.6 3.6	246 4.684 .231 1.083 .760 43.8 3.5	210 4.658 .201 0.936 .765 40.5 4.2	144 4.535 .137 0.620 .763 41.3 5./	VC 60 CODDECTED EDD TEMDEDATUDE AND INSOLATION	NG OD CURRECTEU FUN TERFENATURE AND TROCENTAN	TELE THANNA VALLET	15C VMP IMP TMP FILL UNIG ILI'	(A) (V) (A) (W) FALIUN IENT ENNUN	35/ 4.119 .328 1.349 .//0 40.5 2.0	353 4.109 .332 1.364 ./93 45.8 2.3	310 3.994 .289 1.155 .764 43.8 2./	267 4.021 .248 0.999 .765 42.3 3.1	221 3 818 202 0.772 .715 41.5 3.3	2EE 2 007 27E 1 20E 738 41 3 9		326 3.940 .310 1.223 .703 41.3 2.1	204 4.259 .200 0.854 .850 41.9 2.9	170 4.315 .164 0.707 .861 42.2 3.3	132 4.289 .128 0.551 .863 40.1 3.7		NG 9A CORRECTED FOR TEMPERATURE AND INSOLATION	NUTC MIDBOR OUDI ITY	TCC VMD IMD DMD FILL DRIG TEMP	LOU WILL IFIE FIE LIEL VILLE LIE	(A) (V) (A) (W) FACTOR TEMP EKKUK	348 4.918 .292 1.438 ./08 4/.0 1.9	277 4 893 243 1.187 .741 49.9 1.9	217 5 113 180 0 964 763 44 9 3.7		154 5.213 121 U.050 U22 TO	104 5.102 .077 0.394 .658 39.5 1.5	346 5.034 .283 1.423 .700 44.6 1.7	324 4 700 213 1 024 535 43 1 3 1		2.2 2.2 2.2 2.2 2.2 2.2 2.2 2.2 2.2 2.2	.248 4.8/6 .210 1.052 ./2 43.4 3.2	210 4.830 .186 0.897 .734 43.9 3.2		ING 9B CORRECTED FOR TEMPERATURE AND INSULATION	DNIC MIRROR QUALITY	ISC VMP IMP PMP FILL ORIG TEMP	(A) (V) (A) (W) FACTOR TEMP ERROR	376 3 012 309 0 931 628 41 0 1.5	207 2 000 212 0 020 612 28 7 2 1		/.7 T.EC ATA CA/.0 C+7. 060.7 C67.	.258 2.828 .198 0.559 .565 41.6 2.8	.230 0.170 .149 0.025 .029 41.2 2.0	374 2 925 311 0.910 .625 44.5 2.2	214 2 040 105 0 574 476 43 8 3 0		.19U 2.9U0 .1UD U.3U/ .4444 42.4 2.0	.142 Z.//4 .Ubb U.182 .3/1 41./ Z.1	.UYI I.BUD.Ub5 U.II4 .3/9 3/.I 4.5
OR STRING BA CORRECTED FOR TEMPERATURE AND INSOLATION	I NOT CONIC MIKKUK YUALITT VAC TEC NAME TAD DAVD FILL ORTG TEMP	(V) (A) (V) (A) (W) FACTOR TEMP ERROR	5.861 .392 4.396 .342 1.505 .656 45.6 1.8	5.816.391 4.349.335 1.430 .041 40.0 5.5 5 812 280 4 418 257 1 134 697 42.8 3.1	5.720 250 4.7410 227 0.973 .655 45.6 2.8	5 7 2 8 2 2 8 2 1 1 1 2 6 0 844 646 43.9 1.8	5 868 392 4.427 .343 1.518 .660 45.4 3.0	5 832 347 4 472 .321 1.435 .710 45.6 3.6	5.803 .246 4.684 .231 1.083 .760 43.8 3.5	5,817 .210 4.658 .201 0.936 .765 40.5 4.2	5.644 .144 4.535 .137 0.620 .763 41.3 5./	EAD ETDING OD CADDECTED EAD TEMPEDATHURE AND INSOLATION	FUK SIKING OD CURRECTEU FUN TERFENATURE AND INSCENTION T NAT FONIE MIDDAD ANDIN NICHTY	I NUT CUTTE THANNAN QUALITY VAC TEE VAND TAND DAND FILL ORLE TEMP	VUC ISC VMP IMP PMP FILL UNIG ILI'I	(V) (A) (V) (A) (W) FACIUM TEMP	4.868 .35/ 4.119 .328 1.349 .//0 40.5 2.3	4.880.353 4.109 .332 1.364 ./93 45.8 2.3	4.878 .310 3.994 .289 1.155 .764 43.8 2./	4.892.267 4.021.248 0.999 .765 42.3 3.1	4 885 221 3 818 202 0.772 .715 41.5 3.3	A DAE DEE 2 007 205 1 206 738 41 3 3 9		4.919.32b 5.940.310 1.223 ./03 4.19 2.1	4.862.204 4.259.200 0.854 .860 41.9 2.9	4.832.170 4.315.164 0.707 .861 42.2 3.3	4.821.132 4.289.128 0.551 .863 40.1 3.7		FOR STRING 9A CORRECTED FOR TEMPERATURE AND INSOLATION	T NAT CONIC MIDDAD OUDI ITY	THE TECTION TO THE DWD FILL ORIG TEMP		(V) (A) (V) (A) (W) FACIOK LEMP EKKOK	5.831 .348 4.918 .292 1.438 ./08 4/.0 1.9	5 760 277 4 893 243 1.187 .741 49.9 1.9	E 820 217 E 112 180 D 964 763 44 9 3.7			5.783 104 5.102 077 0.394 .658 39.5 1.5	5_884 .346 5.034 .283 1.423 .700 44.6 1.7	E 807 324 4 700 213 1 024 536 43 1 3 1		5.80U .295 4.62U .203 1.219 .700 3.5 3.5 2.5 2.5 2.5 2.5 2.5 2.5 2.5 2.5 2.5 2	5.843 .248 4.8/6 .21b 1.052 .125 43.4 3.2	5.811.210 4.830.186 0.897 .734 43.9 3.2		FOR STRING 9B CORRECTED FOR TEMPERATURE AND INSULATION	IT NOT CONIC MIRROR QUALITY	T VOC ISC VMP IMP PMP FILL ORIG TEMP	V (V) (A) (V) (A) (W) FACTOR TEMP ERROR	2 04 27 2 01 2 20 0 931 628 41 0 1.5	2 0 0 0 2 0 0 0 2 1 2 0 0 2 0 6 1 2 2 8 7 2 1	2 210 200 2000 2012 2220 2012 2012 2012	7:3 TIGE 010: CO/O EFZ: 068:7 C67: 216:5	3.832 .258 2.828 .198 0.559 .565 41.6 2.8	3.755.230 0.170.149 0.025 .029 41.2 2.0	3 802 374 2 925 311 0.910 .625 44.5 2.2	2 222 214 2 242 105 0 574 476 42 8 3 0	0.00 0.01 10.0 0.00 0.00 0.00 0.00 0.00	5.643 .19U 2.9Ub .1Ub U.SU/ .444 42.4 2.0	3.45/ .142 2.//4 .U6b U.182 .3/1 41./ 2.1	3.284 .091 1.805 .065 0.114 .3/9 3/.1 4.3

FIGURE A7 (CONTINUED)

A14

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NORM PMP 1.000 1.250 1.250 1.250 1.250 0.81 0.81 0.231 0.231 0.231 0.231 0.231 NORM PMP 1.00 1.00 0.90 0.75 0.97 0.97 c.74 UDING 9 [INCLUD] NORM IMPR NORM IMP 0.97 0.986 0.81 0.97 0.97 0.97 0.93 0.93 0.93 0.93 INCL 000000-000 0-00000000 00 TTIONS 77) PMP NORM 15C 1.37 1.37 1.35 1.35 1.29 1.20 1.20 0.13 0.25 0.14 P WITH **TIONS** NORM ISC 0.99 0.99 0.99 0.75 0.98 0.98 0.98 0.92 0.92 0.92 0.92 PMP 0-0000000 M 000000-000 (%) 14.87 13.35 13.35 13.35 13.35 13.35 14.82 14.17 14.17 14.04 10.81 EFFCY źg IMP, IMP, **P** PMP (W) 1.888 2.371 2.371 2.460 2.456 1.864 1.864 1.864 1.864 1.864 1.516 0.435 0.227 150 1.576 PMP (W) 2.100 2.371 2.371 2.280 1.980 1.980 1.980 0.428 0.208 0.208 AING 2B CONNELLE R QUALITY (REFLECTA TO 0 DEGREES FOR I' ISC VMP IMP ລະ ES FOR IMP (A) (A) .338 .444 .468 .464 .336 .271 .336 .077 (MUM OF 5 2A CORRECTET ALITY (REFLE DEGREES FOF DEGREES FOF VWP IMP (V) (A) 7 5.58 (A) 18 5.23 (A) 19 5.65 (A) 10 5.55 (A) 1 F F OR M C F OR A 55 A TO 0 DEGRET ISC VMP (A) (V) .377 5.58 .478 5.34 .518 5.35 .511 5.25 .511 5.25 .3374 5.55 .3374 5.55 .3374 5.55 .3376 5.60 .150 5.73 .092 5.61 .170 THE MAXII (A) (A) 419 466 478 466 409 416 416 416 047 047 FOR STRIM MIRROR (MI 66.18 66.18 66.18 66.18 66.13 75.50 66.09 75.500 DATA NORM PMP 99.00 988.00 12.00 988.00 06 12.00 06 06 06 NORM PMP 1.00 1.00 0.94 0.95 0.73 0.73 0.73 0.68 0.68 0.68 0.38 0.38 g INCLUDING **INCLUD** 61 NORM IMP 1.00 1.00 1.00 0.88 0.88 0.88 0.87 0.87 0.11 0.12 0.12 0.12 0-00000000 0-00000000 LL CONDITIONS SET TO 7) MP, AND PMP, AND PMP, ISC (%) Η IONS .7) PMP ISC ISC 1.00 0.97 0.82 0.82 0.82 0.94 0.94 0.94 0.94 0.91 0.71 0.71 43 Ε PMP L CONDI ET TO IP, AND EFFCY 08 P EFFCY (%) 13.14 13.23 13.23 13.20 8.56 8.56 11.72 5.06 5.06 5.06 0.78 EFFCY (%) 13.47 13.47 (%) (%) 13.47 13.50 112.73 112.73 112.73 112.62 9.84 13.48 113.48 113.48 113.48 113.48 112.81 11.07 9.17 9.17 5.19 SET C IN SET PHP (W) 2.175 2.176 2.176 1.408 1.458 1.958 1.928 11.9288 11.928 11.928 11.9288 11.9288 11.9288 11.9288 11.9288 1. FOR ALL ANCE SET PMP EF PMP EF (W) (ALL PMP (W) 2.162 2.177 2.196 2.008 1.408 1.408 1.928 0.832 0.261 0.129 PMP 2.216 2.221 2.221 2.2316 1.619 2.218 2.218 2.218 2.218 2.218 1.509 0.854 TANCE ISC, I CORRECTED I ALITY (REFLECT ALITY (REFLECT DEGRES FOR IS VMP (V) (A) (V) (A ALITY (REFL DEGREES FO VMP IMP C MIRROR QUA VUZED TO O VIZED TO VIZED TO O VIZED TO V 440 394 273 460 460 460 266 5 151 111 1110 114 200 114 DATA FOR STRING I CONIC MIRROR QUAL NORMALIZED TO 0 ANGLE VOC 0 0.0 6.05 465 1.0 6.05 465 1.0 6.09 446 2.5 6.06 394 2.5 6.06 394 2.5 6.06 394 2.5 5.97 151 3.0 6.10 208 2.5 5.97 151 3.0 6.00 446 3.394 3.0 6.00 446 3.394 3.0 6.00 440 2.5 6.06 394 3.0 6.00 460 2.5 6.06 394 3.0 6.00 460 2.5 6.06 394 3.0 6.00 460 2.5 6.06 394 3.0 6.00 460 2.5 5.97 119 3.0 6.00 460 2.5 5.97 119 3.0 6.00 460 2.5 5.97 119 3.0 6.00 460 2.5 5.97 119 3.0 6.00 460 3.00 6.00 400 3.00 400 3.00 6.00 400 3.00 TH RESPECT DATA FOR S1 DATA FOR S1 NORMIC MIRRY NORMIC MIRRY (PEG) (V) (PEG) (V) (PEG) (V) (PEG) (V) 2.0 6.05 3.0 6.05 3.0 6.05 0.14 -1.0 6.21 -1.0 6.14 MITH RESPE ANGLE VOC (PEG) (V) (PEG) (V) 0.6 6.05 2.5 6.05 2.5 6.05 2.5 6.05 2.5 6.05 2.5 6.05 2.0 6.06 2.14 1.0 6.21 2.5 6.05 2.5 ORIGINAL PAGE IS OF POOR QUALITY NORM PMP PMP PMP PMP 11.00 11.05 11.02 11.02 11.02 0.98 0.92 0.92 0.62 0.62 0.62 S g B L. គ្ម NORM IMP IMP 1.00 1.00 1.00 1.00 1.00 1.00 1.01 1.01 1.01 1.01 1.01 1.01 1.01 1.01 1.01 1.01 1.01 1.01 1.01 1.00 1.0 NORM IMP 1.00 1.00 1.00 0.98 0.89 0.89 0.89 0.89 0.59 0.59 INCL INC 000-000000 000000-0000 PPP 7 NORM 15C 0.99 0.97 0.97 0.95 0.75 0.59 0.59 NORM ISC 15C 0.97 0.92 0.74 0.92 0.74 0.92 0.74 0.95 0.95 0.68 0.68 ALL CONDI SET TO IMP. AND EFFCY (%) 9 13.56 9 13.56 9 13.55 1 14.67 (%) 5 14.48 (%) 5 14.48 (%) 5 13.83 5 13.83 5 13.35 6 13.55 1 14.53 8 11.58 8 11.58 8 11.58 8 11.58 8 11.5 L CONDI FFT TO FF TO FF, AND FF, AND FF, AND FF, AND FF, AND FF, CONDI FF, C (%) 13.55 14.23 14.48 14.48 13.59 13.59 13.59 13.59 13.59 13.59 13.59 13.59 13.59 13.59 13.50 13.58 13.56 13.58 13.56 15.56 15 3504008239 EFFCY Ret. FOR ALL TANCE SE PRP, FF, PRP, PMP (W) 2.223 2.203 2.010 1.529 2.152 2.152 2.057 1.538 CORRECTED ITY (REFLECT TY (REFLECT MP IMP IMP V) (A) (A) V) (A) V
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0.70 Ч REFLECTANCE RROR E CONIC FOR CORRECTED PANEL 56 × 15 FROM DATA A8

FIGURE

A15

NORM PMP 11.00 11.00 0.95 0.95 0.95 0.35 0.35 0.35 0.35 0.35 NORM PMP 0.95 0.95 0.94 0.94 0.95 0.68 0.68 0.34 0.34 NORM PMP 0.98 0.98 0.97 0.97 0.97 0.97 0.33 0.17 NORM PMP PMP PMP 1.00 1.00 1.01 1.01 1.01 1.00 0.79 0.32 0.17 0.17 0.07 0.07 0.07 RESI LUDING INCLUDING w NORM IMP 0.98 0.92 0.92 0.98 0.98 0.98 0.34 0.34 NORM IMP 1.00 1.02 1.03 0.93 0.97 0.97 0.34 * ANGL NORM 1MP 0.97 1.00 1.00 0.93 0.95 0.75 0.30 0.16 0.16 NORM IMP I.00 I.10 I.10 I.10 I.00 I.00 0.75 0.75 0.29 0.16 0.07 I.ANGL INCL 0-00000000 D PMP NO 200 10 PMP NO 200 11 100 11000 1100 11000 1100 11000 11000 11000 11000 110 **T10NS** NORM 15C 15C 1.00 1.00 0.97 0.99 0.99 0.97 0.87 0.87 0.87 0.36 NORM 15C 0.94 0.99 0.99 0.98 0.97 0.31 0.17 0.31 ALL CONDI E SET TO IMP VND FFFCY C (%) C EFFCY (%) 13.36 13.47 13.47 12.68 11.28 11.28 11.28 11.28 11.45 9.14 9.14 EFFCY (%) 12.56 12.76 12.56 11.79 11.79 11.79 12.44 10.22 4.21 2.18 2.18 0.88 (W) 2 2:064 2 2:165 2 2:265 2 ISC, IMP, DATA FOR STRING 3C CORRECTED FOR ALL CONIC MIRROR QUALITY (REFLECTANCE SET NORMALIZED TO DEGREES FOR ISC, IMP ANGLE VC ISC VMP IMP FI (DEG) (V) (A) (V) (M) (W) (F) 0.0 6.05 410 5.17 388 2.004 12 1.0 6.08 459 5.03 443 2.147 11 3.0 6.04 491 5.07 411 2.085 11 3.0 6.04 491 5.07 411 2.085 11 3.0 6.04 491 5.07 411 2.085 11 3.0 6.04 491 5.07 411 2.085 11 3.0 6.04 491 5.07 411 2.085 11 3.0 6.04 491 5.07 411 2.085 11 3.0 6.08 459 5.03 443 2.229 11 2.5 5.81 072 5.47 063 0.344 3.2.6 1.07 14 MAXIMU OF 15.147 11 0.05 6.07 496 5.03 0.147 NORMALIZED TO THE MAXIMU OF 15.147 11 0.02 6.08 445 5.03 0.147 NORMALIZED TO THE MAXIMU OF 15.147 11 0.00 6.08 445 5.03 0.147 0.01 6.08 445 5.03 411 2.067 1 0.05 6.07 448 5.04 311 2.067 1 0.06 0.08 445 5.03 411 2.067 1 0.06 0.08 445 5.03 411 2.067 1 0.06 0.04 416 5.16 397 2.067 1 0.05 6.07 448 5.04 311 2.067 1 0.05 6.04 416 5.16 397 2.067 1 0.05 6.07 448 5.04 311 2.067 1 0.05 6.07 448 5.04 311 2.067 1 0.05 6.07 441 5.54 130 2.067 1 0.05 6.08 455 5.03 411 2.067 1 0.05 6.07 411 5.54 130 2.067 1 0.05 6.07 411 5.54 125 0 0.05 0.035 4.035 1.035 5.47 0.055 0.693 1 0.05 5.01 0.05 5.01 0.145 5) FOR AL TANCE S PMP (W) (W) 2.115 2.115 2.115 2.115 2.115 2.128 2.128 2.128 1.856 1.856 1.856 1.856 1.856 1.856 0.764 PMP (W) 2.115 2.198 2.216 2.086 2.086 2.122 2.122 2.122 2.122 2.122 2.764 0.764 PMP (W) 2.067 2.069 2.067 1.939 1.890 2.046 2.046 0.359 0.359 0.359 (1106 3D CORRECTED F (1106 3D CORRECTED F (1107 (RFELECTA) (1107 (RFELECTA)) (1107 (RFELECTA)) (1107 (RFELECTA)) (R 5 FOR RESET NORM PMP 0.91 0.91 0.93 0.23 0.23 0.23 0.98 0.98 0.98 0.62 0.62 0.62 0.62 0.62 NORM PMP 0.99 0.97 0.97 0.97 0.49 0.49 0.48 0.48 0.48 0.33 0.33 0.33 NORM PMP PMP 1.00 1.04 0.77 0.57 0.57 0.57 0.57 0.57 0.57 0.32 0.32 0.32 0.32 0.32

INCLUDING INCLUDING ш ш NORM IMP 0.99 0.97 0.63 0.63 0.63 0.87 0.87 0.87 0.30 0.30 0.30 0.30 NORM IMP 0.98 0.54 0.55 0.36 0.21 0.97 0.97 0.95 0.85 0.58 Ξ Ξ Dirtions Dirtio LL CONDITIONS I SET TO .7) MP, AND PMP, AND PMP, MP, AND PMP, ISC (%) ISC (%) ISC (%) ISC (%) ISC (%) ISC 10.06 1.00 10.15 0.97 1 0.15 0.97 1 0.13 0.93 1 0.137 0.133 4 4.58 0.44 1 3.72 0.132 1 3.72 0.132 1 3.72 0.132 1 3.77 0.18 1 0.018 1 NORM ISC 1.5C 0.97 0.87 0.64 0.48 0.48 0.47 0.32 0.32 0.32 000000000000 EFFCY (%) 13.36 8.57 8.57 8.57 8.57 8.57 8.57 3.42 3.42 14.67 14.81 14.81 14.81 14.38 12.90 9.11 9.11 EFFCY (%) 10.37 9.41 9.41 7.00 5.20 9.39 9.39 9.39 1.74 (%) 10.06 10.15 7.75 5.74 10.19 8.70 8.70 8.70 8.70 1.77 1.77 1.77 P,0R P ED FOR AL ECTANCE S PMP | (W) ALL C SET C RECIED FOR ALL (REFLECTANCE SET S FOR ISC, IMP PF (A) (W) ((356) 1.655 10 .371 1.721 1.721 .358 1.669 10 .358 1.676 10 .356 10 .556 10 .556 10 .556 10 .556 10 .556 10 .556 10 .556 10 .556 10 .557 10 .556 10 .55 PMP (W) 1.706 1.669 1.548 1.151 0.855 1.728 1.728 1.544 0.831 0.566 PMP 2.406 2.199 1.410 0.563 0.563 2.414 2.437 2.437 1.499 LING 3A CORRECTE R QUALITY (REFLE FO 0 DEGREES FOR ISC VMP IMP THE MA O ISC VMP (V) (V) 4.65 4.65 4.65 5.03 5.03 5.10 5.07 5.07 R STRING IRROR QU TED TO 0 150 0 150 0 150 0 150 0 177 5 1336 4 177 5 177 5 177 5 177 5 177 5 177 5 177 5 177 5 10 THE ORIGINAL PAGE IS

OF POOR QUALITY

(CONTINUED)

A8

FIGURE

												E															
DING	NORM	1.00	0.96	0.87	0.77	0.55	1.00	1.01	0.94	0.84	0.66	E RESI		NORM	dMd	0.99	0.95	0.86	0.76	0.54	0.99	1.00	0.93	0.84	0.65	DING	
INCLU	NORM IMP	1.00	0.95	0.84	0.72	0.50	1.00	1.01	0.92	0.81	0.62	H ANGL		NORM	dWI	1.00	0.95	0.84	0.72	0.50	0.97	0.98	0.90	0.79	0.61	INCLL	
TIONS (1.	NORM	1.00	0.95	0.83	0.75	0.55	1.00	1.01	0.92	0.83	0.64	IT WITH		NORM	ISC	1.00	0.95	0.83	0.75	0.55	0.98	0.99	0.90	0.82	0.63	ITIONS	(7. DMP
T TO AND	FFCY (%)	3.94	3.35	2.14	0.79	7.65	4.01	4.11	3.17	1.83	9.19	OR PV		FFCY	(%)	3.94	3.35	2.14	0.79	7.65	4.01	4.11	3.17	1.83	9.19	COND	AND AND
OR ALL NCE SE	E (M)	294 1	.196 1	1 799.	.775 1	.259	.305 1	.321 1	.167 1	.947 1	.512	SC, IMP		PMP	(M)	294 1	. 196 1	1 766.	.775 1	.259	.305]	.321]	. 167]	.947	512	OR ALI	INCE SE
CTED F	4 G	459 2	438 2	388 1	333]	229 1	447 2	452 2	412 2	361 1	279 1	M OF I		MP	A)	459 2	438 2	388 1	333 1	229 1	447 2	452 2	412 2	361 1	279 I	CTED F	FLECTA
CORRE(Y (REI RFFS	4 C	66	6		 Е	20		13	25	39	43	IAX I MUI		4P	0	66	. 10	. 15 .	. 33	. 50	. 16	. 13	. 25 .	. 39	.43	CORRE	TY (RE
46 2C DUALIT	¦≥2	96	72 5.	12 5.	73 5.	72 5.	36 5.	<u> </u>	17 5.	5.5	[3 5.	THE	FO ISC	\$	с -	96 4.	72 5.	12 5.	73 5.	72 5.	86 5.	90 5.	47 5.	05 5.	13 5	NG 2D	QUAL I
STRI) RROR (E S S	2	2 .4]	3.4	5.33	0.2	8.45	8.4.	6 .4	5 .4	2.3]	ED 10	PECT '	ISI	(A)	2.4	2.4	4.	5	0	8.4	8.4	6.4	5	2 .3	STRI	RROR FD TO
A FOR	E VOC	5.9	5.9	5.9	5.9	6.0	0.9	0.9 0	0.9 (6.0	6.0	MALIZ	TH RES	E VOC	3	5.9	5.9	5.9	5.9	0.9	0.9	0.9	0.9	5.0	6.0	LA FOR	VIC MI 2MAI 17
DAT CON	ANGL	0.0	1.0	2.0	2.5	3.0	0.0	-1.0	-2.0	-2.5	-3.0	NOF	LIM	ANGL	(DEG	0.0	1.0	2.0	2.5	э.с	0.0	-	-2.0	-2-	-, ,	ADA	ିଟ୍ର ହୁ

NORM PMP 1.00 0.98 0.83 0.72 0.83 0.62 0.83 0.62 0.62 IMP 1.00 0.97 0.67 0.67 0.67 0.67 0.83 0.83 0.83 0.83 NORM NORM IMP IMP IMP 11.00 0.97 0.97 0.97 0.47 0.47 0.47 0.47 0.47 0.47 0.47 0.83 0.87 0.83 0.59 0.59 0.59 NORM 11.00 NORM NORM 15C 15C 15C 0.98 0.98 0.54 0.54 0.54 0.54 0.86 0.86 0.86 0.82 0.63 EFF.CV EFF.CV (%) 13.65 11.65 11.65 11.65 11.65 11.65 11.74 11.74 8.74 8.74 8.74 8.74 8.74 PMP (W) 2.298 2.298 1.915 1.915 1.915 1.915 2.2314 2.314 1.438 1.931 1.438 TSC VEWPE 1SC VEWPE 475 5.14 466 5.19 466 5.19 466 5.19 465 5.19 465 5.19 465 5.19 465 5.14 476 ANGLE MARALLEL IV NGLE MARALLEL IV 0:0 6:08 447 2:0 6:07 466 3:0 6:07 466 3:0 6:01 25 3:0 6:01 25 3:0 6:01 25 3:0 6:01 25 0:1 25 3:0 6:02 46 1:1 447 0:1 1:1 25 0:0 6:08 41 1:0 6:01 25 3:0 6:03 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:04 35 3:0 6:05 35 3:05 3:05 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 3:05 35 3:05 35 3:05 3:05 35 3:05

2 QUALITY ORIGINAL PAGE

OF POOR

DATA FOR STRING 5A CORRECTED FOR ALL C CONIC MIRROR QUALITY (REFLECTANCE SET NORMALIZED TO 0 DEGREFS FOR ISC. IMP. NORM PMP 1.100 1.10 1.00 1.00 0.95 0.53 0.53 0.53 0.53 NORM PMP 0.97 0.94 0.94 0.94 0.54 0.54 0.54 0.54

 DATA FOR STRING 4C CORRECTED FOR ALL CONDITIONS INCLUDING CONIC MIRROR QUALITY (REFLECTANCE SET TO .7)

 NORMALIZED TO 0 DEGREES FOR ISC, IMP AND PMP (DEG) (V)
 (A)
 (W)
 (A)
 MOR (M)
 MOR NOR NOR DO
 NOR INCLUDING UDING NORM INCL

IMP I.00 1.00 1.72 1.85 1.72 1.00 1.72 1.45 1.45 1.45 1.45 1.45 NORM IMP 1.00 1.00 0.75 0.75 0.77 0.77 0.69 0.69 0.69 0.69 Ξ NORM ISC 0.99 0.86 0.74 0.74 0.95 0.93 0.68 0.68 0.68 DATA FOR STRING 4D CORRECTED FOR ALL CONDITIONALIZED TO DEGREES FOR ISC, IMP, AND PMF CONIC MIRROR QUALITY (REFLECTANCE SET TO 7 ANGLE VOC ISC VMP IMP FFCY NG (DEG) (V) (A) (W) (K) (K) (X) 1.0 6.24 473 5.40 451 2.434 14.80 1.4 2.0 6.17 454 5.37 449 2.434 14.80 1.4 2.0 6.17 454 5.37 1206 0.9 2.5 6.12 383 5.56 357 12080 10.98 0.1 0.0 6.17 454 5.37 442 2.231 14.10 1.4 0.0 6.17 454 5.37 442 2.231 14.10 1.4 0.0 6.17 454 5.37 442 2.232 10.90 1.1 0.0 6.17 454 5.37 10.44 0.1 2.2 6.12 218 5.63 311 1.777 10.44 0.1 2.2 6.12 218 5.63 1.345 1.902 11.56 0.1 2.5 6.12 2.18 5.51 345 1.902 11.56 0.1 2.6 6.12 2.18 5.51 345 1.902 11.56 0.1 0.0 6.17 441 5.38 4.18 2.252 13.69 0.1 0.0 1.1 4.0 5.51 1.00 6.74 0.1 0.1 1.0 6.17 441 5.38 4.18 2.252 13.69 0.1 1.0 6.17 443 5.37 1.995 12.00 0.1 1.0 6.17 449 5.33 4.18 2.041 14.80 1.1 1.0 6.17 454 5.37 1.985 12.06 0.1 1.5 6.17 454 5.37 1.985 12.06 0.1 1.5 6.17 454 5.37 1.985 12.06 0.1 1.5 6.17 454 5.37 1.985 12.06 0.1 1.5 6.17 454 5.37 1.985 12.06 0.1 1.5 6.17 454 5.37 1.905 10.98 0.1 2.0 6.17 418 5.38 418 2.252 13.69 0.1 1.5 6.17 454 5.37 432 2.311 1.777 10.44 0.1 2.0 6.17 454 5.37 432 2.311 1.777 10.44 0.1 2.0 6.17 454 5.37 432 2.311 1.777 10.44 0.1 2.0 6.17 2.218 5.68 1.95 11.090 1.1.56 0.1 2.0 6.17 2.218 5.68 1.95 1.1090 1.1.56 0.1 2.0 6.17 2.318 5.68 1.95 1.1090 0.1.56 0.1 2.0 6.17 2.318 5.56 1.345 1.305 1.56 0.1 2.0 6.17 2.318 5.56 1.345 1.305 1.56 0.1 2.0 6.17 2.318 5.56 1.345 1.305 1.56 0.1 2.0 6.17 2.318 5.58 1.305 1.1090 0.1 2.0 6.17 2.318 5.58 1.305 1.1090 0.1 2.0 6.17 2.318 5.58 1.305 1.1090 0.74 0.0 2.0 6.17 2.318 5.58 1.305 1.1090 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.305 0.1 2.0 6.17 2.218 5.53 1.1077 0.44 0.1 2.0 6.17 2.218 5.53 1.1095 0.44 0.1 2.0 6.17 2.218 5.53 1.1095 0.1 2.0 6.17 2.218 5.53 1.1005 0.7 2.0 6.17 2.218 5.53 1.1005 0.74 0.1 2.10000000000 PMP

	CONIC	FOR S' C MIRR(ALIZED	TRING DR QUJ	5A COI ALITY DEGREI	RECTEC (REFLEC FS FOR	D FOR AL	SET TO MP. AND	17 INONS	INCLU	DING
	ANGLE	VOC	ISC	VMP	IMP	DWD	FFFCY	NORM	NORM	NORM
	(DEG)	Ξ	Ð	Ξ	E	3	(%)	ISC	dWI	PMP
	0.0	6.33	.467	5.23	.422	2.206	13.41	1.00	1.00	1.00
		6.29	.488	5.19	.450	2.337	14.20	1.04	1.07	1.06
	0.v	6.25	.452	5.22	.418	2.182	13.26	0.97	0.99	0.99
		67.0 4	176.	5. C	862.	2.104	12./9	0.90	0.94	6. 6
		62.0 94	467	0.4.0 01.0	205.	1.944	11.82	28.0	0.85 00	0.88 0.0
	-1.0	6.22	.362	5.19	334	1.734	10.54	0.78	0.80	8.1
	-2.0	6.13	.224	5.38	202	1.088	6.61	0.48	0.48	0.50
	-2.5	6.05	. 180	5.26	. 163	0.859	5.22	0.39	0.39	0.40
	-3.0	5.95	. 145	4.92	.126	0.620	3.77	0.31	0.30	0.29
	NORM	ALIZED	10 1	IE MAX	IMUM OF	: ISC, II	MP,OR PI	TIW AM	h angl	E RESET
	HLIM	RESPEC	CT 10	ISC						
	ANGLE	202	ISC	dWA	dWi	d Md	EFFCY	NORM	NORM	NORM
	(nee)	ΞĴ	e,	Ξ	(A)	(M)	(%)	ISC .	dWI ,	d Hd
		5.00	784.		435	G/2.2	13.83	00.1	8.7	8.1
		0.74 7	· / ·		159.	007.7	13.77	86.0	0. I	1.00
		0.73	714.	27.0	897.	2.023	62.21	18.0	68.0	0.89
		0.	100.		700.	205-1	11.00	P 9	28.0	12.0
		27.0	145.	0.43	675.	1./03	10.1	2/.0	0.74	2.0
			191.	0. IV	0.54.	2.230	57.22 57	1.00	9.98	0.98
		77.0	165.	0.19	005.	1.8/1	11.3/	18.0	28.0	287
	, u , c	1.10	147.	00.00	C77.	1.200	02.7	10.0	10.0	0.00
	0.6-	5.95	143	07.0	1/1.	0.612	9. c	52.0	82.0 82.0	72 0
						112.0		22.2		
	DATA	FOR SI	FRING	5B COI	RECTED	FOR AI	LL COND	ITIONS	INCLU	DING
	CONIC	C MIRRC	а Зо Зо Зо Зо Зо Зо Зо		REFLEC	TANCE	SET TO	(<u></u>		
		ייטע		DEGRE		154, 17	TLL AND	AMA		
		25		152	181	ŧ.	EFFLY	NUKM	NUKM I MD	NUKM
		6.00	431		404	(") (8)	12 65	20	2	
	1.0	6.04	440	5.15	410	1111	12.83	80	38	00.1
	2.0	5.99	404	5.16	388	2.003	12.17	0.94	0.95	0.96
	2.5	5.98	.380	5.15	.362	1.866	11.34	0.88	0.89	0.90
	3.0	5.97	.350	5.16	.334	1.719	10.45	0.81	0.82	0.83
	0.0	6.05	.429	5.15	.408	2.101	12.77	1.00	1.00	1.00
_	- - -	6.04	.413	5.14	.386	1.986	12.07	0.96	0.95	0.95
	0.v	6.01 6	.348	5.25	.326	1.712	10.41	0.81	0.80	0.8]
	 	5.0	205	67. G	982.	1.502	9.13	0.70	2.0	0.71
	NODMA	00.00	17 11	000 IF MAV	07T.	140.0	2.50 10 00 01	0.30	67.0	0.31
	N TH	DESDEC				121,17	λ, CK Σ	L M 4	H ANGL	E KESEI
	ANGLE		1SC	VMP	IMP	DMD	FFF/	MOON	MOON	MOON
	(DEG)	S	(A)	2	(A)	3	(%)	ISC	dWI	DMP
	-1.0	é. 00	.431	5.09	409	2.081	12.65	0.98	1.00	66.0
	0.0	6.04	.440	5.15	.410	2.111	12.83	1.00	1.08	1.00
	1.0	5.99	.404	5.16	.388	2.003	12.17	0.92	0.95	0.95
	1.5	5.98	.380	5.15	.362	1.866	11.34	0.86	0.88	0.88
	2.0	5.97	.350	5.16	.334	1.719	10.45	0.80	0.81	0.81
	-1.0	6.05	.429	5.15	.408	2.101	12.77	0.97	1.00	1.00
	0.2-	5.0	514.	5. I4	.386	1.986	12.07	0.94	0.94	0.94
		10.0	545.	0.70 2	320	1./12	10.41	6/.0	0.80	0.81
	- 4	10.0	200.	0.20 7	007.	200.1	ч. 1. 1.	0.04 20	00	0./1
	2.5	00.0	171.	00	.120	0.041	5.40	2.72	27.0	0.30

ED FOR ALL CONDITIONS INCLUDING ECTANCE SET TO .7)	IR ISC, IMP, AND PMP	PMP EFFCY NORM NORM NORM	2 2 010 12 22 1 00 1 00 1 00	7 1.972 11.99 0.97 0.99 0.98	1 1.850 11.24 0.84 0.90 0.92	8 1.403 8.53 0.62 0.65 0.70	15 1.083 0.58 0.48 0.50 0.54 0 1 004 12 12 1 00 1 00 1 00	19 1.904 11.57 0.94 0.97 0.95	6 1.813 11.02 0.86 0.92 0.91	9 1.591 9.67 0.74 0.80 0.80	3 1.102 6.70 0.49 0.55 0.55	UP ISC, IMP, UK PMP WI H ANGLE KESE	PMP EFFCY NORM NORM NORM	(W) (%) ISC IMP PMP	2 2.010 12.22 1.00 1.00 1.00	7 1.972 11.99 0.97 0.99 0.98	1 1.850 11.24 0.84 0.90 0.92	8 1.403 8.53 0.62 0.65 0.70	0 1.083 0.58 0.48 0.50 0.54	9 1.994 12.12 1.00 0.99 0.99	9 1.904 11.5/ 0.94 0.9/ 0.95 5 1 813 11 83 6 85 6 61 6 60	0 1.613 11.02 0.60 0.91 0.90 0 1 501 0 57 0 74 0 60 0 70	3 1.102 6.70 0.49 0.54 0.55	ED FOR ALL CONDITIONS INCLUDING	R ISC, IMP, AND PMP	PMP EFFCY NORM NORM NORM	(W) (%) ISC IMP PMP	8 1.90/ 11.59 1.00 1.00 1.00 8 1.825 11.00 1.00 2.00	5 1 840 11 24 0 24 0 20 0 27	9 1.859 11.30 0.91 0.98 0.97	1 1.759 10.69 0.84 0.90 0.92	8 1.909 11.61 1.00 1.00 1.00 5 2 040 12 40 2 22 1 22 1 22	5 1.675 10.18 0.74 0.79 0.88	7 1.431 8.70 0.63 0.66 0.75	9 1.069 6.50 0.47 0.49 0.56	UF ISC, IMP, OK PMP WITH ANGLE RESET	PMP EFFCY NORM NORM NORM	(M) (%) ISC IMP PMP	8 1.907 11.59 0.97 0.98 0.93		10 / 0 / 0 / 0 / 0 / 0 / 0 / 0 / 0 / 0 /	1 1 759 10 69 0 81 0 89 0 86	8 1.909 11.61 0.97 0.98 0.94	6 2.040 12.40 0.90 1.00 1.00		/ 1.431 8.70 0.01 0.03 0.70 9 1 060 6 50 0 46 0 48 0 52	
RING 4A C	TO O DEGR	ISC VMP	(A) (V)	.451 4.8	.392 4.9	.288 5.2	7.C 227.	438 4.7	401 4.8	.346 4.8	.230 4.9	T TO ISC	ISC VMP	(A) (V)	466 4.8	.451 4.8	.392 4.9	2.2 882.	2.6 222.		4.10 4.10 A01 A D	0.4 104.	.230 4.9	RING 4B COR	TO 0 DEGRI	ISC VMP	(A) (V)	2.4 0CF	479 4 80	416 4.9(.383 5.0	454 4.9	337 5.48	286 5.58	215 5.67	TO ISC	ISC VMP	(A) (V)	458 4.92	4/0 4 8: 170 4 01	416 4 91	383 5.02	454 4.92	425 5.15	33/ 5.40 206 6 50	215 5.67	
DATA FOR SI CONIC MIRRO	NORMAL I ZED	ANGLE VOC	(Utu) (V) 0.0 5.86	1.0 5.84	2.0 5.84	2.5 5.82	3.U 5./9	-1.0 5.78	-2.0 5.81	-2.5 5.77	-3.0 5.72	WUKMALIZEU WITH RFSDFF	ANGLE VOC	(DEG) (V)	0.0 5.86	1.0 5.84	2.0 5.84	2.5 5.82	5.0 5.0%	1.0 5.70	1.0 3./0	10.0 0.7	3.0 5.72	DATA FOR ST	NORMAL I ZED	NGLE VOC	DEG) (V)	ci.o U.U	2.0 6.01	2.5 6.02	3.0 5.99	0.0 6.08	2.0 6.10	2.5 6.11	3.0 6.11	WITH RESPECT	NGLE VOC	DEG) (V)	1.0 6.15	60.0 0 10 9 0 1	1.0 0.1	2.0 5.99	1.0 6.08 .	2.0 6.10	3.U 0.1U .	4.0 6.11	
							_	-	-															A1	7		-					,		'	•		4	-	'				'	1	• •	•	

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NORM PMP 11.00 11.00 0.73 0.63 11.00 0.63 0.65 0.65 0.65 0.65 0.65 FRESET NORM PMP 0.99 0.99 0.87 0.73 0.73 0.73 0.69 0.69 0.61 0.61 0.61 0.61 0.61 0.61 0.61 INCLUDING INCLUDING NORM IMP 1.00 1.00 0.71 0.71 1.00 1.00 0.61 1.03 0.91 0.65 1 ANGL NORM IMP 1.00 1.05 0.97 0.97 0.97 0.97 0.45 0.45 0.45 0.45 0.45 P.7) NORP ISC ISC 1.00 0.27 0.58 0.69 0.65 0.82 0.87 0.67 0.67 0.687 PMP WIT CONDITIONS NORM ISC 0.97 0.58 0.58 0.58 0.87 0.87 0.69 0.69 0.81 0.67 NORM ISC 0.95 0.95 0.98 0.98 0.64 0.56 0.43 TO AND P EFFCY *() EFFCY (%) 10.63 10.62 8.64 7.81 6.70 6.70 10.70 9.59 9.06 9.16 7.16 (%) 10.63 10.63 8.64 8.64 6.70 6.70 10.70 9.59 9.59 9.06 9.06 9.06 9.06 INP. 1.178 7 ISC, IMP, AL
 RING
 TA CORRECTED
 FOR ISC
 Indiant
 PMP (W) (W) 1.749 1.746 1.421 1.284 1.284 1.284 1.284 1.578 1.578 1.578 PMP (W) 1.749 1.749 1.749 1.284 1.284 1.760 1.760 1.760 1.780 1.781 1.491 1.178 FOR A TANCE ISC, I , CORRECTED FL A CORRECTED FL QUALITY (REFLECTAN O DEGREES FOP 4.69 4.69 4.80 4.84 4.75 4.75 4.71 4.71 4.71 1.50 1.50 1.50 1.50 4.69 4.69 4.80 4.75 4.75 4.71 4.71 4.71 IC MIRKOR 00 VALIZED TO 0 VOC ISC (V) (A) 5.64 -413 5.64 -413 5.64 -413 5.64 -413 5.64 -413 5.64 -413 5.64 -413 5.64 -411 5.63 -319 4 5.63 -319 4 5.63 -319 4 5.64 -71 5.336 4.77 7.336 4.77 7.336 4.77 7.336 4.77 7.0 THE MAY V WP 4.18 4.03 4.20 4.20 4.20 4.20 4.20 4.41 ۷MP Ξ 20 2 ÿ STRI SPECT ESPECT VOC (V) (V) 44.80 44.85 44.85 44.85 44.85 44.85 44.85 44.78 44.78 44.78 44.78 FOR AND MIT ON IC MIT NORMALIZ NORMALIZ ANGLE VC (DEG) / MIR 2.5 5.5 5. 2. ä DATA FOI CONIC M CONIC DATA NORM PMP 1.00 0.77 0.77 0.63 0.45 0.45 0.45 0.45 0.77 0.72 0.72 0.72 RESET NORM PMP 1.00 0.75 0.63 1.00 1.00 1.00 0.75 0.67 7.65ET NORM PMP 0.99 0.91 0.76 0.44 0.99 0.99 0.90 0.81 0.71 0.71 NORM PMP 0.98 0.74 0.74 0.62 0.79 0.79 0.79 0.79 0.79 0.67 UDING INCLUDING NORM IMP 1.00 0.88 0.75 0.40 0.40 0.99 0.99 0.40 0.98 0.75 0.63 NORM IMP 1.00 0.75 0.75 0.75 0.61 0.40 1.00 0.99 0.81 0.77 0.64 1 ANGL INCL -----D FOR ALL CONDITIONS IN CTANCE SET 0. 7) R ISC, IMP, AND PMP PMP EFFCY NORM (M) (%) ISC (0) 2.010 12.22 1.00 352 1.753 10.66 0.86 300 1.514 9.20 0.73 .243 1.257 7.64 0.73 .397 2.041 12.41 1.7 .397 2.041 12.41 0. .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.622 9.86 0 1.254 1.369 8.32 7 .305 1.522 9.86 0 .305 1.522 9.36 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 1.522 9.86 0 .305 1.522 9.86 0 .305 1.522 9.50 0 .305 1.522 9.50 0 .305 1.522 9.50 0 .305 1.522 9.50 0 .305 1.522 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.525 9.50 0 .305 1.555 9.50 0 .305 1.555 9.50 0 .305 D 0.7) D 0 0.7) 15C 1 15C 1 15C 1 1.00 1. 0.65 0 0.50 0 0.50 32 ~ .(L CONDITIONS). .c SET TO .7) .c, IMP, AND PMP .**) Ξ (%) 10.32 8.57 8.57 7.10 7.10 4.99 11.25 11.25 11.34 10.15 9.15 9.15 9.15 9.15 EFFCY (%) 12.22 10.66 9.20 5.00 5.00 5.00 12.41 10.46 9.86 9.86 8.32 PMP (W) (W) ...843 ...843 ...168 ...168 ...168 ...851 ...851 ...866 ...851 ...851 ...851 ...866 ...851 ...866 ...833 CORRECTED IMP (A) .401 .352 .352 .352 .352 .337 .337 .337 .337 .325 DEGRES T VMP EES T VMP EES 7 VMP EES 5.02 5.05 5.13 5.14 5.33 5.33 5.33 5.33 5.33 ISC 1SC VMP ING 6A COF QUALITY (Σ 5.03 벌 10 0 [ISC (A) (A) .427 .357 .357 .357 .354 .329 .329 .329 .329 .329 .329 2 2 (A) 367 367 367 367 358 482 482 367 482 367 359 482 329 329 280 L STR11 IRROR ESPECT RESPECT VOC 6 VOC (V) 55.73 55.73 55.73 55.73 55.73 55.73 55.73 55.73 (V) 55.73 55.73 55.73 55.79 55.79 55.79 55.79 Fog NORM PMP 1.00 1.01 1.01 0.96 0.96 0.72 0.60 0.43 0.43 NORM PMP PMP 0.92 0.77 0.66 0.66 0.66 0.78 0.97 0.97 0.78 0.78 0.78 0.78 UDING INCLUDING w NORM IMP 11.00 11.03 11.03 0.94 0.94 0.97 0.97 0.58 0.58 0.58 0.58 NORM IMP 0.99 0.96 0.73 0.74 0.74 0.74 0.74 0.74 0.74 NORM IMP 1.00 0.78 0.65 0.68 0.68 0.68 0.68 0.68 0.68 0.97 0.97 0.97 0.97 ANGI INCL P.7 NORP ISC ISC P.0 0.92 0.92 0.92 0.95 0.95 PMP WIT Ŧ Ξ CONDITIONS C CORRECTED FOR ALL CONDI ITY (REFLECTANCE SET TO GREES FOR ISC, IMP, AND MP IMP PMP EFFCY 1 V) (A) (W) (%) (%) 23 411 2.148 13.06 1 23 4.04 2.117 12.87 1 23 4.04 2.117 12.87 1 333 1.995 12.73 1.0 6 3.33 1.782 10.83 0.1 4 4.00 2.095 12.73 1.0 5 .33 1.561 7.67 0.56 5 .279 1.500 5.47 0.42 1.68 0.900 5.47 0.42 1.68 0.900 5.47 0.42 1.68 0.900 5.47 0.42 00000000000
 FANCE SET TO

 ISC, IMP, AND F

 PMP EFFCY I

 PMP EFFCY I

 ISG II.31

 I.W1 (%)

 I.W2 (%)

 I.S3 (11.31

 I.951 (11.36

 I.951 (11.86

 I.951 (11.86

 I.951 (11.86

 I.951 (11.86

 I.951 (11.86

 I.951 (11.86

 I.960 (0.94

 I.960 (0.94
 COND EFFCY (%) 11.31 10.39 8.72 7.20 7.20 7.48 11.32 11.32 11.32 10.13 8.88 PMP (¥) 22.154 1.962 1.962 1.662 1.615 22.166 22.166 22.166 1.319 0.889 PMP (W) 1.861 1.710 1.710 1.710 1.710 1.863 1.863 1.951 1.951 1.667 1.460 QUALITY (REFLE D D DEGREES FOF ALITY (REF DEGREES F (V) 5.24 5.23 5.24 5.23 5.35 5.24 5.37 5.37 (V) 55.23 55.23 55.24 55.25 55 (V) 44.88 44.88 44.92 44.92 5.03 5.03 (V) 4 4 88 4 4 90 4 4 90 4 4 92 5 03 5 03 ٨W ZED TO 0 D ZED TO 0 D ISC (A) 3345 4 3345 4 3345 4 335 4 335 5 55 5 10 TE MA 10 TE TA 10 TE 1 3 5 (A) 452 452 452 310 310 392 358 305 305 g STRING

 814
 DATA FOR STRI

 • NURMALLIZED T
 • NURMALLIZED T

 • ANGLE VOC
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 • 0.0
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 • 0.1
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 • 0.0
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 • 1.0
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FIGURE A8 (CONTINUED)

ORIGINAL PAGE IS OF POOR QUALITY

$ \begin{array}{c} \text{MIC} \text{res} \text{Tres} \text{ res} $			
MAX FOR STRING BALCORRECTED FOR ALL COUNTIONS MAX FOR STRING BAL CONSECTED FOR ALL COUNTIONS MAX FOR STRING BAL CONSECTED FOR ALL COUNTIONS MAX FOR STRING BAL CONSECTED FOR ALL COUNTIONS MAX FOR STRING BAL COUNTIONS MAX FOR STRING BAL COUNTIONS MAX FOR STRING BAL FOR STRING BAL <td>CONDITIONS INCLUDING TT TO .7) AND PMP FFCY NORM NORM NORM (%) ISC IMP PMP 9.80 1.00 1.00 1.00 8.34 0.82 0.86 0.85 5.06 0.52 0.49 0.55 3.29 0.37 0.32 0.34 9.70 1.00 1.00 1.00 7.19 0.97 0.78 8.45 0.85 0.90 0.87 8.45 0.85 0.90 0.87 7.50 0.75 0.81 0.74</td> <td>EFFCY NORM NORM NORM (x) ISC IMP PMP 9.80 1.00 1.00 1.00 9.81 0.82 0.86 0.85 7.31 0.66 0.72 0.75 5.06 0.52 0.49 0.52 3.29 0.37 0.32 0.34 9.70 0.99 0.97 0.99 9.70 0.99 0.97 0.99 9.70 0.94 0.94 0.94 9.70 0.94 0.96 0.73 9.70 0.94 0.94 0.94 9.74 0.94 0.94 0.94 9.75 0.73 0.95 0.94 9.74 0.74 0.78 0.77 9.24 0.94 0.94 0.77</td> <td>L CONDITIONS INCLUDING FFT TO 7) F, AND PMP FFC NORM NORM NORM NORM (%) ISC IMP PMP 9.51 1.00 1.00 1.00 9.51 1.00 1.00 1.00 9.51 0.01 0.01 0.04 8.01 0.88 0.88 0.84 6.75 0.59 0.03 9.30 1.00 1.00 6.05 0.88 0.38 0.38 7.49 0.56 0.38 0.38 7.49 0.56 0.38 0.38 7.49 0.56 0.25 0.25 7.80 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.98 0.98 7.43 0.71 0.66 0.62 6.08 0.77 0.68 0.97 8 0.78 0.78 0.07 9.81 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.98 0.98 7.43 0.71 0.66 0.62 6.08 0.71 0.66 0.62 6.08 0.71 0.66 0.62 6.08 0.71 0.66 0.62 6.00 0.09 1.00 9.81 1.00 0.98 0.98 7.43 0.79 0.78 0.78 0.78 7.24 0.14</td>	CONDITIONS INCLUDING TT TO .7) AND PMP FFCY NORM NORM NORM (%) ISC IMP PMP 9.80 1.00 1.00 1.00 8.34 0.82 0.86 0.85 5.06 0.52 0.49 0.55 3.29 0.37 0.32 0.34 9.70 1.00 1.00 1.00 7.19 0.97 0.78 8.45 0.85 0.90 0.87 8.45 0.85 0.90 0.87 7.50 0.75 0.81 0.74	EFFCY NORM NORM NORM (x) ISC IMP PMP 9.80 1.00 1.00 1.00 9.81 0.82 0.86 0.85 7.31 0.66 0.72 0.75 5.06 0.52 0.49 0.52 3.29 0.37 0.32 0.34 9.70 0.99 0.97 0.99 9.70 0.99 0.97 0.99 9.70 0.94 0.94 0.94 9.70 0.94 0.96 0.73 9.70 0.94 0.94 0.94 9.74 0.94 0.94 0.94 9.75 0.73 0.95 0.94 9.74 0.74 0.78 0.77 9.24 0.94 0.94 0.77	L CONDITIONS INCLUDING FFT TO 7) F, AND PMP FFC NORM NORM NORM NORM (%) ISC IMP PMP 9.51 1.00 1.00 1.00 9.51 1.00 1.00 1.00 9.51 0.01 0.01 0.04 8.01 0.88 0.88 0.84 6.75 0.59 0.03 9.30 1.00 1.00 6.05 0.88 0.38 0.38 7.49 0.56 0.38 0.38 7.49 0.56 0.38 0.38 7.49 0.56 0.25 0.25 7.80 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.98 0.98 7.43 0.71 0.66 0.62 6.08 0.77 0.68 0.97 8 0.78 0.78 0.07 9.81 1.00 0.99 1.00 9.81 1.00 0.99 1.00 9.81 1.00 0.98 0.98 7.43 0.71 0.66 0.62 6.08 0.71 0.66 0.62 6.08 0.71 0.66 0.62 6.08 0.71 0.66 0.62 6.00 0.09 1.00 9.81 1.00 0.98 0.98 7.43 0.79 0.78 0.78 0.78 7.24 0.14
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FIGURE A8 (CONTINUED)

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RESE | NORM | PMP | 1.00 | 0.99 | 0.95 | 0,84 | 0.70 | 1.00 | 0.94 | 0.83 | 0.69
 | 0.43

 | | DING | | NORM
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IMP | 1.00 | 0.91 | 0.78 | 1.00

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0.00 | 0.45 |
ANGL | NORM | IMP | 0.99 | 1.00 | 0.90 | 0.77 | 0.65 | 0.99 | 0.93 | 0.81 | 0.69
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WITH | NORM | ISC | 0.98 | 0.95 | 0.84 | 0.73 | 0.62 | 1.00 | 0.95 | 0.87 | 0.73
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 | ISC | 1.00 | 1.02 | 0.95 | 0.87 | 27.0
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 | 0.70 | 0.98 | 0.87 | 0./b | 0.37 |
| AND | FFCY _ | 1.7 | 1.22 | 9.86 | 1.1

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 | | | AND | FFCY
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IMP | 1.00 | 0.94 | 0.80 | 1.8

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 | 86.70 | 0.80 | 0.60 | 0.27 | ANGLE
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A20

FIGURE A8 (CONTINUED)

FIGURE A9

* Offpoint > 15 represents output due to scatter from primary and secondary.

NOTES: * Shadowed output is shadow equal in size to optic. This represents background.

Angle Offset																
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З	139	.48	164	.61	136	.46	168	.61	134	.55	199	. 99	187	.62	139	.60
2.5	195	.67	212	.78	19 4	.66	197	11.	180	.74	224	.75	232	.77	176	.17
2	228	.78	228	.84	238	.81	214		198	-82	241	.80	247	.82	192	.83
1.5	238	.82	238	-88	248	.84	230	.83	202	.83	257	.86	256	.85	200	.87
7	252	-86	259	- 96	260	.88	245	.88	220	.91	271	6.	282	.94	217	.94
s.	274	-94	268	- 99	286	.97	263	.95	234	.97	290	.97	292	.97	228	66.
0	292	1.00	270	1.00	294	1.00	276	1.00	239	.99	297	66.	297	66.	229	1.00
0	292	1.00	271.	1.00	293	1.00	277	1.00	242	1.00	300	1.00	300	1.00	230	1.00
.5	298	1.02	267	66.	296	1.01	278	1.00	244	1.01	295	- 98	301	1.00	230	1.00
1	293	1.00	272	1.00	296	1.01	268	.97	240	66 .	277	.92	299	.98	231	1.00
1.5	303	1.04	267	66.	291	66.	238	.86	227	.94	243	.81	279	.93	224	.97
2	254	.87	253	.93	278	.95	203 .	.73	204	.84	219	.73	247	.82	203	.88
2.5	212	.73	209	.77	237	.81	188	.68	178	.74	195	.65	217	.72	179	.78
e	185	.63	183	.68	214	.73	167	.60	163	.67	163	.54	192	.64	164	.71
3.5	161	•55	140	.52	185	.63	112	.40	124	.51	98	.33	147	.49	126	.55
4					123	.42	66	.24	58	.24	47	.16	71	.24	75	.33
4.5					52	.18	33	.12	19	89.	16	.05	17	•06	30	.13
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10													.30	.0043		
15													.91	.0030		
Shadowed *							.25	6000.		-				<u>.</u>		
Offpoint > 15**							.70	.0025								

SECONDARY PROOF MIRRORS

OFFPOINT DATA CORRECTED TO AMO AND 28°C ONLY

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SECONDARY PROOF NORMALIZATION AND CONVERSION

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AVG	.62	.81	.95	.97	.93	.95	66.	1.01	1.00	1.01	1.02	66.	.96	.89	.81	.60	.30	.11	.04
თ		.78	.96	66.	.94	.96	1.00	1.01	1.00	1.01	1.03	1.04	1.05	.97	.92	.72	.42	.16	
œ		.80	.96	.97	.92	.96	.98	1.01	1.00	1.01	1.01	1.00	.97	.	.83	.64	.31	.07	.02
2		.86	.94	•96	.94	.93	66.	1.00	1.00	.99	-94	.87	.87	.81	.70	.43	.20	.06	.02
9		.71	.92	.97	.89	.93	.98	1.00	1.00	1.02	1.02	1.01	1.00	.92	.87	.67	.31	.10	.05
2		.79	.89	.91	.89	-90	.96	1.00	1.00	1.01	1.00	.93	.87	.85	.78	.52	.31	.15	.05
с	.60	.86	1.01	1.00	.95	1.00	1.01	1.01	1.01	1.02	1.02	1.02	.96	16.	.82	.53	.23		
2		.79	.97	1.00	.95	66.	1.00	1.00	1.00	1.00	1.03	1.07	1.10	.96	88.	.68			
1	.63	.87	. 97	.97	.93	.96	1.01	1.02	1.02	1.01	1.07	.94	.87	.79	.71				
	3.5	m	2.5	2	1.5	1	<u>،</u>	0	0	.5	1	1.5	2	2.5	3	3.5	4	4.5	ß

FIGURE A10

Engineering & Test Division TRW Space & Technology Group

4.0 INSPECTION RESULTS

The small panel was checked and mapped for defects in the primary mirror coating and for weld joint integrity. Figure All is a sketch of the defects found.

The large panel was inspected in the same manner as the small panel. It was noted that 5 mechanically produced nickel conic mirrors originally machined as test articles with no coatings or polish found their way onto the panel as noted in Figure A12. What is surprising is that the machined parts had relatively small effect on output of the strings involved. Apparently the coating degradation is approximately equal in effect to a bare nickel machined part.

Lack of schedule precluded replacing these machined conic parts.

Figure A13 presents electrical inspection remarks as determined during output testing. A number of elements were found to be open or shorted as shown. The Varian string 10A was not possible to electrically measure due to the characteristics of the string. Some elements had essentially 0 current but full voltage capability and acted as reverse diodes in series with the string. It was not practical to jumper the effected elements as only 1 element was actually producing power correctly. This string will be monitored only for mechanical degradations.

A23



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FIGURE A12 INSPECTION RESULTS OF 15" x 56" PANEL.

Electrical Test notes showing locations of shorted and open cells as well as thermistor locations. FIGURE A-13.



Appendix B - MCC

ELECTRICAL MANUFACTURING

1. FABRICATION

Items required for fabrication:

CELL I/C BeO I/C Spider Washers

1.1 CELL AND BEO INTERCONNECTS

Approximately 300 interconnects for the cell and BeO cell mounting were required for the MCC job. Kovar was chosen as base material due to close match in CTE with the GaAs cell, and by availability. The Kovar was cut into 0.001" x 1" x 6" strips which were plated with nickel, copper and either silver or gold as required. Plated strips were then stacked and machined using a wire electro-discharge process. Cut rates were extremely slow to avoid fusing strips together and alloying of base material with platings. Final cut stacks were then separated as individual piece parts. Stress relief loops were formed in each part using a two piece die; five parts were formed per cycle. Completed parts were then cleaned in a solvent bath and protective packaged for later use.

1.2 SPIDER

Approximately 270 spiders were required. Fabrication techniques were almost identical to those used for the interconnects. Base material for the spider was chosen as Aluminum; weight was a major driver. The aluminum plates were stacked as limited by the machine wire tolerance and, again, a slow burn rate was used to avoid fusing parts and/or alloying of plating and base material. Cut stacks were separated and sent to a silver plating bath. The silver plate allowed the use of solder to bond the secondary mirror to the spider. The parts were then protective packaged for later use.

B1 ·

1.3 WASHERS

Approximately 250 Kapton/RTV washers were required for the MCC job. These washers are used at installation of the MCC element into the Tri-Hex grid. Commercially available pop-pins (snap inserts) were used to hold the MCC elements in place. An uneven top surface of the three elements held by the pop-pins created non-uniform pressure on the elements, tending to distort the surface or the pin. Therefore, it was desirable to have a pliable surface between the element and the pop-pin surface.

This surface was created by making washers the size of the the pop-pin head. These washers were made from Kapton and RTV. A 0.002" Kapton sheet was covered with a thin layer 0.001-0.002" of RTV 142. After cure, the outside diameter of the washers were punched, one unit at a time. Concentric with the 0.D., an inner circle of material was removed that matched the pin shaft 0.D., completing the washer. Washer to Pop-pin Cell I/C to Cell BeO I/C to BeO Coverglass to Cone Secondary to Spider

2.1 WASHER TO POP-PIN

The completed washer was installed to the pop-pin. Since the pop-pin shaft 0.D. is much larger at the pressure fitting than the washer I.D., tooling was required to compress the pop-pin shaft. This avoided splits to the Kapton washer during installation. The completed pin washer assembly was then stored for later use.

2.2 CELL AND BEO INTERCONNECT ATTACHMENT

As discussed in section 3.4.2.3, welding was selected for joining I/Cs to both the cell and BeO pads. Tooling was fabricated for both of these operations. The cell or BeO were loaded into a cavity and solvent cleaned. The interconnects as made in section 1.1 of this appendix were centered over a locating pin and rotated over the cell and/or BeO until desired location was achieved (Figure B1, Left tool). The weld was then made in two places for each interconnect. The completed joints were then cleaned and the completed assembly was boxed for later use.

For the cells, all were measured for I/V characteristics prior to the welding and identified. After a weld schedule had been developed for each vendor, the cells were then grouped by performance and welded. It was assumed that performance degradation would be relatively constant for all cells, by vendor. The cells were re-grouped by "performance prior to welding," after welding. These groups were selected to develop a kitting plan to group similar performance cells at the panel level.

B3



FIGURE B-1. BeO welding tool (left) and conic mirror coarse alignment tool (right).

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2.3 COVERGLASS TO CONE BONDING

As discussed in section 3.4.6, several options were evaluated for joining the cone to the coverglass. This joint was critical in that the cone must be perpendicular to the glass and that no bonding material could be allowed on the interior of the cone. Reduced viscosity bonding materials were ideal for good filleting but "leaked" under cone to inside surfaces. Higher viscosity materials did not provide filleting, or the force required for filleting caused mis-mating of the two components. Dymax 628, a UV curing adhesive was chosen. This material has a very low viscosity but can be kept from "leaking" by accelerated cure under intense UV exposure.

A multiple place tool was constructed for this operation (Figure B2) Five coverglasses were loaded into cavities for locating and cleaning. Five cones were then loaded onto the tool and centered by estimation. Centering spindles made of nylon and match ground to the base ID of the cone were lowered into the cone and brought down flush to the glass. The centering nylon could touch only the base of the ID of the cone. This locked the two components for bonding. A small dot (5 mg) of the UV adhesive was placed on the side wall of the cone. As the material ran down the wall of the cone and filleted the coverglass, it was exposed to high intensity UV light for 10-15 seconds. This operation was repeated for all four corners of the coverglass. The resulting bond was then baked for 30 minutes at 100°C in air to ensure full cure.

Cleanup and rework was accomplished by flushing the bond with acetone and IPA. Care was taken to avoid contamination of the interior cone surface.

This bond was tested by thermal cycling sample components in air from +100°C to -100°C, 200 cycles in duration. Also, sample components were exposed to acoustic protoqual pressure levels. No joints showed evidence of delamination or failure.



FIGURE B-2. Conic mirror to coverglass bonding tool.

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2.4 SECONDARY TO SPIDER JOINTS

Adhesive bonding was selected as a baseline process for joining the secondary mirror the the spider support. This baseline was a very difficult method. To keep the secondary pointed and true to the cone, the adhesive layer had to be perfectly flat and continuous. Low viscosity materials were investigated, however, bond strength was marginal. Paste adhesives resulted in inconsistent bond thickness. Attempts to eliminate the interface bond and fillet the joint with paste adhesives were equally unsatisfactory as well as extremely time consuming to complete.

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A secondary system was developed to solder the secondary mirror to the spider. The aluminum spider was silver plated with nickel-copper base. The interior surface of the secondary, electroformed nickel, was not prepared. A silver filled solder, preform was made by wrapping a rod sized slightly larger than the inside diameter of the secondary with solder wire. Preforms were then cut from the rod. The spider was located on a solder fixture (Figure B-3, right tool) on its outside diameter. The solder preform was then fluxed in Alpha flux diluted with isopropyl alcohol. The preform was then located over the spider outside diameter on the fixture. Installation of the secondary mirror on top of the preform capped the assembly. The preform was then pushed inside the secondary mirror and held by "spring action" to the inside surface. The secondary was pressed firm to the spider by slight pressure of a teflon pad.

The fixture containing secondary, spider and preform were then soldered via Vapor Phase soldering on a controlled elevator for time at temperature. Solder schedules were developed for producing 100% filleting to the inside surface. Pressure and flux were critical to achieve wetting to the nickel interior.

None of these subassemblies required rework.

3. OPTIC ASSEMBLY

Cell Stack Installation Feed Through Post, Installation Cone/Core Installation Painting Secondary/Spider Installation

3.1 CELL STACK INSTALLATION TO PRIMARY MIRROR

The original proposal for installation of the cell stack was to make one joint at a time, using vapor phase solder techniques. However, each subsequent joint had to utilize higher temperature solders to prevent reflow (and misalignment) of the prior joint. This quickly proved unworkable and expensive. A secondary approach called for joining the cell to the BeO and the BeO to the primary mirror in a single vapor phase operation. This method was much more difficult to tool due to the extremely tight tolerance for placement of the cell but was chosen over the method above for cost constraints.

Solder preforms were experimented with and selected at 70% of the total interface area and at 0.001" thick of silver filled solder (to avoid gold migration from the BeO). Tooling fabrication was made to locate the BeO pad and the cell into the Primary. This tool had a two step cavity (Figure B-3, left tool small cylinder with cavity). The first cavity held the solar cell, active surface down with its interconnect. The cell solder preform was then dipped in flux and placed on the back cell surface. Excess flux here broke cells and was minimized. The cavity was made slightly less deep than the cell. The BeO was then placed in the second cavity, over the cell solder preform. The BeO solder preform was then fluxed and added to the back of the BeO. This cavity was also slightly less deep than the BeO.

The outside diameter was match ground to the inside diameter of the primary mirror. A through locating pin aligned the tool to the primary mirror, where the tool was inserted and pushed flush with the base of the primary. The undersized cavity created pressure between all components and the preforms. The tool was then clamped to the primary by a mating shell with spring loaded tension (Figure B-3, left tool, hexagonal, with coil interior and leaf exterior springs).



FIGURE B-3. Cell and BeO insulator to primary vapor phase solder tool (left) and secondary to spider vapor phase solder tool (right). The primary with tool clamped in place, was then soldered in the vapor phase solder machine. A schedule was developed to ensure good wetting of the cell and BeO to each other and to the primary. To maintain schedule, soldering of the cell stacks was done concurrent with the soldering of the spider assemblies noted in B.4.

The soldered primary was then removed from the vapor phase and allowed to cool. A vapor degreaser was used to remove the flux from the tool and completed primary subassembly after soldering and removal of the clamp. The locating tool was then removed. The primary was then identified with the cell and electrical group contained within.

This operation caused the worst cell breakage as the GaAs cell was very brittle and had to be held to the center of the primary. Vent and flux cleaning holes were added to the tool which improved throughput yields, see attached Figure B-4 This area will be further evaluated in follow-on contracts.

The completed cell stacks were then protective packaged, identified, and stored.

3.2 FEED THROUGH POST INSTALLATION

To this point, the interconnected cell and BeO (-)N and (+)P contacts were floating freely in the primary mirror. Hermetically sealed feed through posts as used by the printed circuit board industry were acquired and used to connect the contacts and feed through the base of the primary to form terminations.

Before assembly, the base of the terminals (ground) were coated with encapsulent to prevent shorting of the soldered joints. The back surface of the primary was lightly abraded and cleaned with acetone to prepare it for soldering. The post was then inserted from the backside and soldered to the primary mirror using a hand held iron and silver filled solder. A 50% fillet was required. The joints were tested for isolation between pin and mirror at 500 V. Any failures were reworked. Flux was used as required to activate the surface.

The positive and negative contacts were then made on each assembly using a hand held iron and a mild flux. The assembly was held in a fixture so that the operator could make both joints required without contacting ground (mirror or pin body).



FIGURE B-4

Because the heated flux tended to splatter and contaminate the primary mirror, prior to soldering, the mirror was coated with X59 optic cleaner. The cleaner was recommended for use by the TRW optic lab as its residue is measured in angstroms and it is easily removed. The toluene base material was coated on the interior of all optics and removed after soldering with a touch of masking tape applied to a non mirror surface.

Removal of this material revealed severe plating problems with the primary mirror plating adhesion.

3.3 CONE AND COVER INSTALLATION

The cone and cover assembly was bonded to the cell using a small drop of optical adhesive DC93-500. The rightmost tool in Fig. B-1 was used to install and rough center the cone assembly to the primary. The cone was centered on the cell by visual alignment and tacked in place by using an elevated temperature cure lamp. After tacking, the assembly was baked at 100°C for 90 minutes to full cure the adhesive.

Rework for misalignment was easily performed by swelling the cover adhesive with a chlorinated solvent, manually cleaning, and rebonding.

3.4 PAINTING

Painting of the optics was probably one of the most difficult tasks. The paint, S13GLO a white RTV paint, is difficult to work with and does not adhere well to nickel or silver plating. Two surfaces required application of paint - the backside of the primary mirror and the top side of the spider/secondary assembly.

The primary mirror was placed on a painting aid and bonded in place with double sided tape. Positions of the optics were mapped to show identification and the tags were removed. Surface prep included wipes with acetone and alcohol with one half hour dry times in between. The posts and the mirror support hole were then masked with painting aids and the surface was primed with a thin coat of the vendor supplied primer. The primer was air brushed on in a box coat to a thickness of less than 0.0003". S13GLO paint was then mixed and sprayed per the vendor instructions. Approximately 0.001" of paint was applied per session, with an overnight dry between applications. The total paint thickness was targeted at 0.003" to 0.004".

The painted primaries were then removed from the double back tape by cutting an edge in the tape with an "X-Acto" knife. The plugs were removed and the flaking paint at these edges was cleaned with the knife. The part was then bagged and identified from the map.

Secondary mirror subassemblies were loaded into a custom fabricated aid for painting. A sheet of neoprene rubber with a best fit packing factor was cut with through holes that allowed the secondary mirror outside diameter to "press fit" through. The neoprene sheet was supported by "lexan" plastic. The spider assemblies, when placed in the aid, were then masked with masking tape dots at the to be bonded ends of the spider legs. Cleaning, priming and painting were achieved using the same procedure as noted above. The sole exception was that the upper edge of the interior diameter of the secondary was hard brushed with primer and paint.

The spider assemblies were removed and cleaned using a sharp knife to remove excess and flaking paint. Special care was taken not to damage the legs of the spider in removal. The painted parts were then protective packaged for the next assembly.

3.5 SECONDARY/SPIDER INSTALLATION TO PRIMARY

The secondary/spider assembly self aligned to the primary on three mounting posts. The interface between the surfaces was cleaned with acetone and allowed to dry for one half hour. The secondary was then placed on the primary and three small dots of lightweld 628 adhesive were added. The spiders were quickly tacked in place with the UV lightsource used in section 2.3 of this appendix. Final cure was accomplished in an oven at 100°C for 30 minutes. After cure, the completed optic was bagged and identified.

4. PANEL ASSEMBLY

Installation of the Floating Inserts Optic Installation Harness Fabrication Series Stringing and Harnessing Testing and Rework

4.1 INSTALLATION OF PANEL INSERTS

Three candidate materials were installed to the Tri-Hex grid in the development phase as discussed in the report body. All three candidates were included on the 66 and 180 optic panels.

Installation of the inserts creates the plane that the optics rest on and therefore is critical for electrical performance. This work demonstrated that even though the panel was bowed significantly, the inserts could create a new plane. The panel was placed on a granite table with the optic side down. Spacer shims were then added between the panel and the table rather at random. The inserts were then slid through the panel from the back side of the panel until they located on the granite table. (Note: inserts had to be deburred prior to installation. Burrs were made by the mirror vendor.)

After insertion, three inserts were selected in the middle of the panel that made the largest possible triangle. These three inserts were bonded with UV adhesive noted above, thus creating the optic plane. With great care not to touch or distort the panel, the next intersecting and bisecting triangles were selected and bonded. Soon the panel was sturdy and rested on the bonded inserts; the shims were removed. The remaining inserts were bonded as these first triangles, row by row.

The panel was then inverted and epoxy bond (EA9321) added as a fillet around the top of the insert to add strength to the bond. The panel was then cured at 100° C for two hours. Rework was accomplished by solvent and heat gun removal and subsequent rebonding of the insert on the micro flat granite.

4.2 OPTIC INSTALLATION

The first step towards optic installation was development of a kitting plan. The optics had been identified throughout manufacture with the original cell output data as well as optic type (several optics were of Ni/Cu/Ni sandwich construction). Based on original cell performance data, the optics were kitted to the panel per attached Figure B-5. Roadmaps were made showing the pedigree of each optic as it was loaded to the Tri-Hex grid.

After loading, the optic was fastened to the Tri-Hex with the pop-pin/washer assembly detailed in section 2.1 of this appendix. Each optic was held by three such pins. Pins were all loaded to the floating insert and then pressed into position, one at a time such that the RTV washer captured the lip of the optic. the optics were all oriented so that the feedthrough terminals were aligned for ease of series wiring.

4.3 HARNESS FABRICATION

Two harnesses were fabricated for the MCC panels. Both used rectangular connectors and a three stage potting sequence in a low boot configuration. There was no ground strap or loop. Fabrication and cut length instructions are attached as Figure B-6.

Wire used for the harness was a nylon insulated ribbon cable with 28 Awg wire. The wire was stripped with a laser wire stripper and separated with a sharp knife. Contact fillers were installed as required.

4.4 SERIES STRINGING AND HARNESSING

The harness fabricated above was installed to the panel with lacing ties along the wire bundle. The connector was mounted to the panel by a twin pair of aluminum plates, mounted with hardware, and held in place with by clamping pressure across the width of the Tri-Hex.

Series wiring optic to optic was made with a 26 Awg jumper wire looped between the Tri-Hex grid and stress relieved. Terminations were soldered to the terminal feedthroughs using a silver filled solder and an alpha flux.

Figure B-5. MCC PANELS - KITTING PLAN

Small Panel:

<u>String</u>	<u>Oty</u>	<u>Optic</u>	<u>Cell/%</u>	
1	8	Ni	ASEC/19.81-20.1	Set l
2	15	Ni/Cu/Ni	ASEC/19.81-20.1	Set 1
3	15	Ni/Cu/Ni	ASEC/20.11-20.7	Set 1
4	15	Ni/Cu/Ni	ASEC/20.11-20.7	Set 1
5	<u>15</u>	Ni/Cu/Ni	ASEC/20.11-20.7+	Set l
	68			

Large Panel:

1	12	Ni	Varian	
2	24	Ni	Varian	
3	24	Ni	Spectrolab 17.51-	-18.6
4	24	Ni	ASEC/19.21-20.0	Set 1 & 2
5	24	Ni	ASEC/19.51-20.0	Set 1 & 2
6	24	Ni	ASEC/19.51-20.0	Set 1 & 2
7	24	Ni	ASEC/19.51-20.5	Set 1 & 2
8	<u>24</u>	Ni	ASEC/19.81-20.1	Set 1
	180			

16 Pin (Minimum) Connector- 10 Pin (Minimum) Connector-

•

		(MIN)			(MIN)
<u>PIN#</u>	<u>COLOR</u>	<u>LENGTH</u>	<u>pin#</u>	<u>COLOR</u>	LENGTH
1	В	65"	1	В	30"
2	R	65"	2	R	30"
3	В	55"	3	В	25"
4	R	55"	4	R	25"
5	В	50"	5	В	20"
6	R	50"	6	R	20"
7	В	45"	7	В	15"
8	R	45"	8	R	15"
9	В	40"	9	В	10"
10	R	40"	10	R	10"
11	В	30"			
12	R	30"			
13	В·	20"			
14	R	20"			
15	В	10"			
16	R	10"			

•

Figure B-6. Harness Fabrication Instructions for 15 x 21 and 15 x 56 Panels

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Terminations were made to the harness bundle in accordance with the attached schematic Figure B-7. The schematic was developed from the best fit kitting plan to avoid electrical mismatch degradation. Terminations to the harness bundle were made using a western union splice soldered as above and sleeved with a shrink sleeve tubing of Kynar co-polymer series.

4.5 TESTING AND REWORK

The completed panel assembly was installed on the solar tracker and tested per procedures noted in the body of the report.

Optics identified with performance problems were removed and replaced with attrition quantities. Removal was difficult as the pop-pin is a one way device. The most effective removal technique was to drill out the pop-pin. A vacuum and shielding were used to protect the optics and chips were removed as they were generated. Replacement optics were installed and tested as above.

Thermistors were added to the panel to collect temperature information during test. Thermistors were bonded to the back of the primary mirror with conductive epoxy in an area where the Sl3GLO paint had been removed. The paint, however, had left a silicone contamination which made subsequent bonding with non-silicones nearly impossible. Abrasion and cleaning resulted in relatively weak bonds.


Schematic (66 Optic Panel)

APPENDIX C STRUCTURE MANUFACTURING

BACKGROUND:

Previous NASA contracts and a TRW PMI Program demonstrated the feasibility of manufacturing a structurally sound tri-hex grid from a single tow graphite prepreg roving. It was believed that the low fiber volume/high resin content characteristics of panels which were previously fabricated could be improved by utilizing a trapped rubber molding (TRM) expansion process during cure (see Figure C-1). A major goal of the present NAS8-36159 contract was to develop this process, resulting in a higher fiber volume and lower resin content substrate. Development and co-curing of lightweight molded inserts, thin uniform wall thicknesses in the substrate and elimination of tool removal problems were also objectives of this contract.

TECHNICAL APPROACH:

The graphite prepreg roving materials chosen for evaluation were 6 K tow T-300/Fiberite 934 ($350^{\circ}F$ cure) and 6 K tow T-300/Fiberite 982 ($250^{\circ}F$ cure) systems. The effect of different cure temperatures on the TRM process needed to be established in order to select the best material from which to fabricate the tri-hex grid.

To establish expected material properties and determine the structural effect of crossing yarns, six graphite samples were fabricated using the TRM process. The expandable elastomer chosen was Dapocast 1-100 silicone casting compound (CTE 10.6 x 10^{-5} in/in/^oF).

The rubber inserts were fabricated in the molds used to layup the straight and crossover samples by pouring the rubber with aluminum cores in place which replicated the graphite samples (see Figure C-2).

Three straight and three crossover samples were fabricated. The parts were first tested in bending and then specimens were cut from each part to determine specific gravity, resin content, void content and fiber volume. Findings are shown in Figure C-3. Failure of the straight strips occurred in a buckling mode due to the thin cross section. No structural degradation was seen in the cross strips at crossover points. The bending test set up is shown in Figure C-4.

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Figure C-2. Strip Samples and Tooling.

FIGURE C-3: GRAPHITE TRI-HEX SAMPLE FINDINGS

<u>s/n</u>	TYPE	CURE TEMP(^O F)	20 YARN <u>THICKNESS(1n)</u>	SPECIFIC GRAVITY (gm/cc)	CONTENT	VOID CONTENT (%)	VOLUME	MAXIMUM BENDING LOAD (LB)
3A	CROSS	350	.020023	1.5461	23.0	2.9*	67.9	42.50**
38	STRAIGHT	350	.021024	1.6367	23.5	0.0	70.1	19.75
4A	CROSS	350	.019022	1.6367	22.5	0.0	72.1	20.85
48	STRAIGHT	350	.023027	1.6412	21.7	0.0	73.1	20.15
5A	CROSS	250	.019029	1.5248	27.3	3.9*	66.7	29.35
5B	STRAIGHT	250	.027030	1.5487	29.3	0.0	64.3	21.50

NOTE THAT SAME NUMBER SAMPLES WERE CURED CONCURRENTLY.

* VOIDS WERE FOUND IN S/N 3A AND 5A SINCE SPECIMENS WERE CUT TO INCLUDE A CROSSOVER POINT. VOIDS WERE STILL LESS THAN THE ALLOWABLE VALUE OF 4%.

** THE HIGH MAXIMUM LOAD FOR S/N 3A WAS DUE TO A LIP WHICH EXISTED ON THE EDGE OF THE SAMPLE CAUSED BY THE INITIAL FABRICATION TECHNIQUE.



FIGURE C-4: CROSS STRIP SAMPLE IN TEST FIXTURE

1.

TRIM AND PANEL LAYUP DEVELOPMENT:

Five mini-panels $(5.0" \times 6.0")$ were fabricated-two $350^{\circ}F$ cure and three $250^{\circ}F$ cure-to develop the optimum wrapping technique and tooling approach, verify the ability to co-cure inserts with the panel, and determine the degree of wall compaction which could be attained in a tri-hex structure (see Figure C-5). During fabrication of the mini-panels, the optimum debulking (compaction) schedule was developed and it was found that debulking after the third, sixth, eighth and ninth course resulted in a uniform structure. It was necessary to debulk around wrapping pins after each course. Debulking was performed using .24" thick x .5" wide stainless steel Starrett shim stock.

Two major tooling innovations were proven out on the mini-panels. The first was to fabricate a two piece rubber hex for expansion molding (see Figure C-6). Initially, all rubber pieces were installed on the layup plate and the tows were wrapped in between them. This was done since it was physically impossible to drop full size rubber pieces between the tows after wrapping without trapping some fibers underneath. A disadvantage of having all rubber pieces on the mold is you are essentially working blind since tows cannot be seen. This slows down the wrapping. The two piece rubber approach was based on the fact that two rubber pieces with the same volume as a single piece should perform the same thermally. This was proven to be The two piece hexes were fabricated by placing 1.500" true. diameter aluminum plugs in the mold before pouring the rubber The aluminum plugs were removed, the outer hex (Figure C-7). rubber was released and the central rubber core then poured in the same mold. The two rubber pieces were then separated and the outer hex cut through on one side for ease of installation in the layup.

The second major tooling breakthrough was the development of screw pins as wrapping pins (see Figure C-8). Initially, .125" diameter dowel pins, snug slip fit in the layup plate, were used as wrapping pins. The tri-hex grid tended to lock around the pins during cool down making part removal very difficult. By modifying 10-32 socket head cap screws into wrapping pins, we took advantage of the "screw jack" effect which could be used to remove pins from the backside of the layup plate, thus eliminating part removal problems.

C5



OF POOR QUALITY

Figure C-5. Mini Panel with Tooling.



C7



figure C-7. Rubber Insert Mold.



SCALE: NONE



FIGURE C-8: THE SCREW PIN CONCEPT ALLOWED EASY DISASSEMBLY OF THE THG LAYUP TOOL AFTER CURE. The first three mini-panels used machined epoxy glass triangular inserts as placeholders. Production type injection molded thermoplastic inserts for element mounting were co-cured with panels number four and five (see Figure C-9). Inserts were molded from 30% graphite fiber filled PPS (RYTON), PEEK and TORLON. It was found the PPS was easiest to mold, requiring very small gates. These gates had to be enlarged slightly for injection of PEEK material and enlarged to the maximum for TORLON. Inserts were tooled to the layup plate using .203" diameter teflon pins for location and 6-32 socket head cap screws for angular clocking and tie down.

The method which evolved as the easiest way to fabricate the several hundred rubber pieces required for the 15" x 21" and 15" x 56" panels was to pour the rubber into an open mold overfilling slightly, and then clamping a caul plate with holes This allowed excess rubber to extrude out and controlled to it. thickness. De-airing of the initial Dapocast mix was found to be critical and allowing air to rise to the surface before covering with the caul plate helped cut down on voids. The thin cross section of the outer hex contributed to voids in some This cross section should be increased slightly for any parts. future fabrication by decreasing the diameter of the aluminum inner hex mold plug. It was found that post curing the Dapocast up to 400°F causes a color change from yellow to rust, but there is no degradation in properties unless continually used at this temperature. It also happened that one Dapocast mix resulted in "soft" rubber pieces. They had a Shore hardness of 30 A versus a normal value of 50 A. These soft pieces exhibited no detrimental difference in CTE when used for TRM.

The overall TRM Process Development Plan is shown in Figure C-10.

PANEL FABRICATION:

Based on the properties achieved in the strip samples and evaluation of the mini panels, it was decided to use the T-300/982 resin system for fabricating the 15" x 21" and 15" x 56" panels. Since this is a 250° F curing system, less internal stress due to thermal growth is built into the panel. The 15" x 21" layup tool and panel configuration is shown in

C10



ing Development									
Engineering and Test Division TRW Space & THG Process Manufactul Technology Group	DEFINE MATERIALS REQUIREMENTS	 MANUFACTURE SMALL TEST ARTICLES WITH VARIATIONS IN BASELINE PROCESS 	 TEST AND EVALUATE TEST ARTICLES 	 CHECK FOR STRUCTURE WEAKENING AT FIBER CROSSOVER 	MANUFACTURE SMALL TRI HEX GRID WITH INSERTS	 VERIFY GRID MEETS REQUIREMENTS SELECT BEST PROCESS PARAMETERS 	 MANUFACTURE 18" × 18" GRID 	 VERIFY ENGINEERING REQUIREMENTS, INCLUDING FLATNESS 	MANUFACTURE 15" X 56" GRID

Figure Cl0

Figure C-11. The wrapping pattern is a six tow sequence (one course) repeated 9 times resulting in a total of 18 tows in each internal wall. The outer frame has a consistent pattern, but does not have the same number of tows at every location. To give a better appearance to the frame and further stiffen the structure, the frame was covered with T-300 6K tow unidirectional tape (MT3-103-3) around the periphery. This tape has a 350° F curing resin so it is not fully cured at the 260° F curing temperature, but it has reached the glassing temperature (Tg) and is securely bonded from the resin in the roving.

The graphite tows were drawn through a series of dies (.052", .043" and .033" diameters) utilizing the technique developed on a previous PMI program. This rounds out the flat fibers and makes it easier to uniformly wrap around inserts and pins. A 108 style bleeder cloth was placed on top of the layup and the caul sheet was clamped down with 1/4-20 socket head cap screws threaded into the layup plate. Rails and inserts were .450" high, but some rubber pieces were slightly higher so this extra clamping helped to eliminate loose tows. The panel was turned over so the bleeder side was down and resin would be soaked up during the three hour, $260^{\circ}F$, vacuum bag cure. The 15" x 21" panel was easily removed from the mold and met all requirements (see Figure C-12). The panel is shown in Figure C-13 with the 15" x 56" layup tool.

Since the tri-hex pattern repeats, the 15" x 21" layup tool was simply extended to accommodate the 15" x 56" panel. The layup procedure was the same as the 15" x 21", but the cure cycle was modified. In an effort to reduce thermal stresses in the part, it was cured for three hours at $200^{\circ}F$ (beyond the Tg), wrapping pins were removed and the part was postcured for two hours at $260^{\circ}F$. When removed from the mold, the part was inspected and found to have a .240" bow. The walls of the grid tapered from .015"-.028" and this unbalanced condition was suspected as the cause of the bow. It was decided to build a second panel using a controlled compaction technique to guarantee an equal number of tows above and below the center line of the panel. The second panel was bowed .310" even though the walls were more uniform (.016"-.026"). This taper was

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C14

TOW	MECHANI	CAL MANUF	ACTURING
	ENGINE	ERING DEPA	\RTMENT
PARAMETER	FIGURE C-12; IRL-HEX GRI REQUIREMENT	D SPECIFICATIONS GOAL	ACTUAL CLUE MINIM M
FIBER VOLLIME TENSION/COMPRESSION MODULUS (O ^O)	40% minimm 13 × 10 ⁶ psi minimm	60% minimum 20 × 10 ⁶ PSI MIN	d4% printiput 15 × 10 ⁶ PS1 minimum (calculated From symle bending samples)
MALL THICKNESS	.030" <u>+</u> .010"	,020" ± 010"	,024" ± ,002" (15" × 21")
FLATNESS	.020" IN 10"	,005" IN 10"	.(121" ± .(105" (15" × 26") .014" IN 10" (15" × 21")
MEIGHT (LESS INSERTS)	N/A	,067 G/CM ³	$066 \text{ G/CM} \frac{10}{15} \times \frac{12}{21} \times \frac{32}{21}$
INSERT MEIGHT	Reduce Aluminum Weight of 3.3g	<u>ی</u>	
MATERIALS	SPACE COMPATIBLE	N/A	T-300 GRAPHITE/EPOXY PRE-PREG INJECTION MOLDED PEFK, RYTON
"Requirements" need to "Goals" represent a mor specifications mherever	be met for NaS8-36159 test e efficient structure. Fut : Practical.	Articles, Jre production panels	AND TORLUN 30% GRAPHITE FIBER FILLED. SHOULD MEET OR EXCEED THESE

C15

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Figure C-13. 15" x 21" Panels with 15" x 56" Layup Tool

partially due to rubber triangle inserts allowing fibers to get underneath during wrapping. Longer pins to secure these inserts would eliminate this problem. The layup process is shown in Figures C-14, C-15, and C-16.

The decision was made to straighten both panels to gain data points even though panel #2 was planned for use as the deliverable article since it had a more uniform structure. They were heated to 310F for 16 hours while restrained in the direction opposite the bow as shown in Figure C-17. Panel #2 was placed back into the oven at 360° for 16 hours to further straighten it. The results are shown in Figure C-18. In summary, panel #1 was flat within .020" after one straightening and panel #2 was flat within .040" after two straightenings.

RESULTS/CONCLUSIONS:

- a. All tri-hex grid specifications for this contract have been met or surpassed (see Figure C-12).
- b. The TRM technique was extremely successful in increasing the fiber volume of the tri-hex grid structure.
- c. Injection molded thermoplastic inserts can be successfully co-cured with an epoxy based prepreg roving.
- d. A tri-hex grid can be easily removed from the mold when screw pins are used.
- e. Thermally induced residual stresses are built into the 15" x 56" structure as a result of aluminum layup tool expansion during cure, causing the panel to bow. A graphite layup plate and caul sheet is recommended for fabricating any tri-hex grid panel with a length or width dimension greater than 30".



Figure C-14. Drawing TOW Through Die.





Figure C-16. Rubber Inserts Installed in Panel.







PANEL #	DIMENSION	AFTER INITIAL CURE	AFTER FIRST STRAIGHTENING	AFTER SECOND STRAIGHTENING
1	Α	.000	.000	N/A
	В	.000	.020	N/A
	С	.140	.010	N/A
	D	.050	.000	N/A
	E	.000	.010	N/A
2	Α	.000	.000	.000
(Deliverable	В	.025	.000	.000
Article)	C	.310	.080	.040
	D	.050	.010	.010
	E	.000	.000	.000

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